

Study of FEMB Saturation Response

Shanshan Gao on behalf of the BNL CE team
Brookhaven National Laboratory

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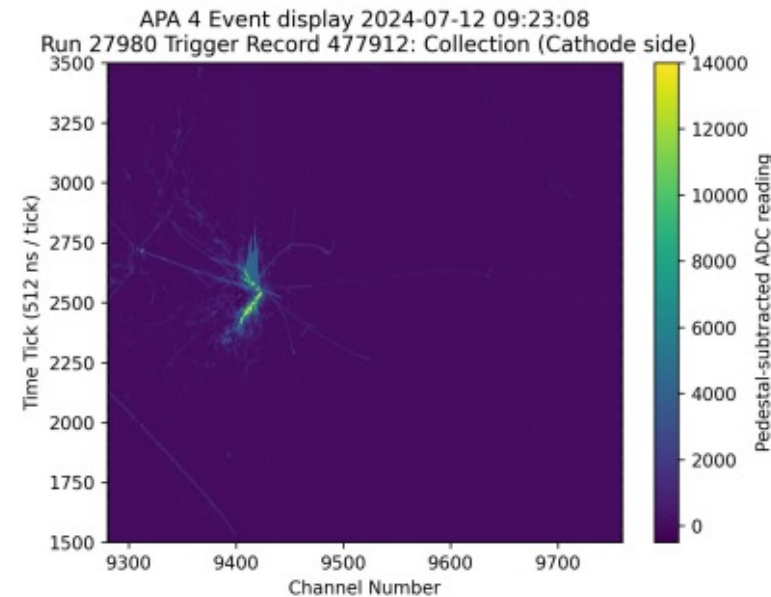
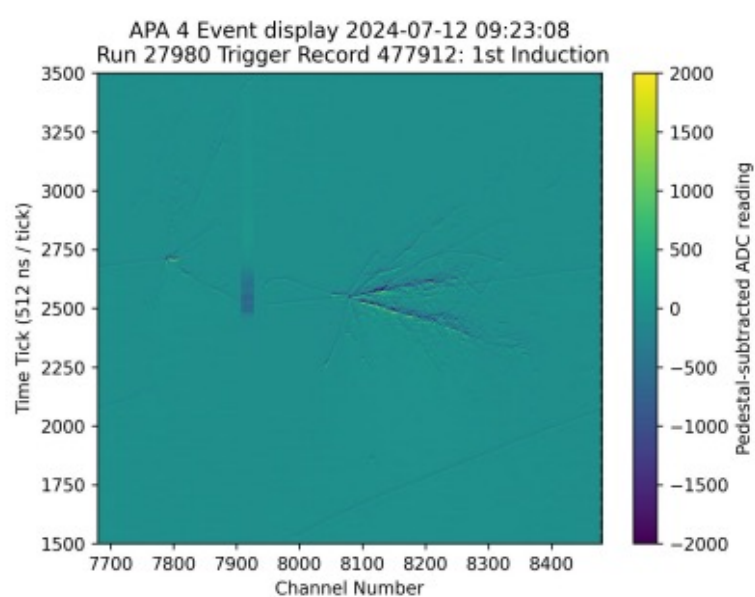
Introduction

- Roger's report on July 30 and August 6
 - <https://indico.fnal.gov/event/65701/>
 - <https://indico.cern.ch/event/1444711/>

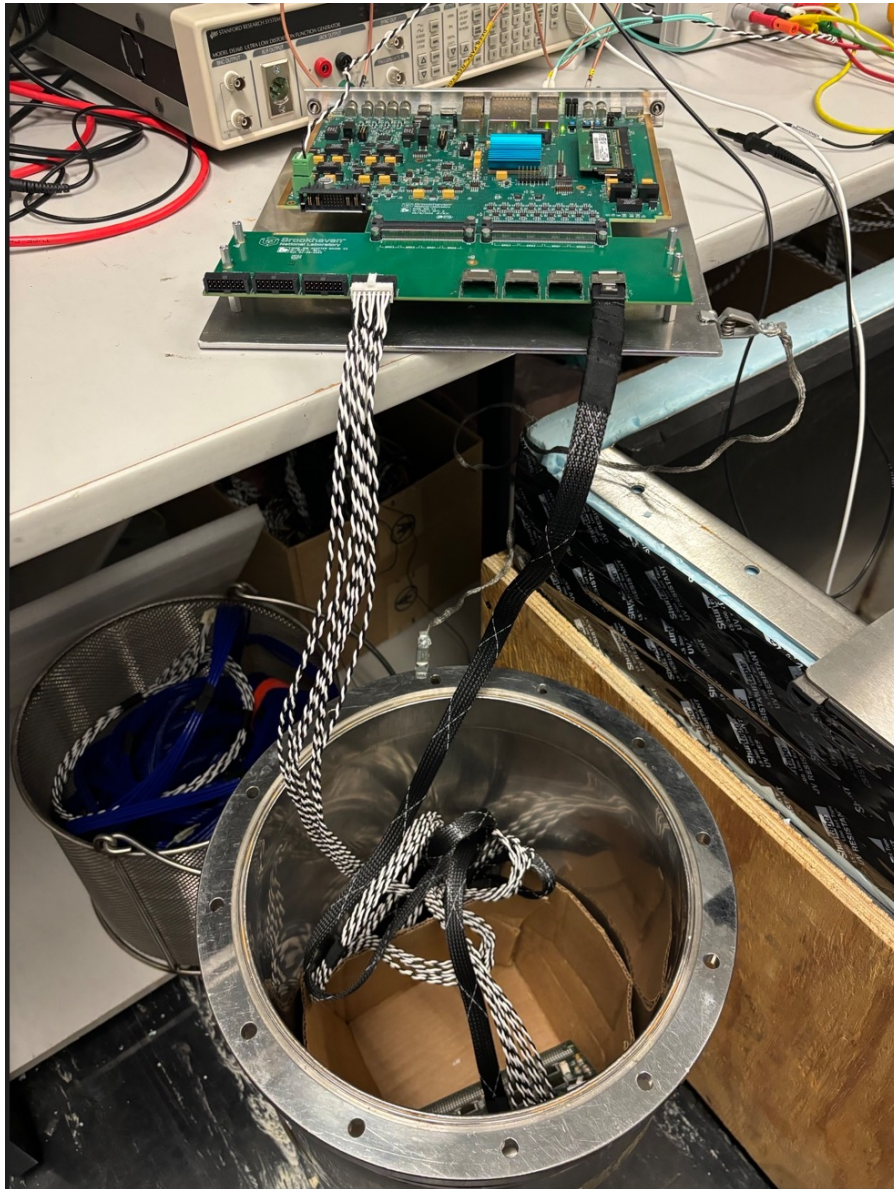


Half-FEMB Negative Pulses

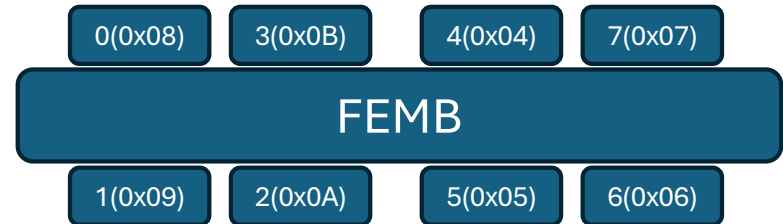
- When a lot of charge is collected in a few ASICs, it induces a negative “bounce” signal in the rest of the same half-FEMB
- This may be related to the power rails, which are supplied per half-FEMB



Setup at BNL

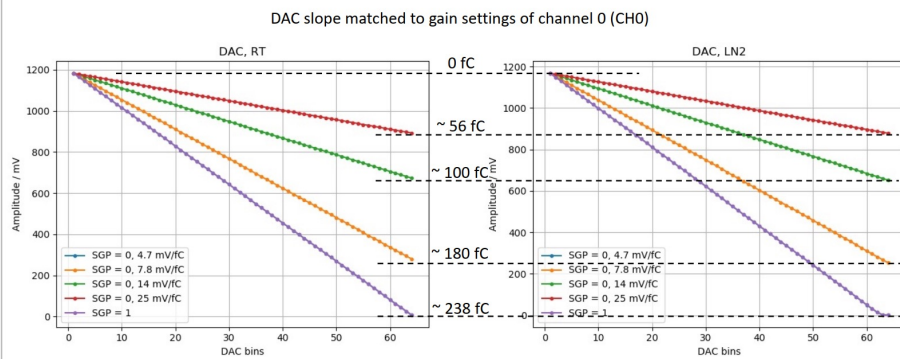
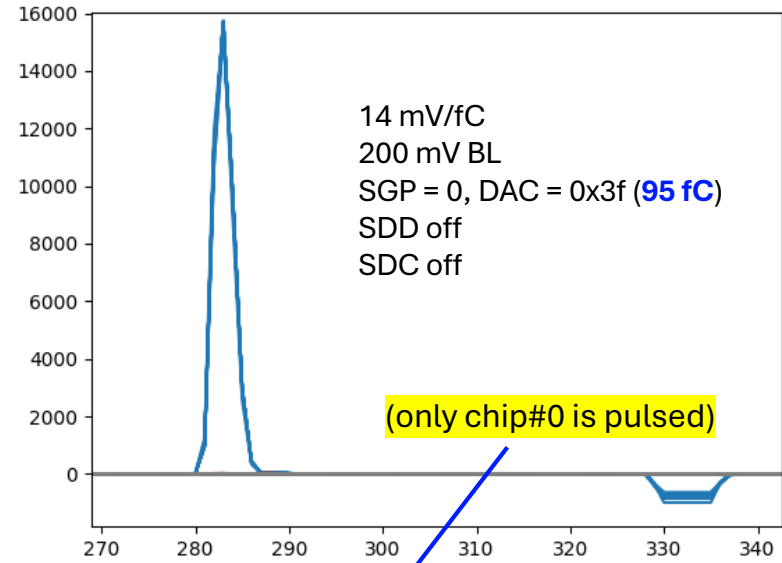
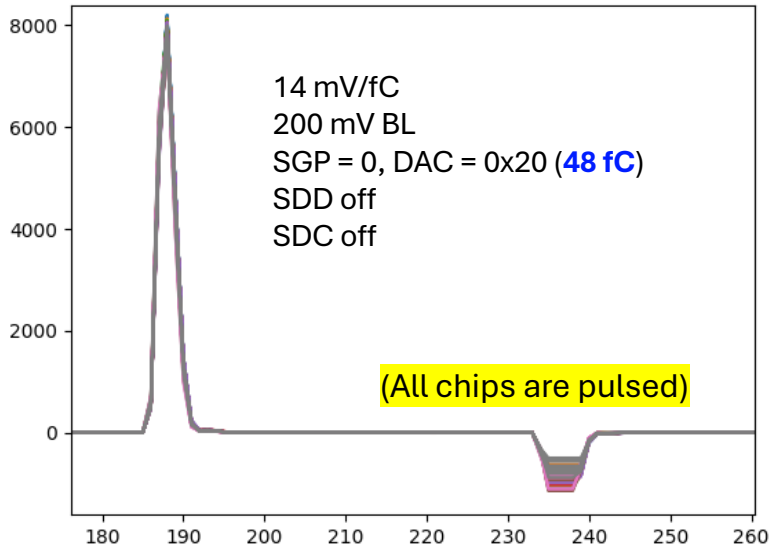


Location of LArASIC (ColdADC I2C address)



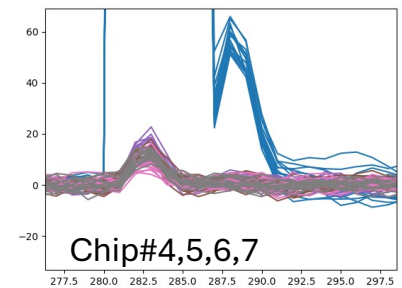
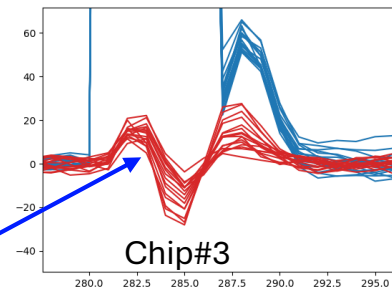
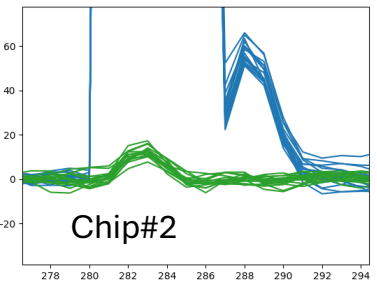
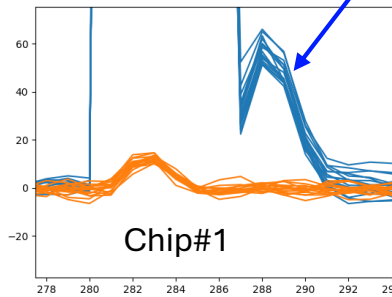
- Chip#0-3 (16x4 = 64 channels) share the same power rails on the half FEMB
- Chip#4-7 share the same power rails on the other half FEMB

At room temperature (1)



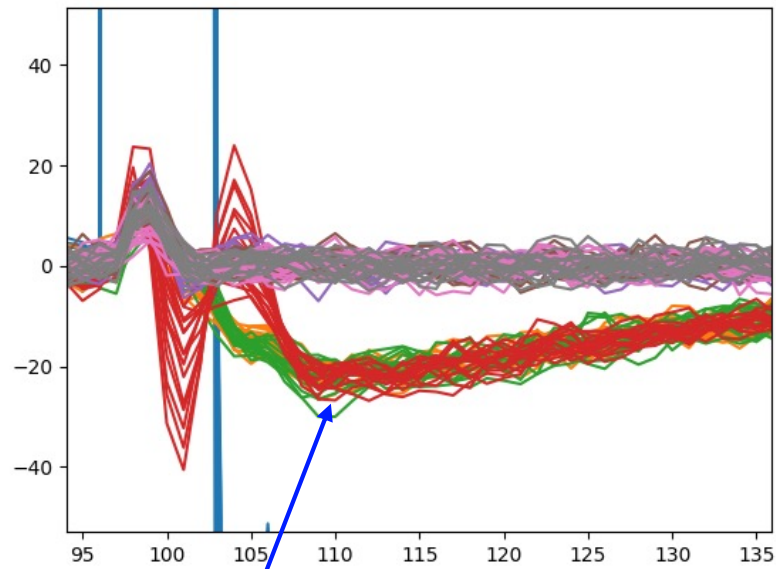
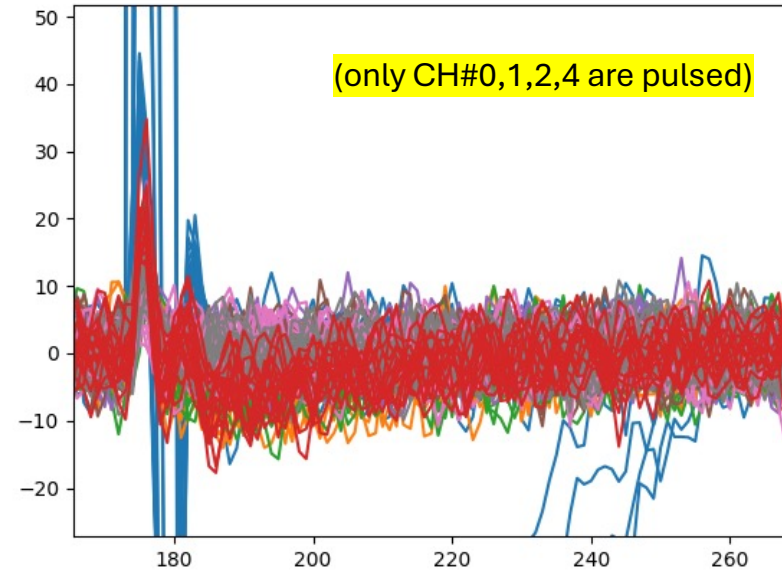
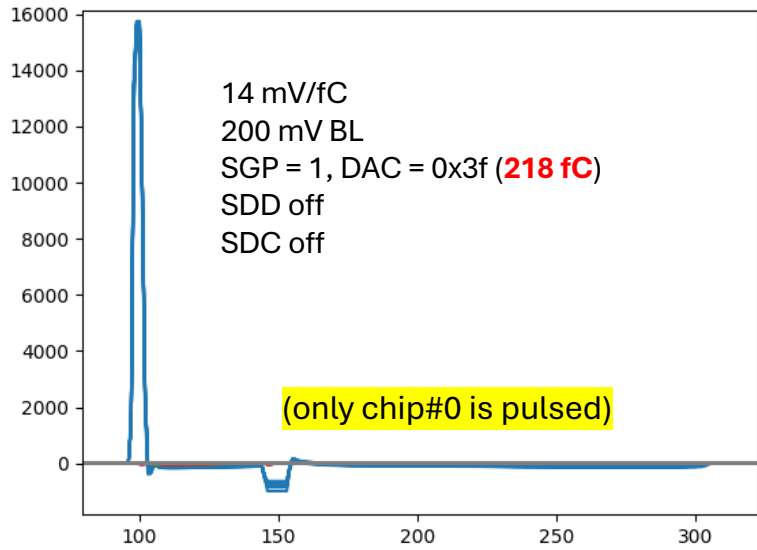
SGP = 0

- 4.7 mV/fC: DAC LSB = 18.66 mV (SGP = 1)
- 7.8 mV/fC: DAC LSB = 14.33 mV
- 14 mV/fC: DAC LSB = 8.08 mV
- 25 mV/fC: DAC LSB = 4.61 mV

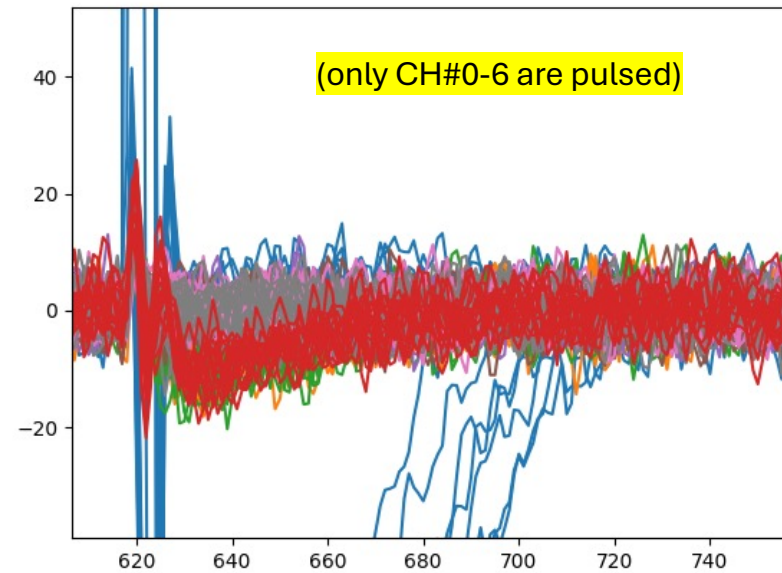


Note: Small spike (crosstalk) on chip#1,2,3,4,5,6,7 is affected by [LArASIC_PULSE](#) from COLDATA. Chip#3 and chip#0 are both on the top side

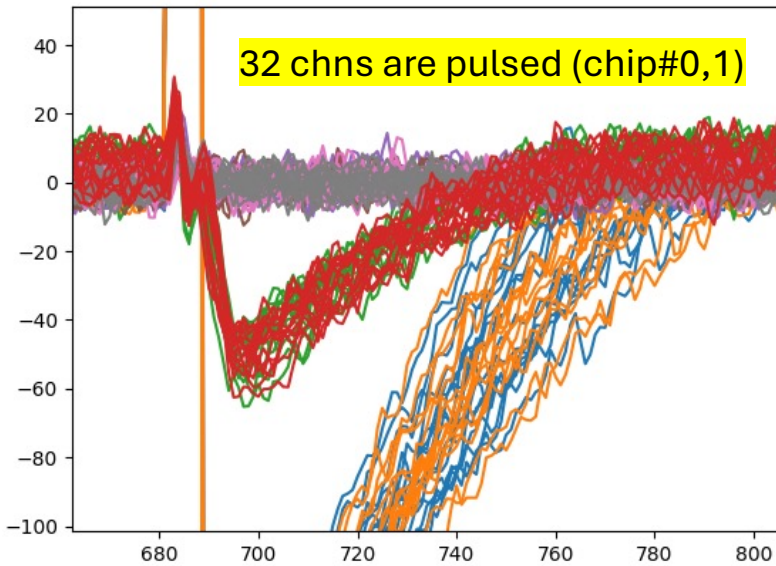
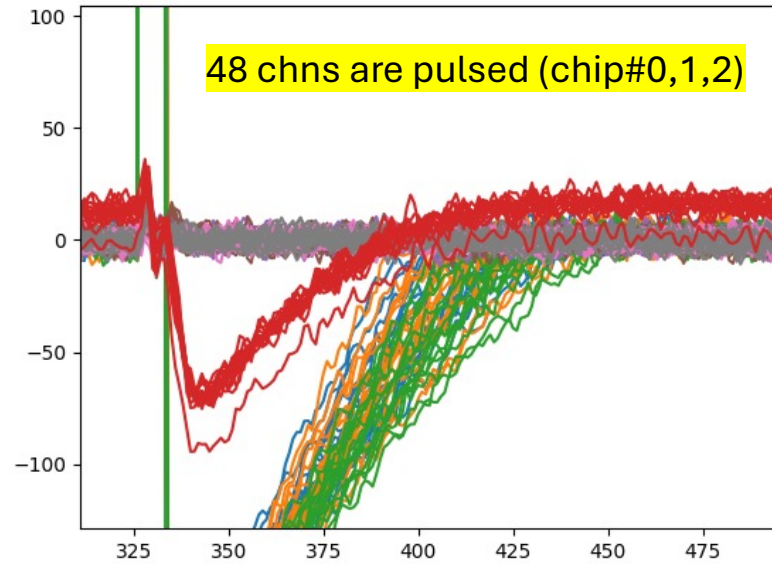
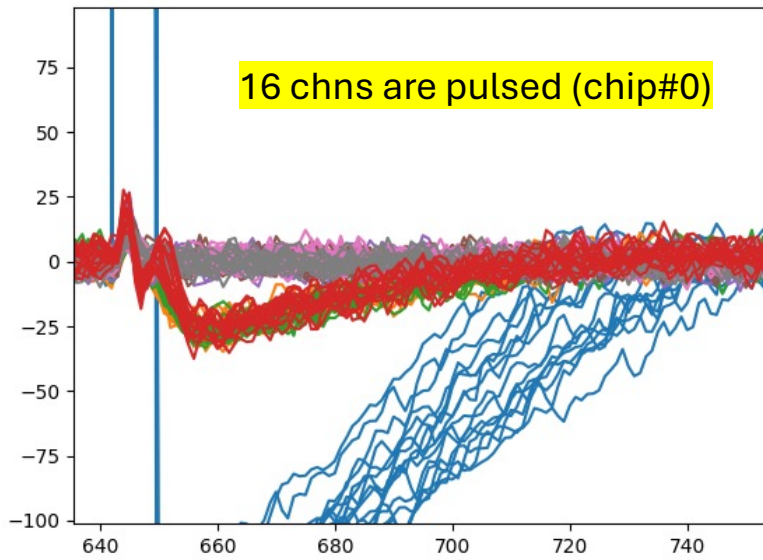
At room temperature (2)



Negative tail observed on chip#1,2,3



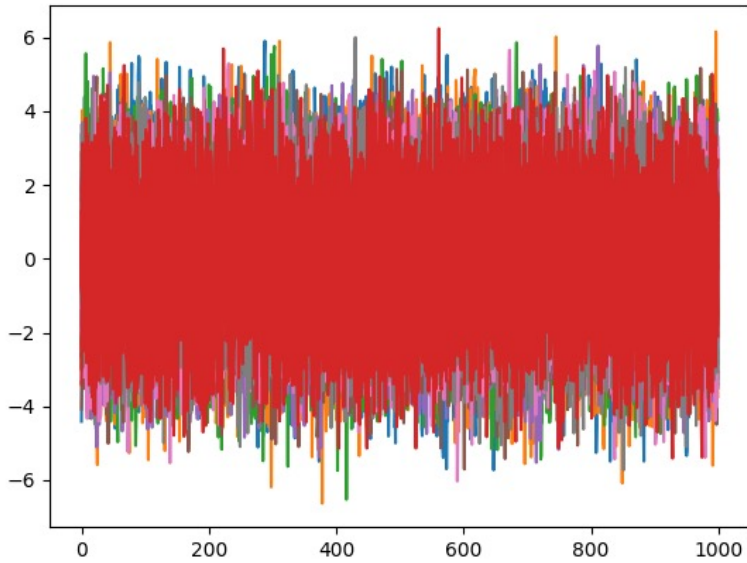
At room temperature (3)



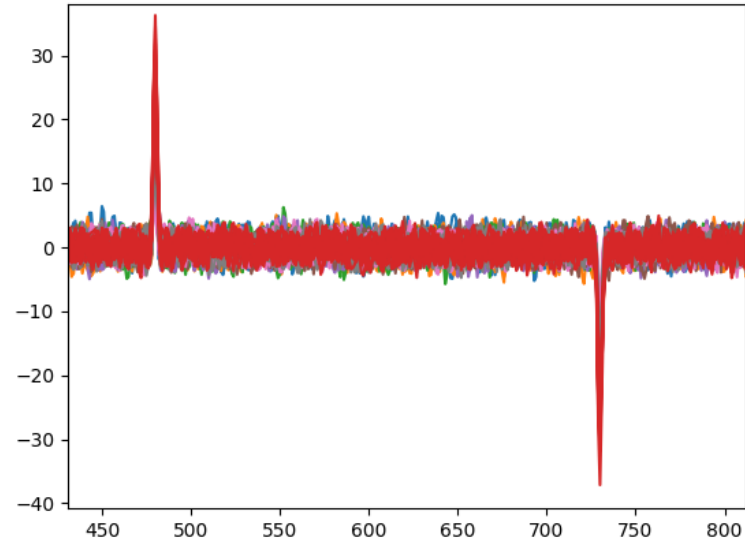
Note: Saturation response is independent of the baseline setting

At LN2

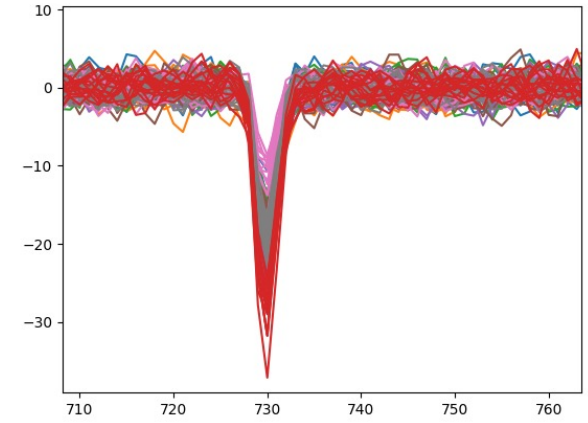
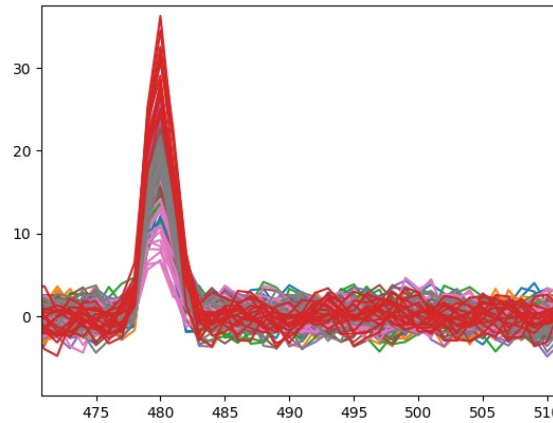
LN2



Pedestal data @ 14 mV/fC
Disable all calibration sources



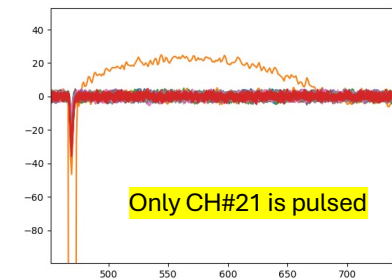
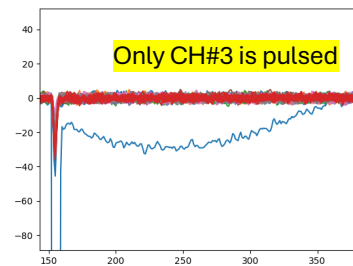
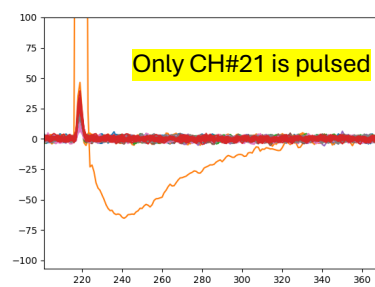
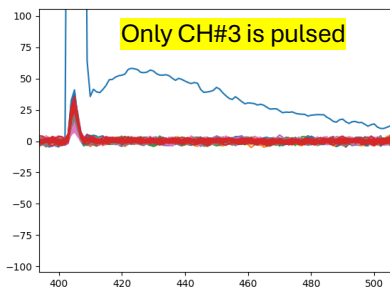
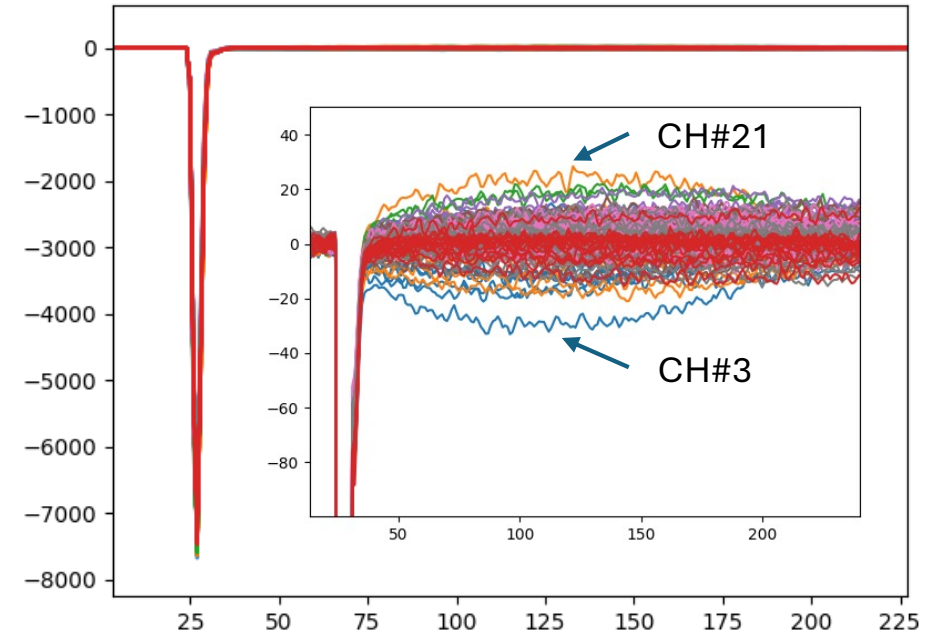
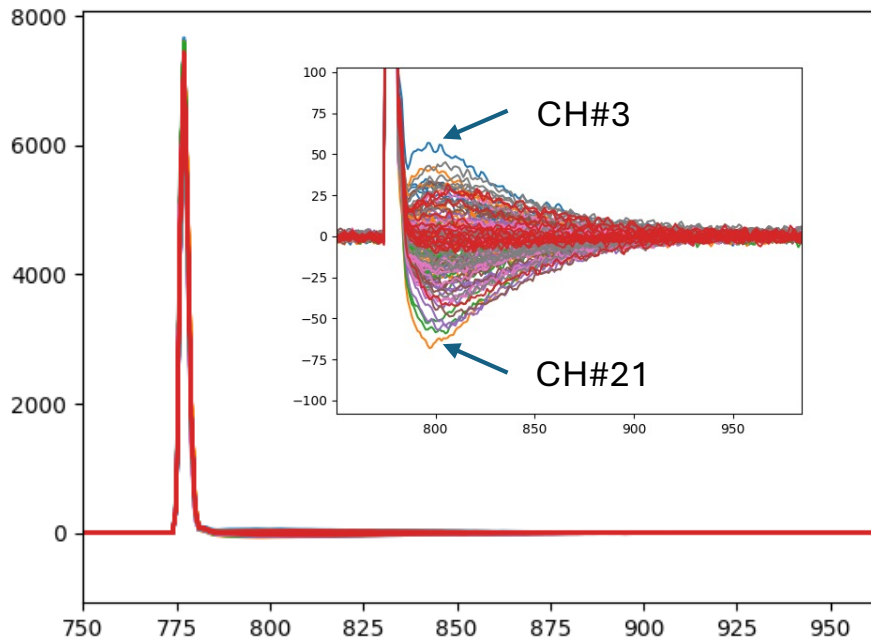
LArASIC calibration is disabled
Pulser control signals generated by COLDATAs are on



Crosstalk needs to be taken into account in the calibration data processing

LN2: All channels are pulsed

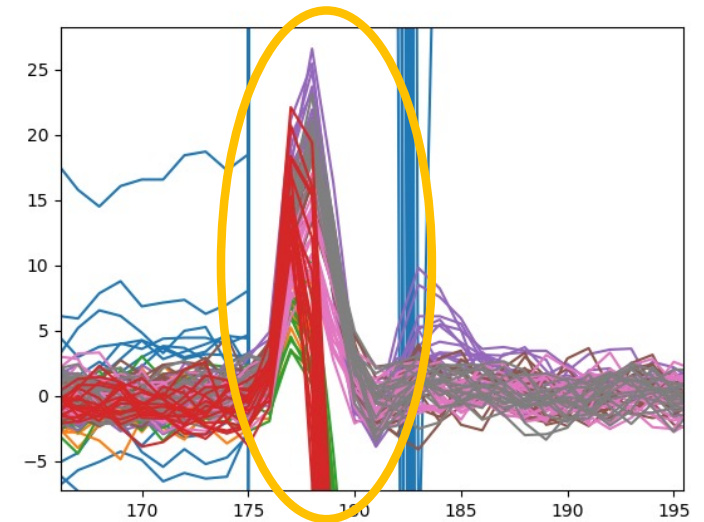
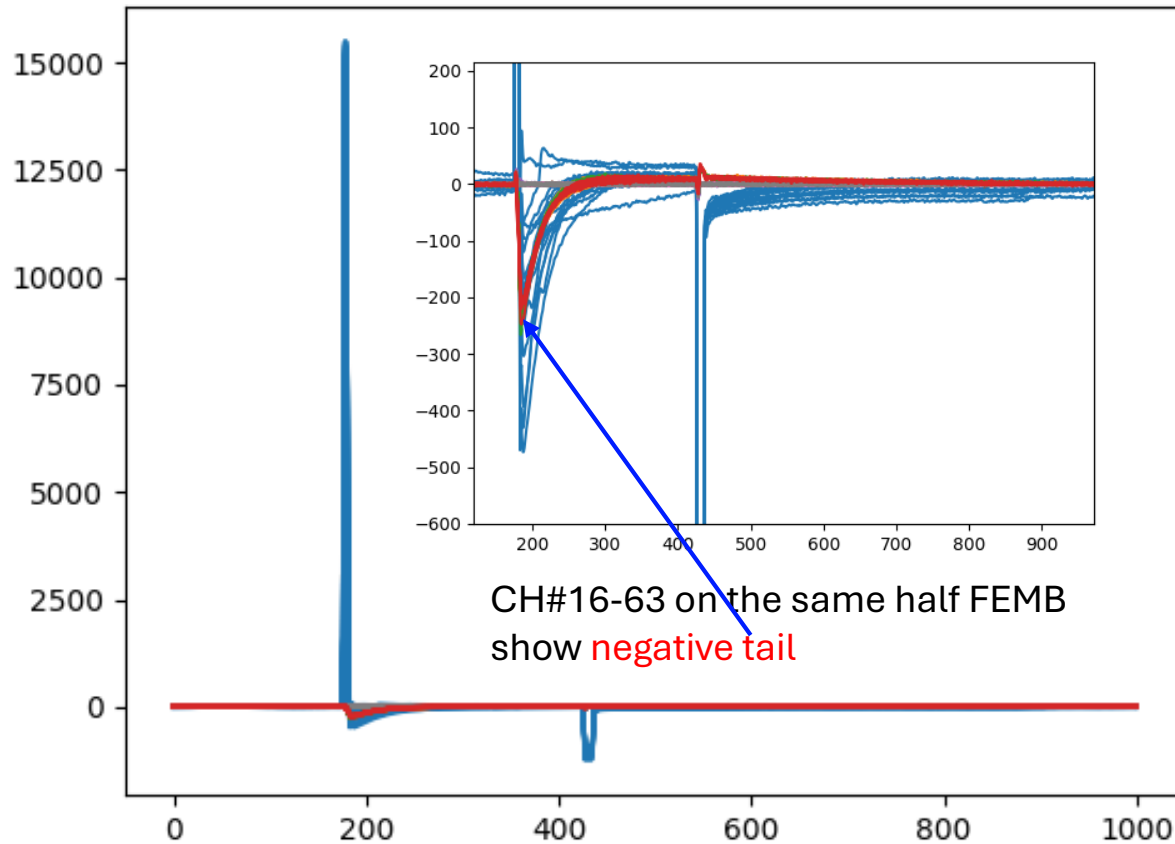
14 mV/fC, **46 fC** (sgp=0, dac=0x1f), 900 mV BL



- **Non-ideal pole-zero cancellation (return to baseline) is more pronounced at LN2 temperature due to mismatch, response is independent among different channels**
- **Negative tail is negligible when FE is not saturated**

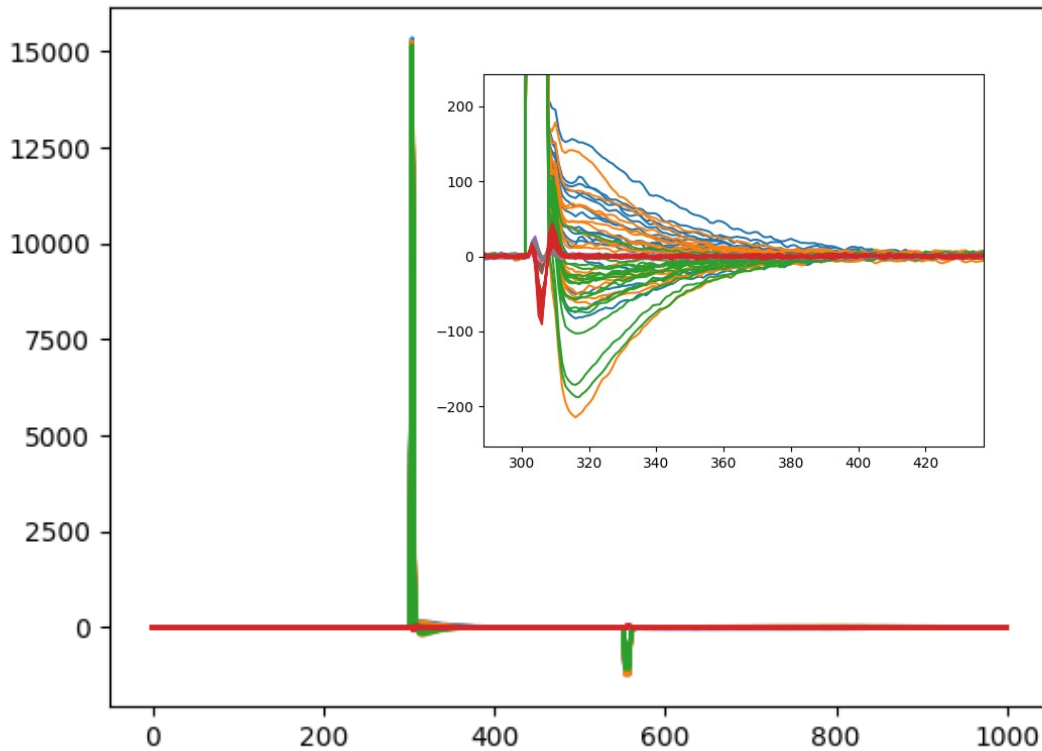
LN2: Chip#0 (16 chns) is pulsed

- sgp=1, dac=0x3f (**218 fC**), 14 mV/fC, chip#0 is 200 mV BL (other 900 mV BL)

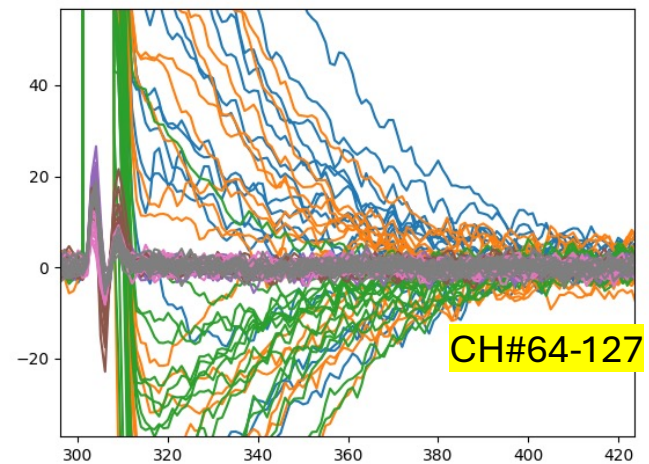
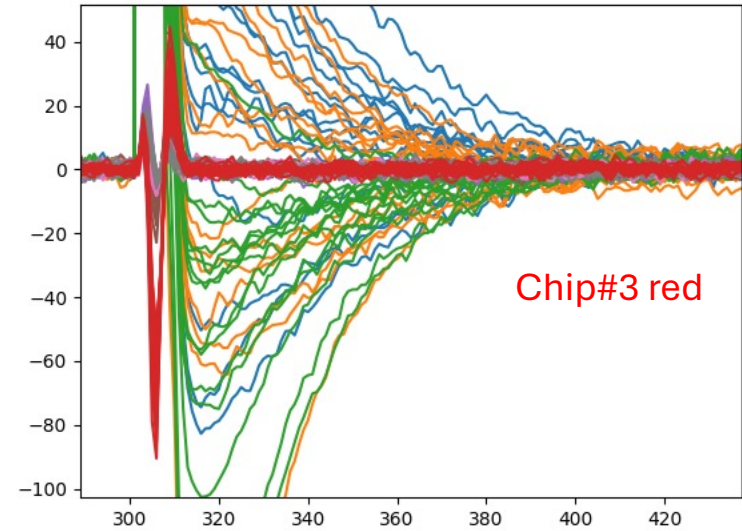


LN2: Chip#0,1,2 (48 chns) are pulsed with 95fC

- sgp=0, dac=0x3f (95 fC), 14 mV/fC, chip#0,1,2 are 200 mV BL (other 900 mV BL)

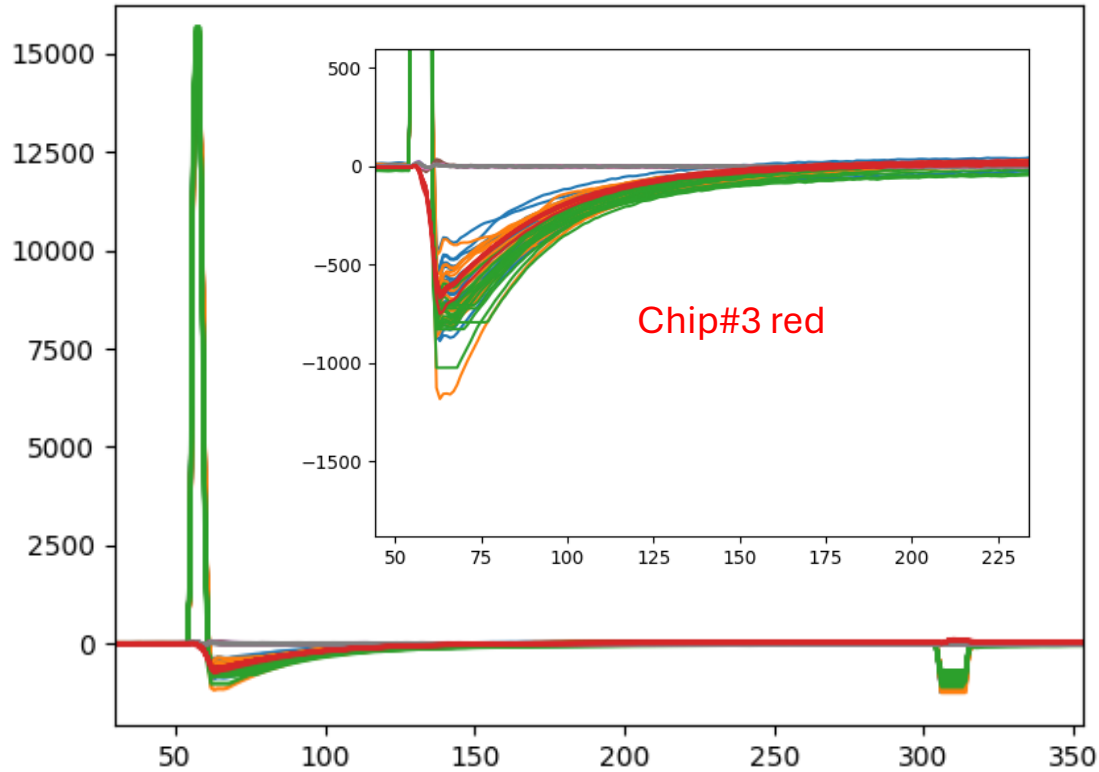


Negative tail on the same half FEMB is relatively small when FE just reaches its maximum dynamic range

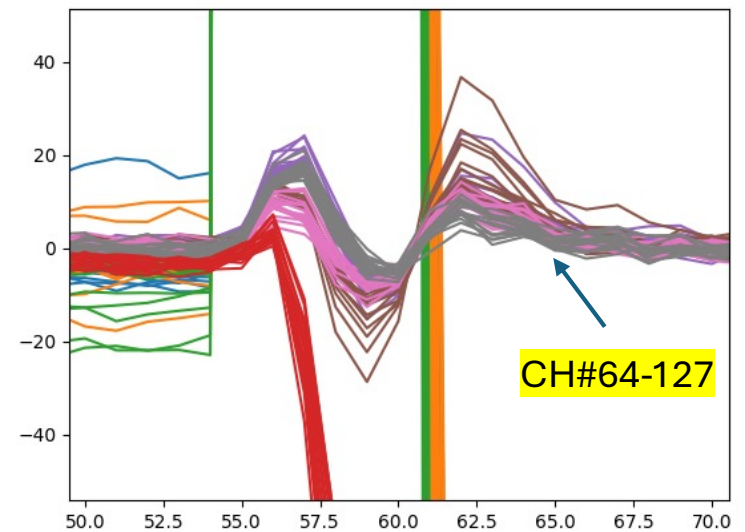


LN2: Chip#0,1,2 (48 chns) are pulsed with 218 fC

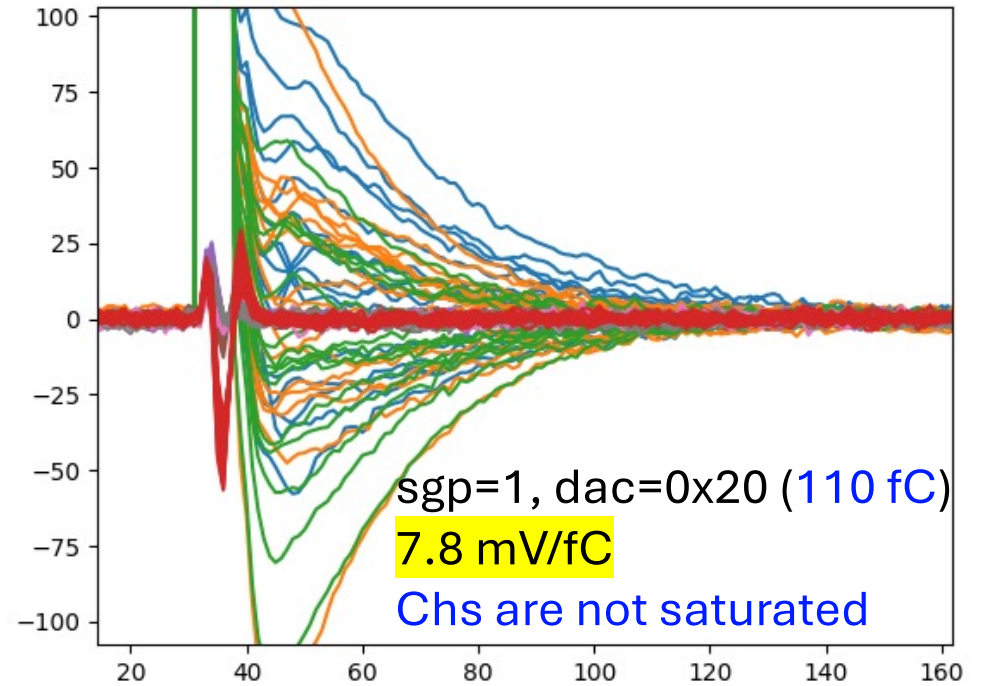
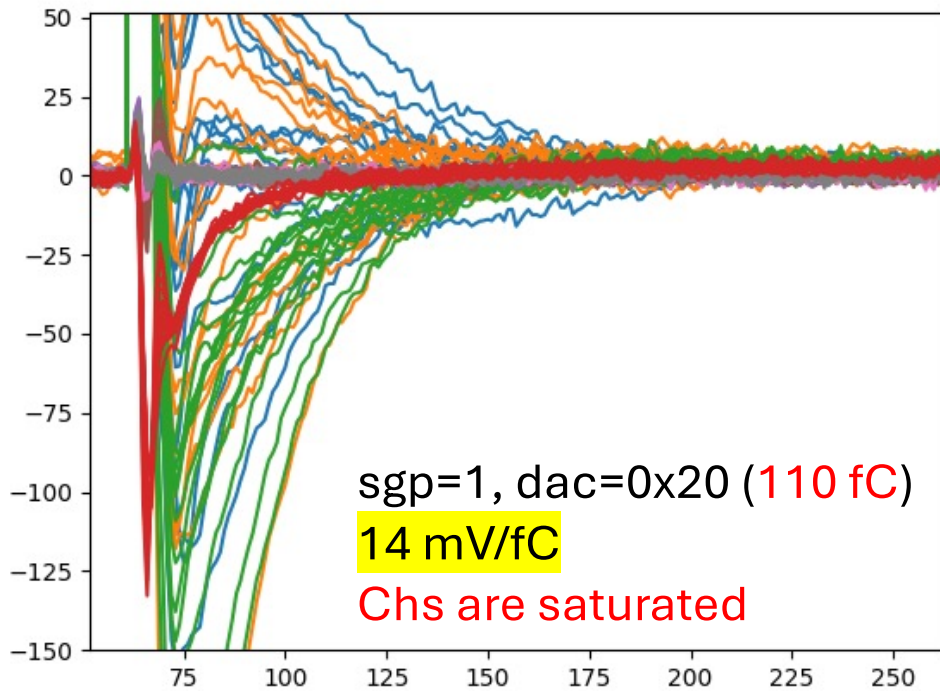
- sgp=1, dac=0x3f (218 fC), 14 mV/fC, chip#0,1,2 are 200 mV BL (other 900 mV BL)



- Negative tail of the half FEMB shows up when FE channels enter deep saturation



LN2: 3 chips (48 chns) are pulsed at 110 fC



LN2: Summary of observations

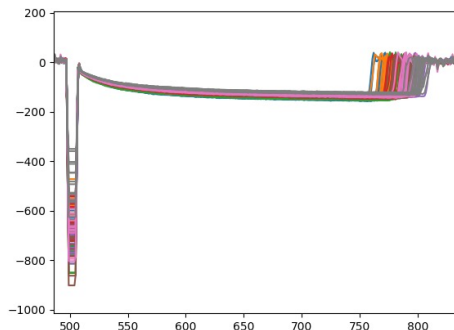
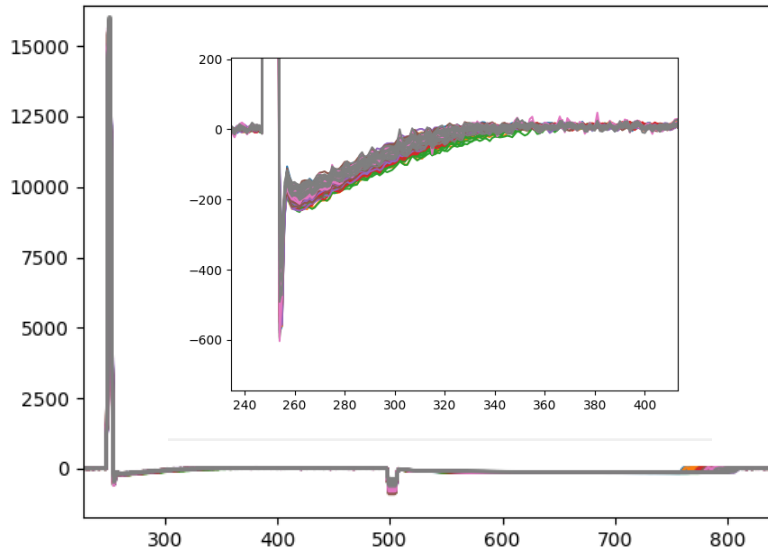
- Many more detailed measurements are in backup slides
 - Similar observations with both internal and external calibration injections
- **Negative tail shows up when channel enters saturation**
 - At LN2, even only one channel is deeply saturated, other channels on the same half FEMB show negative tail
- **The amplitude of negative tail becomes larger when more channels are deeply saturated**
 - The amplitude of negative tail has more dependency on the number of saturated channels rather than the deep saturation charge
- **Negative tail is mostly independent of**
 - Leakage current setting
 - Gain setting when channels are deeply saturated
 - Peaking time setting ($\geq 1 \mu\text{s}$)
 - Output mode setting when channels are deeply saturated

Investigation of power rails

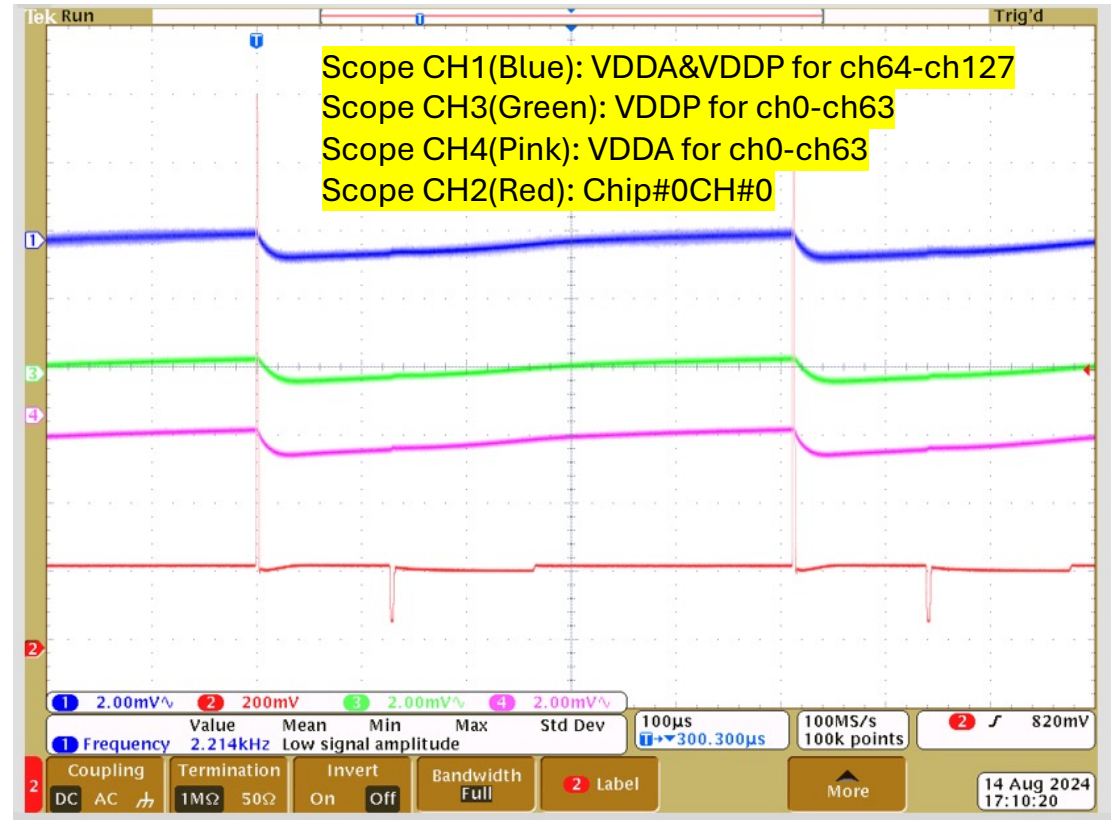
RT: Chip#0CH#0 is selected for monitoring

- All channels are pulsed at 218 fC

VDDA&VDDP of CH64-CH127 tied together
VDDA&VDDP of CH0-CH63 tied together



200mV BL

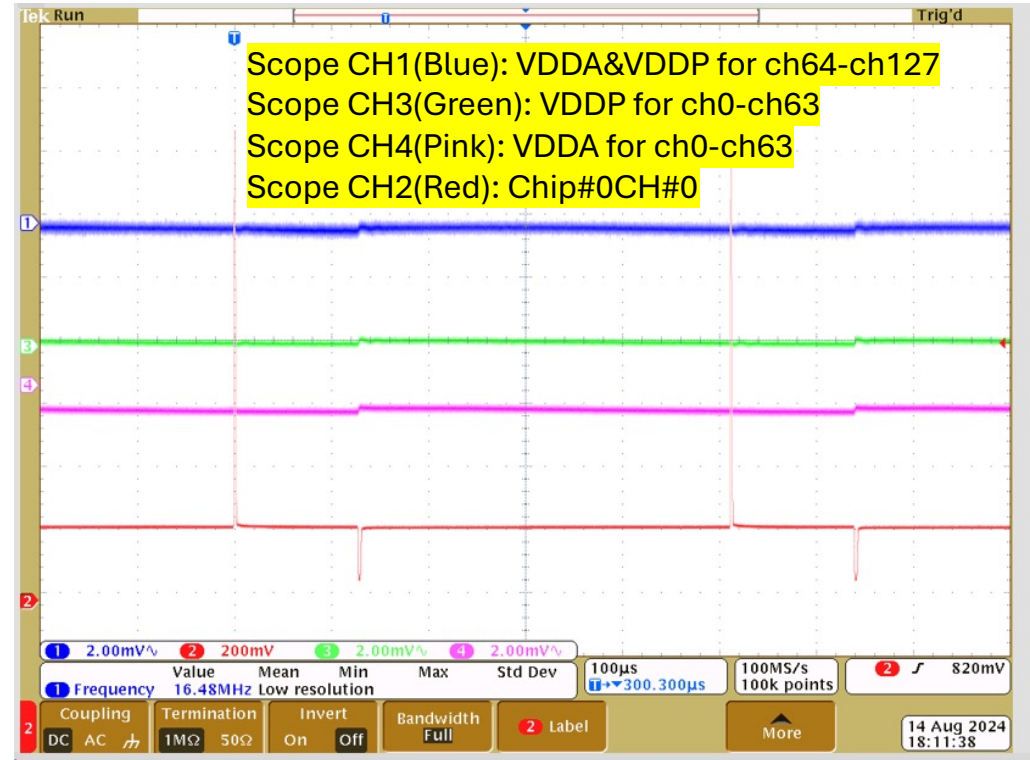
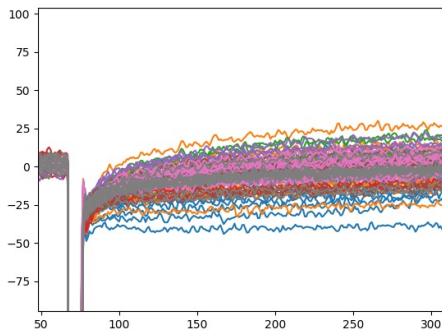
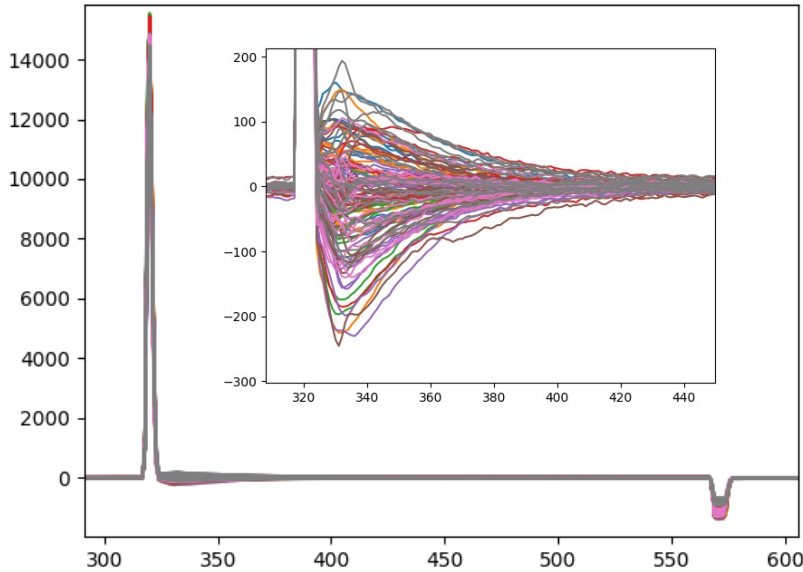


Sagging of 1.8V power rail is observed

LN2: Chip#0CH#0 is selected for monitoring

- All channels are pulsed at 95 fC

VDDA&VDDP of CH64-CH127 tied together
VDDA&VDDP of CH0-CH63 tied together

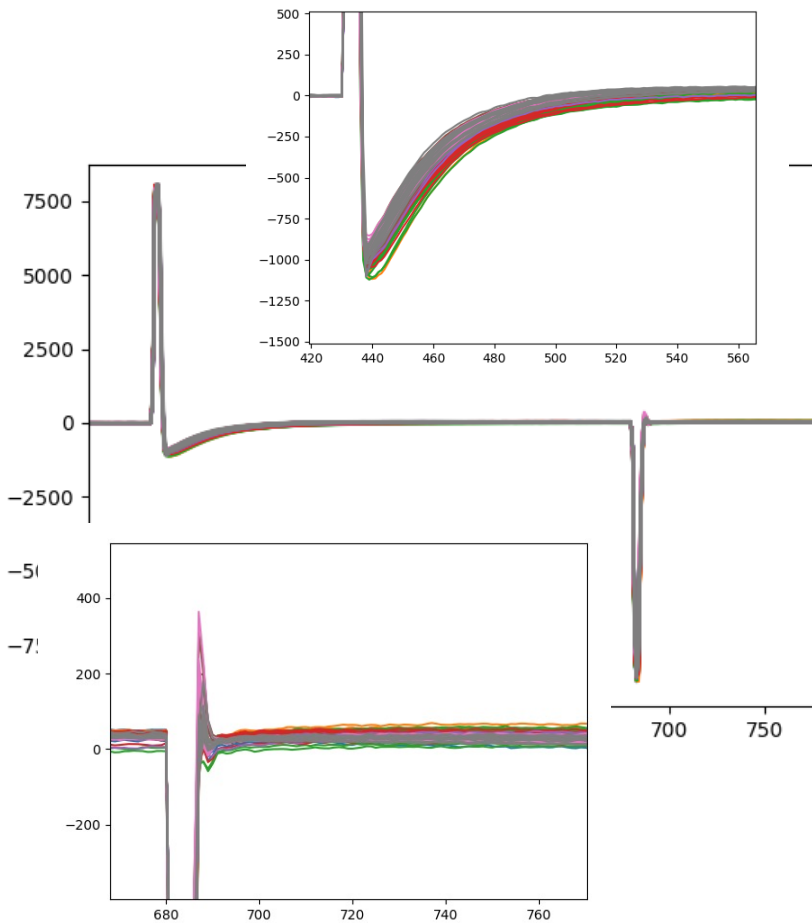


No obvious sagging of 1.8V power rail before FE saturation

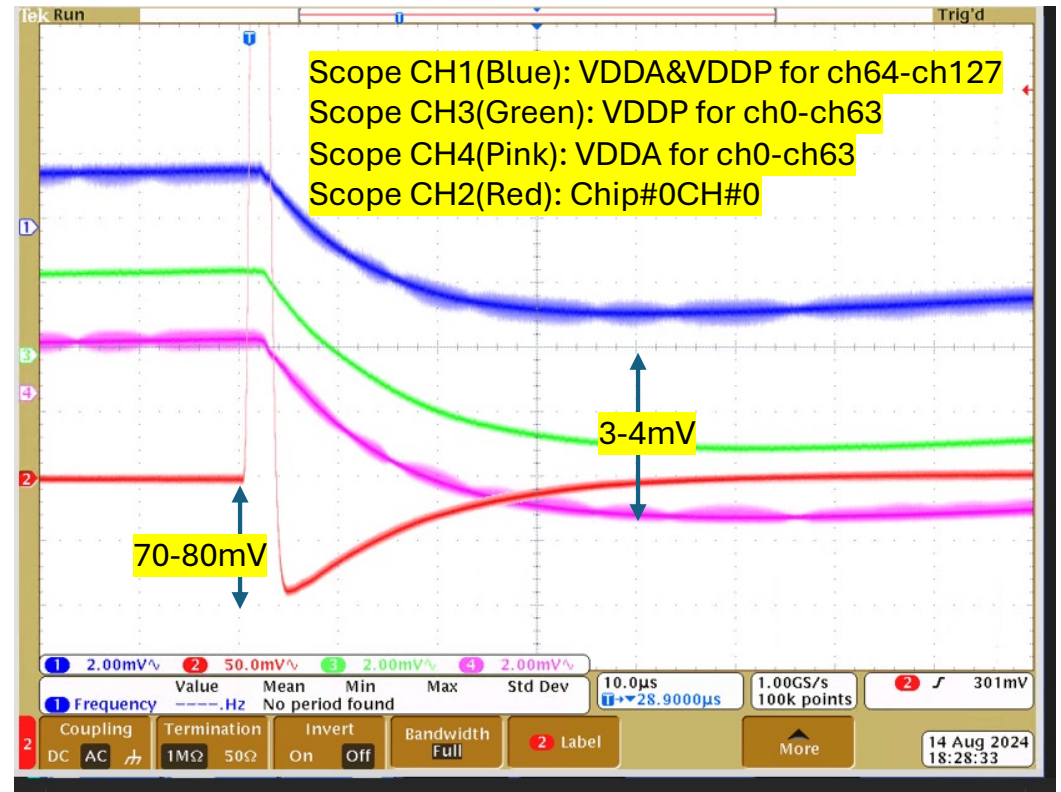
LN2: Chip#0CH#0 is selected for monitoring

- All channels are pulsed at 218 fC

VDDA&VDDP of CH64-CH127 tied together
VDDA&VDDP of CH0-CH63 tied together



900 mV BL

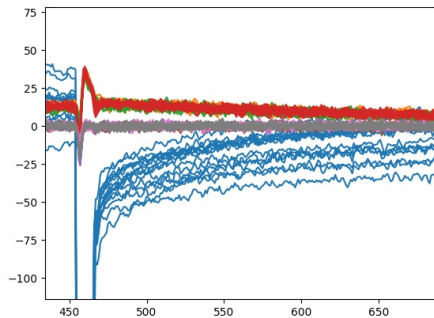
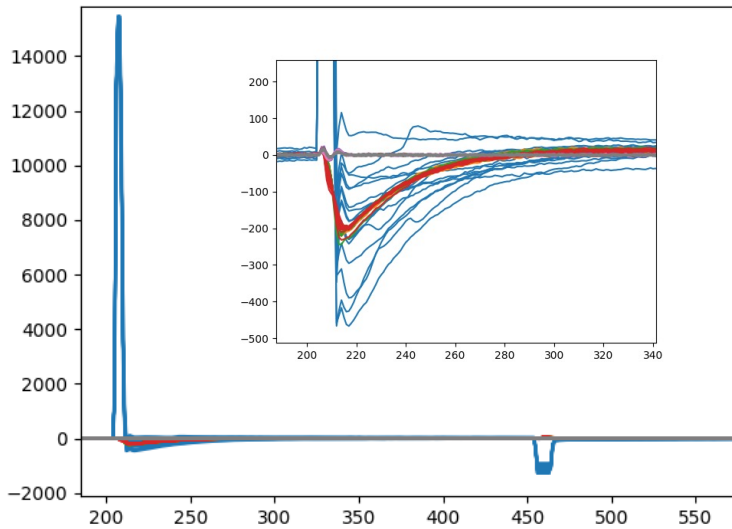


Sagging of 1.8V power rail is observed

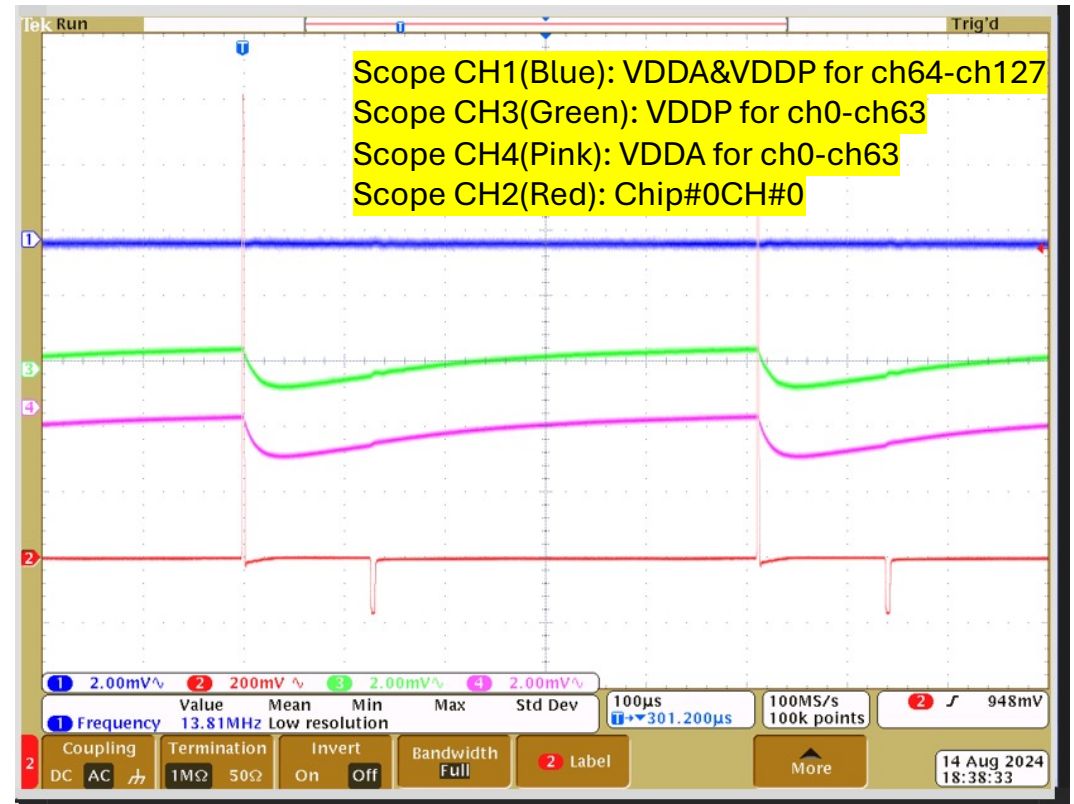
Note: Negative tail is sensitive to insufficient power

LN2: Chip#0CH#0 is selected for monitoring

- Chip#0(16 chns) is pulsed at **218 fC** VDDA&VDDP of CH64-CH127 tied together
VDDA&VDDP of CH0-CH63 tied together



200 mV BL



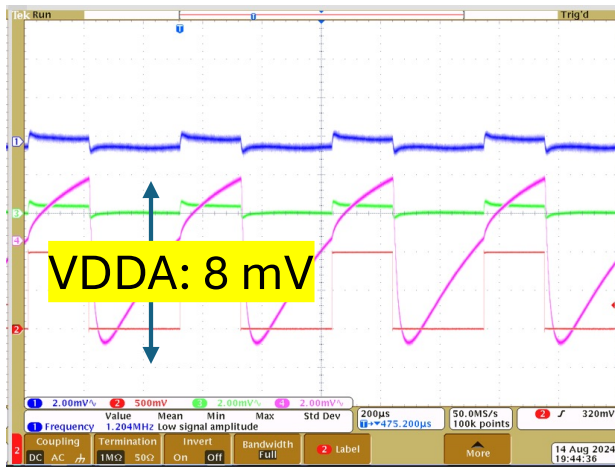
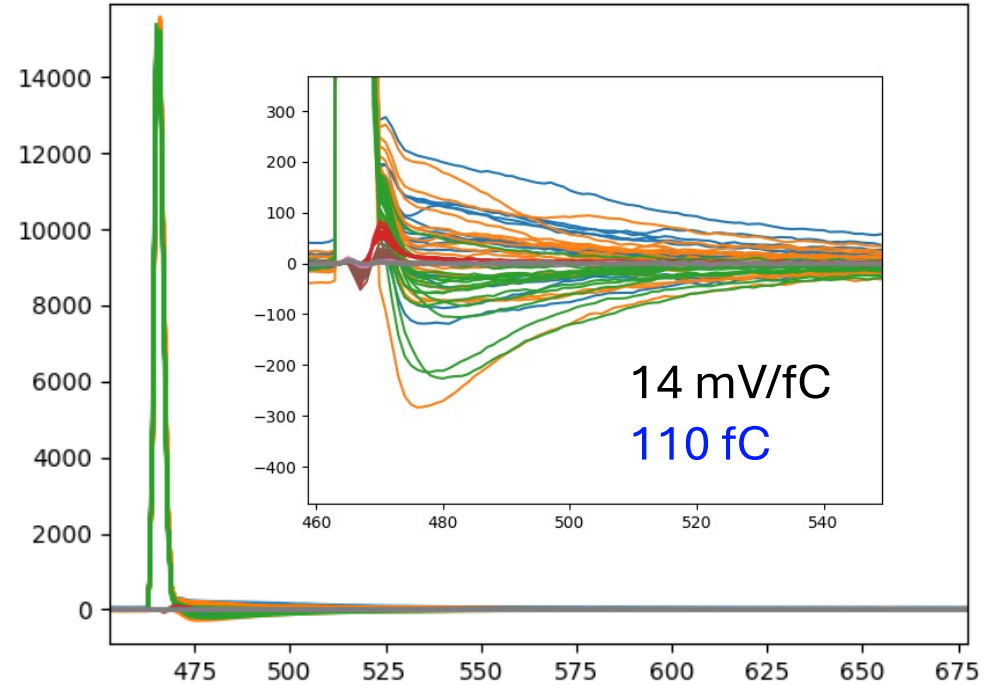
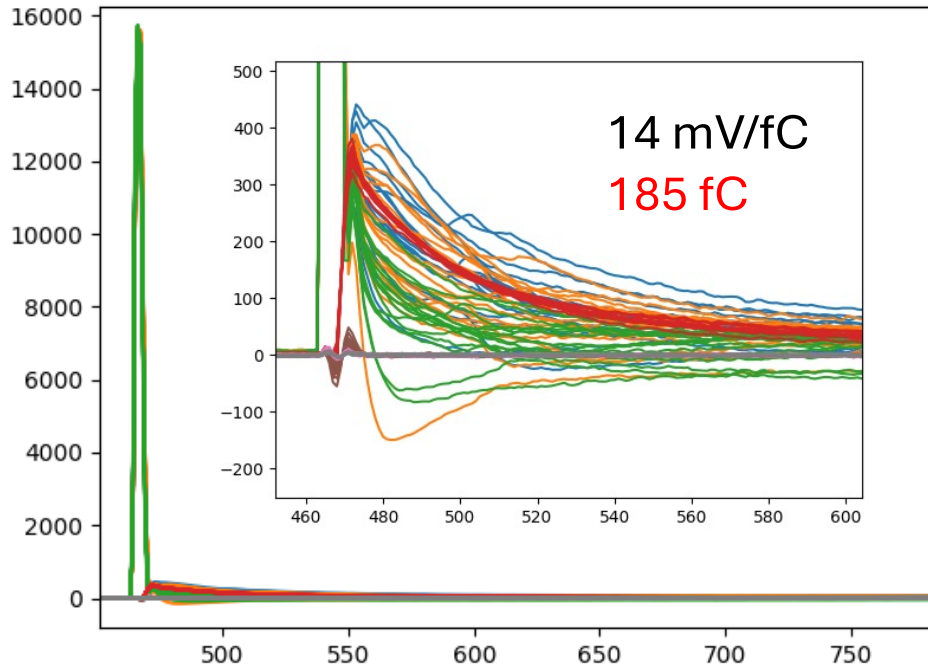
Sagging of 1.8V power rail is observed

- Negative tail is correlated to the sagging of power rails
- Many more detailed measurements are in backup slides
 - Similar observations with both internal and external calibration injections

Separate VDDP and VDDA

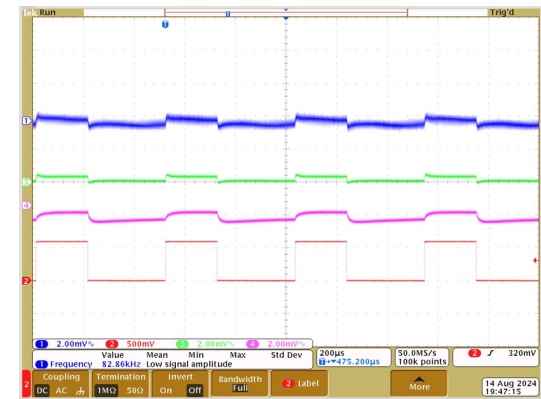
CH#0-63: VDDA & VDDP are separated

- External calibration pulser from WIB



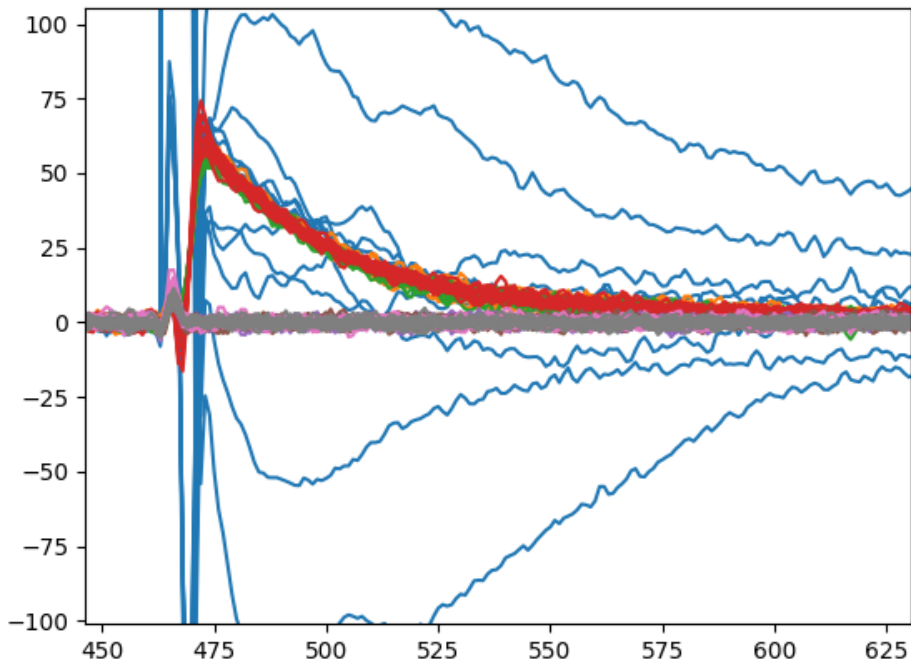
Chip#0,1,2 (48chns) are pulsed

Sagging of VDDA is observed

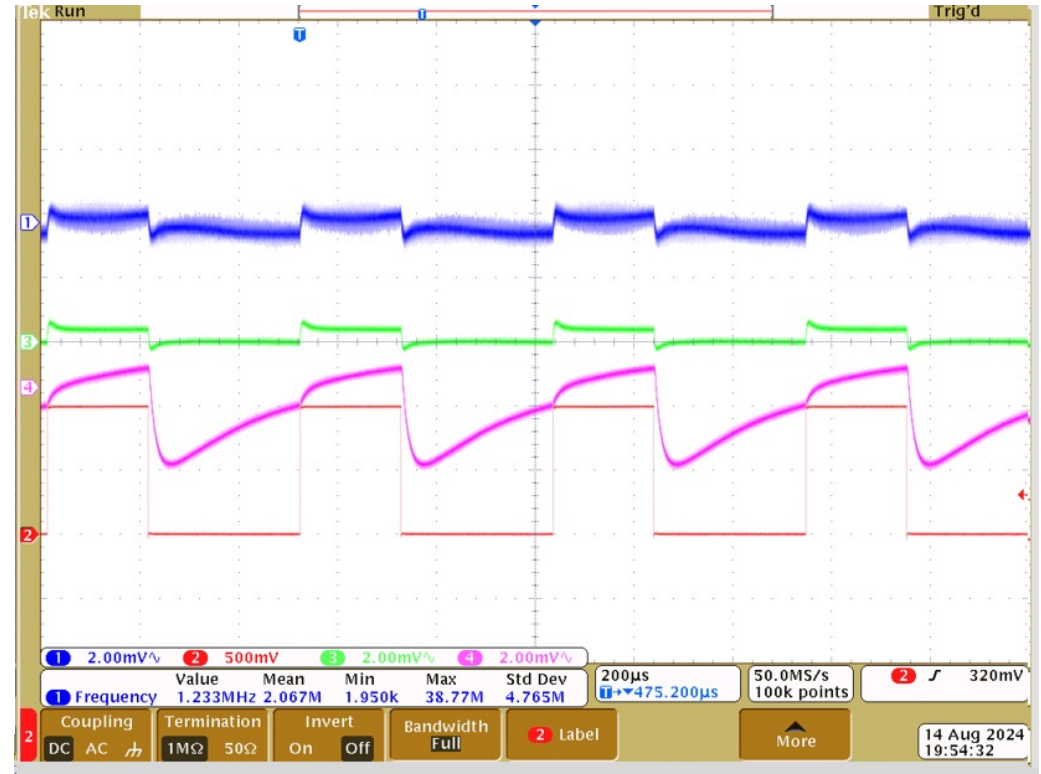


CH#0-63: VDDA & VDDP are separated

- Chip#0 (8chns) are pulsed



1000 mV (185 fC)

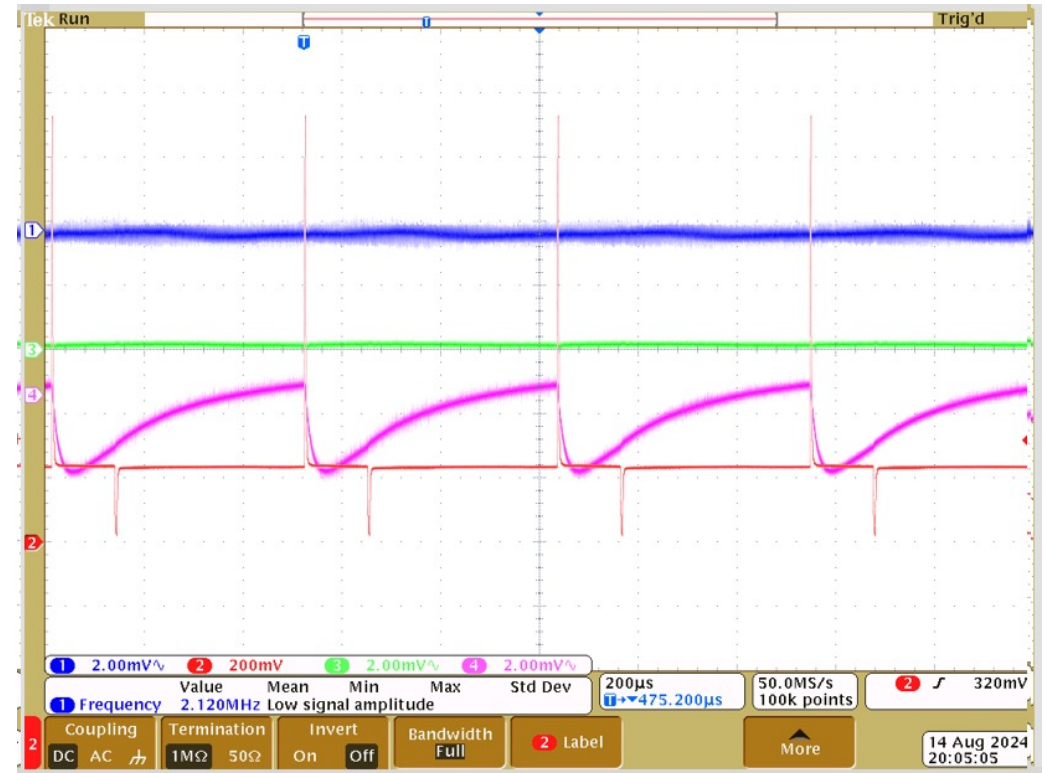
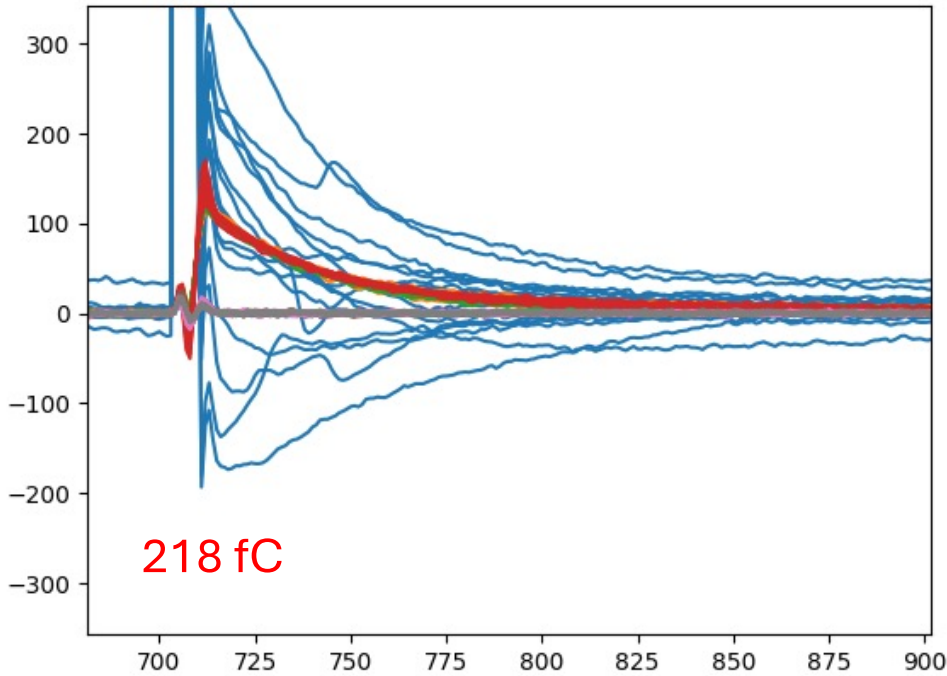


- Long tail is correlated to the sagging of VDDA (shaper)
- Separation of VDDP and VDDA changes the tail polarity, positive tail is observed with slightly reduced amplitude

Adjust RC filter

CH#0-63: VDDA & VDDP are separated

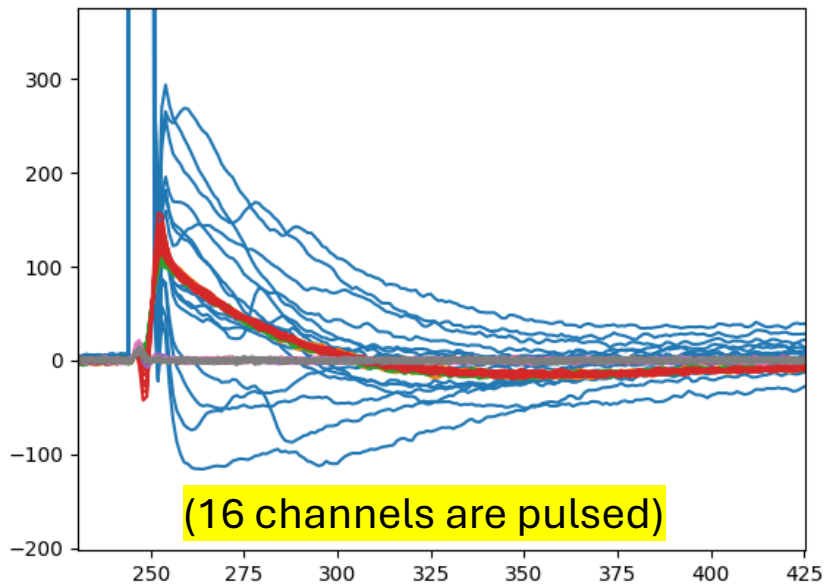
- Chip#0 (16chns) are pulsed with LArASIC-DAC



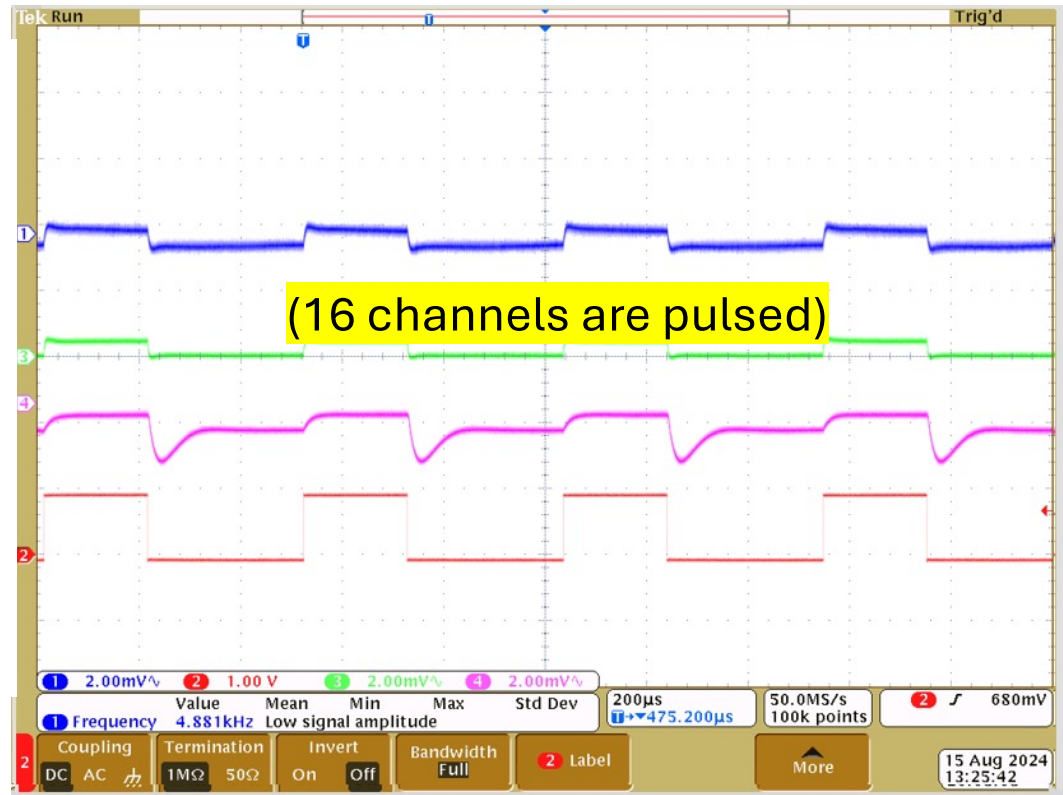
RC filter: R = 1 Ohm

CH#0-63: VDDA & VDDP are separated

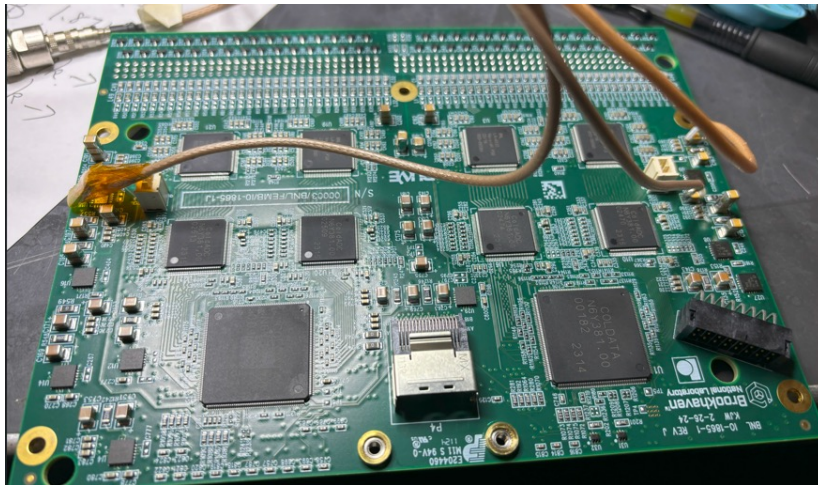
- Chip#0 (16chns) are pulsed by signal generator (185 fC)
 - Power rail VDDA recovers faster with smaller R, but the long tail doesn't decrease significantly



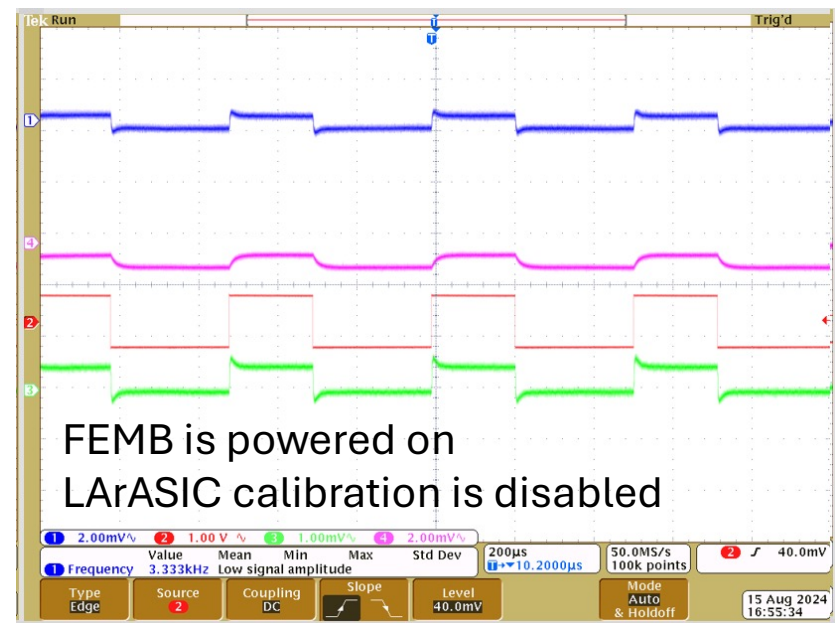
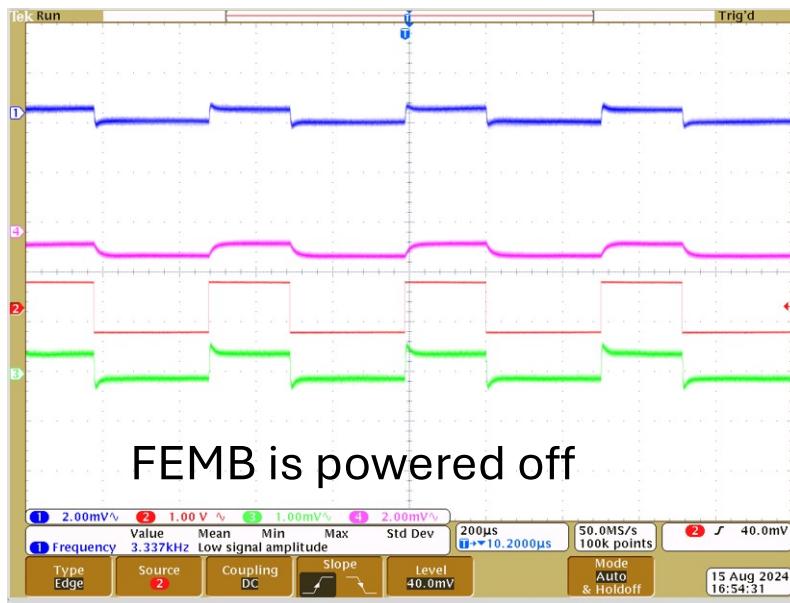
RC filter: VDDA R = 0.1Ohm



Experiment more 330 uF capacitors

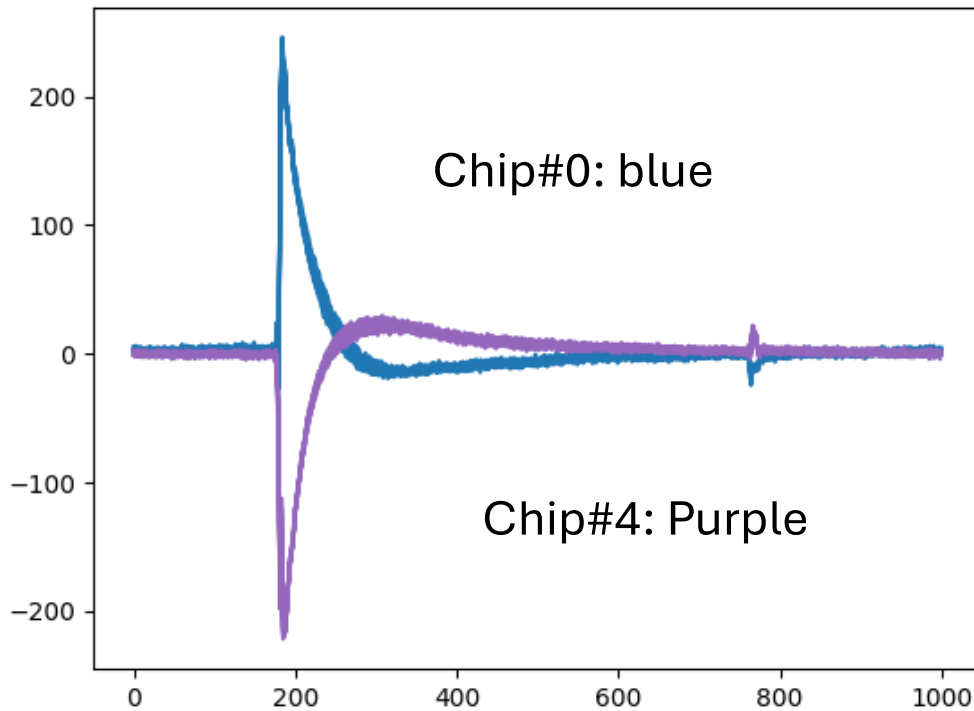


- External Pulser from Signal Generator: **Note** coupling of scope channels



External Pulser from Signal Generator

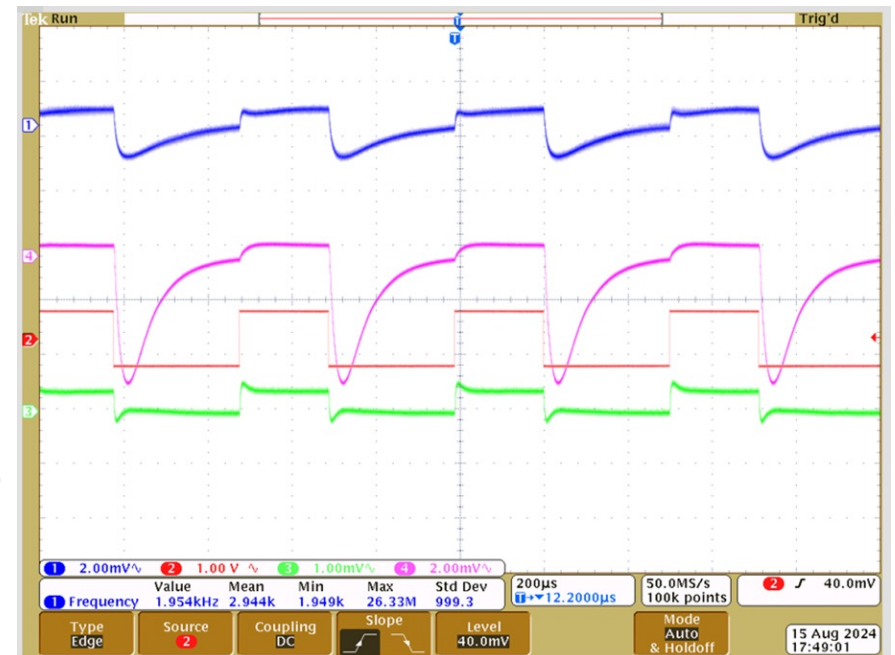
- Chip#1,2,3,5,6,7 are pulsed at **185 fC**



VDDA for chip0-3: **0.1 Ohm, 2x C**

VDDP for chip0-3: **0.1 Ohm, 1x C**

VDDA/VDDP (tied together) for chip 4-8: **0.1Ohm, 3x C**



Scope CH1(Blue): VDDA&VDDP for ch64-ch127

Scope CH3(Green): VDDP for ch0-ch63

Scope CH4(Pink): VDDA for ch0-ch63

Scope CH2(Red): CH#0

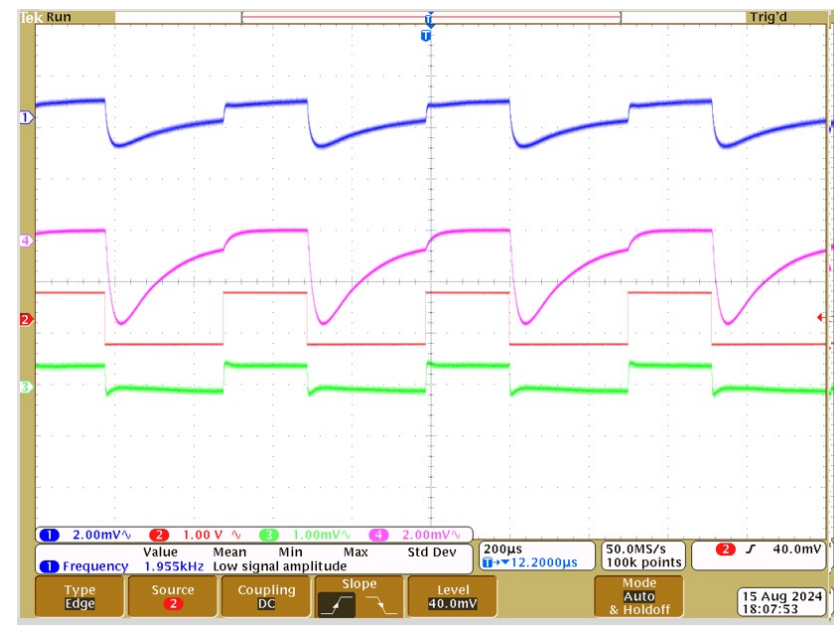
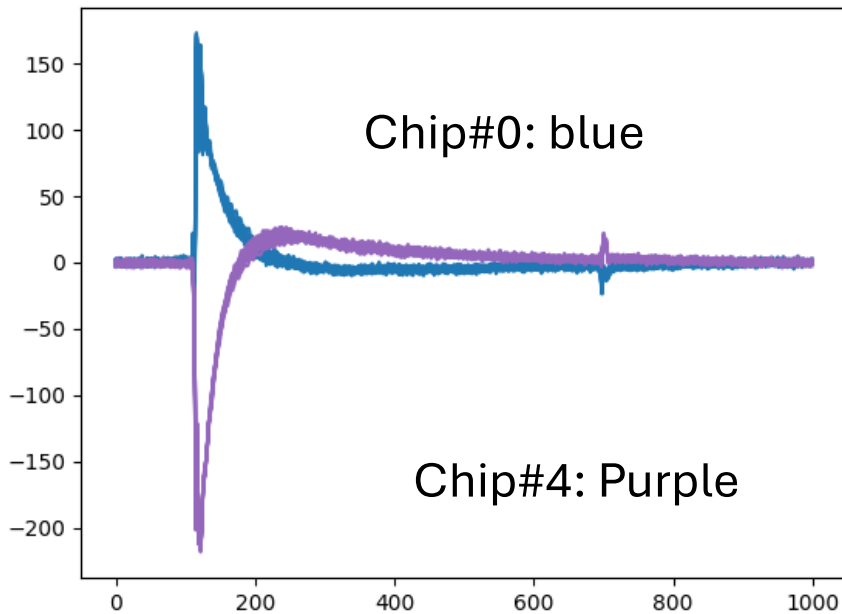
External Pulser from Signal Generator

- Chip#1,2,3,5,6,7 are pulsed at **185 fC**

VDDA for chip0-3: **0.1 Ohm, 4x C**

VDDP for chip0-3: **0.1 Ohm, 1x C**

VDDA/VDDP (tie together) for chip 4-8: **0.1 Ohm, 3x C**



- Many more detailed measurements are in backup slides
- Adding capacitors can help mitigate the long tail
- However, FEMB has very little room to add twice or even four times of capacitors

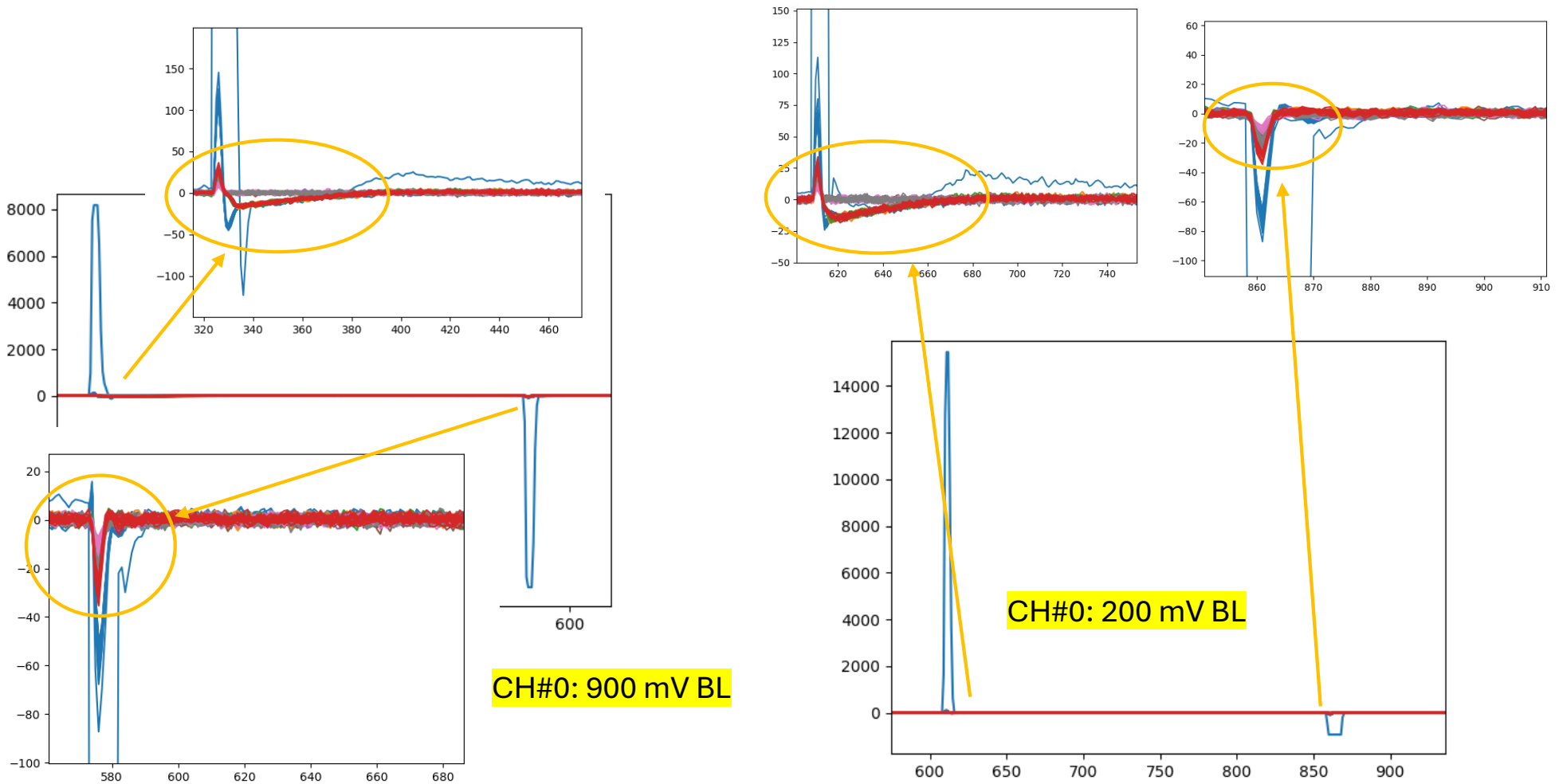
Summary

- Negative tail of the half FEMB observed in NP04 has been re-produced in lab bench tests
 - Negative tail shows up when channel enters saturation
 - The amplitude of negative tail becomes larger when more channels are deeply saturated
- Investigation shows the negative tail is correlated to the sagging of VDDA when FE channel is deeply saturated
 - Separate VDDA and VDDP will change the polarity of long tail, although which is not recommended from the FE ASIC design
 - See page 23 of the ASIC FDR document
 - https://edms.cern.ch/ui/file/2314428/2/LArASICDevelopment.20210714_docx_cp.pdf.pdf
 - Adjustment of RC filter, particularly adding capacitors, helps mitigate the long tail but can't eliminate it
 - Adding more capacitors on FEMB would be challenging
- Proposed next steps
 - Reduce the gain of FE ASIC to 7.8 mV/fC will extend the dynamic range and reduce the probability of saturation
 - Collection plane ~180 fC and induction plane ~90 fC
 - Impact on physics analysis to be evaluated
 - Data processing to make offline correction of negative tail could be explored, related to the crosstalk and pole-zero cancellation studies

Backup Slides

LN2: CH#0 is pulsed with 218 fC

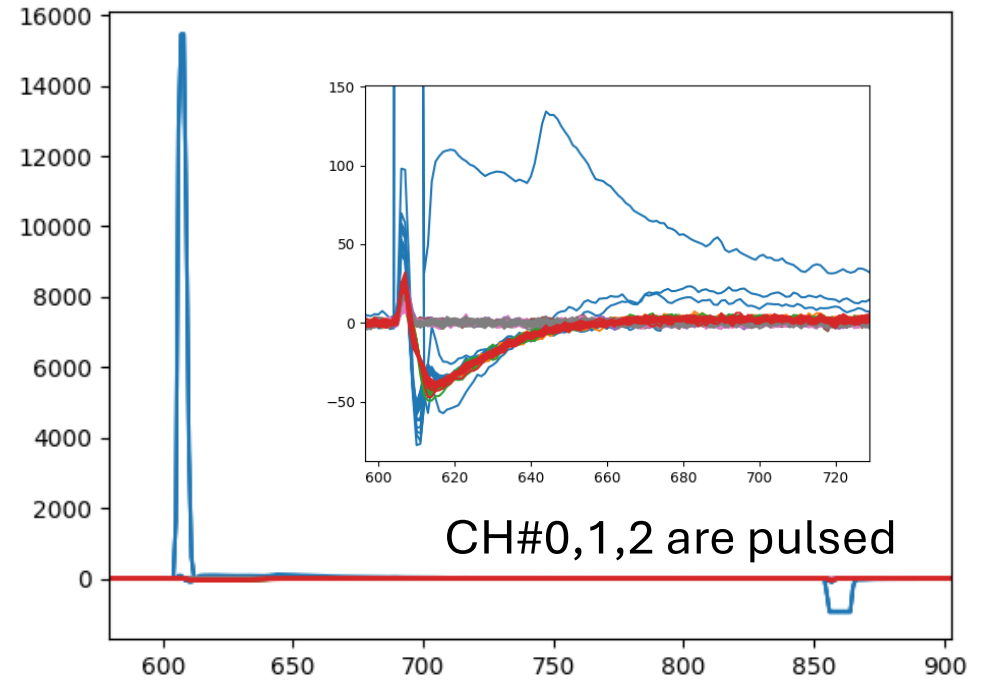
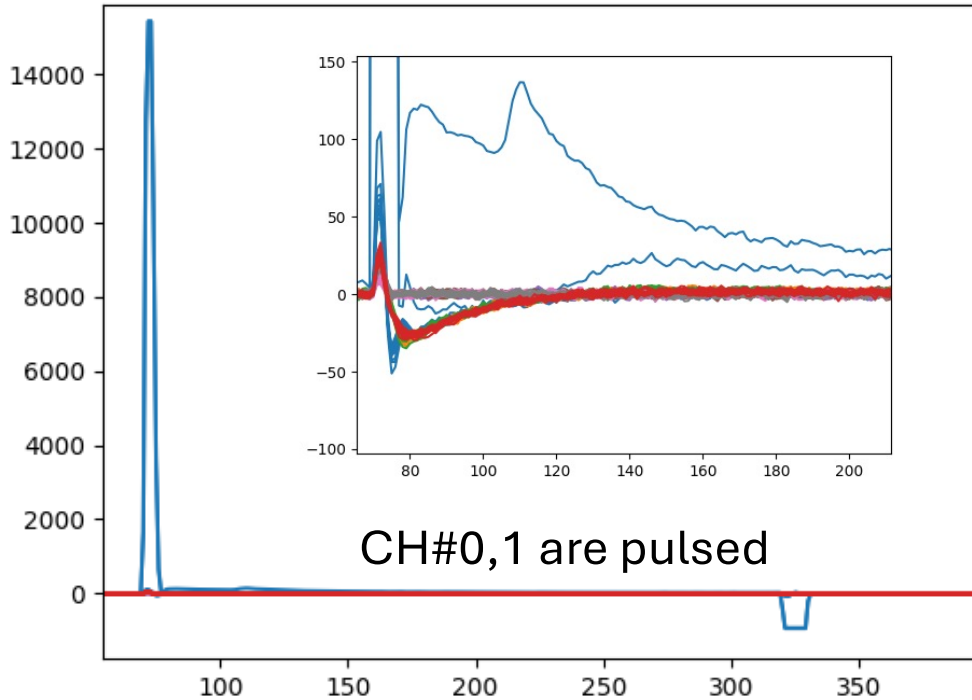
- sgp=1, dac=0x3f (218 fC), 14 mV/fC, chip#0 CH#0 (other 900mV BL)



At LN2, even only one channel is deeply saturated, other channels on the same half FEMB show negative tail

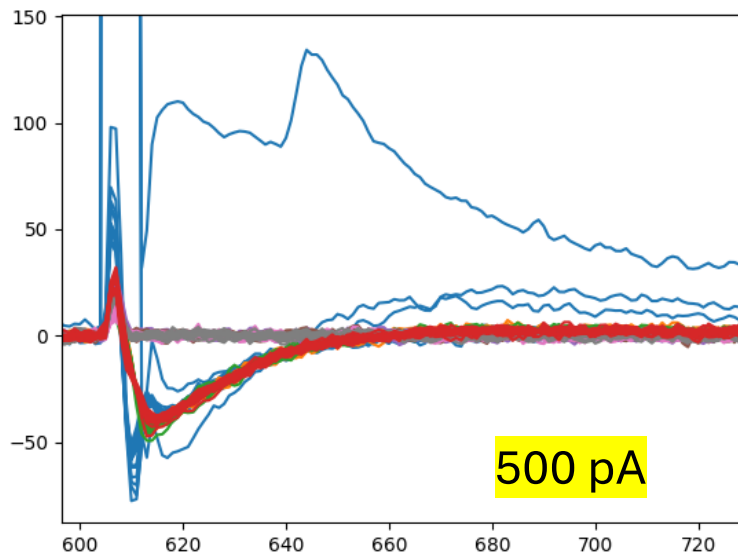
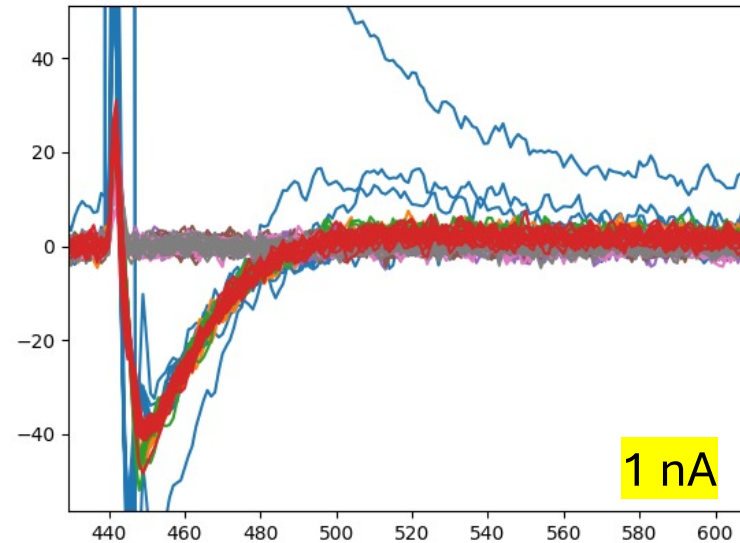
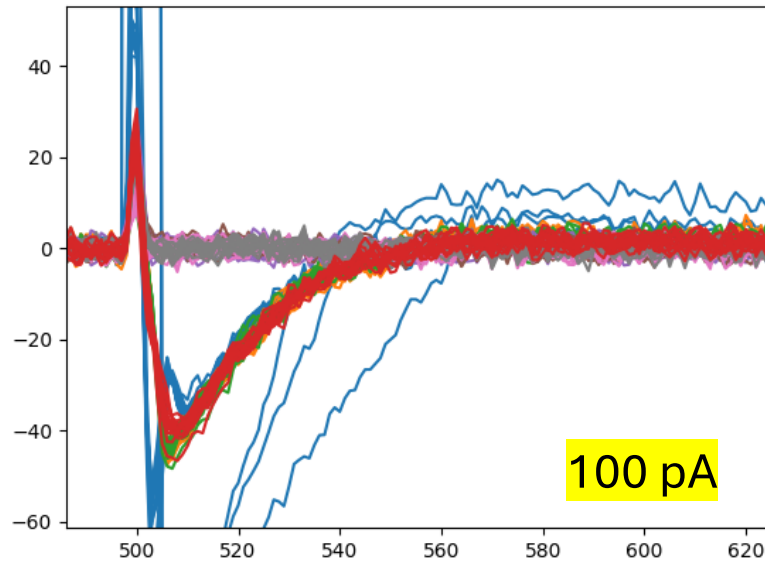
LN2: pulsed with 218 fC, 2 chns vs. 3 chns

- sgp=1, dac=0x3f (218fC), 14 mV/fC, chip#0 200 mV BL (other 900mV BL)



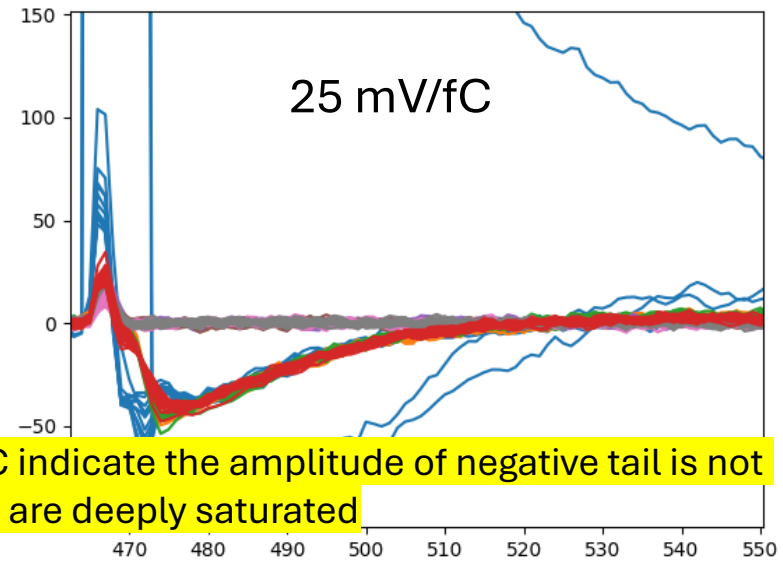
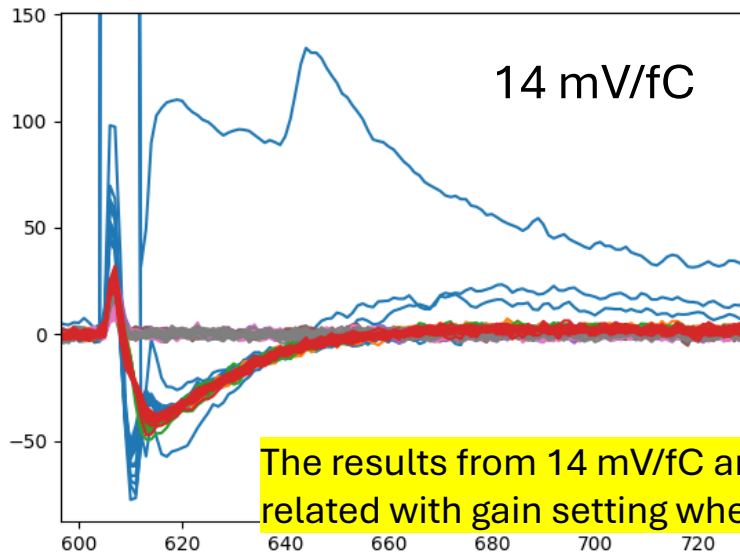
The amplitude of negative tail becomes larger when more channels are deeply saturated.

LN2: 3 chns pulsed with 218 fC, different leakage current settings

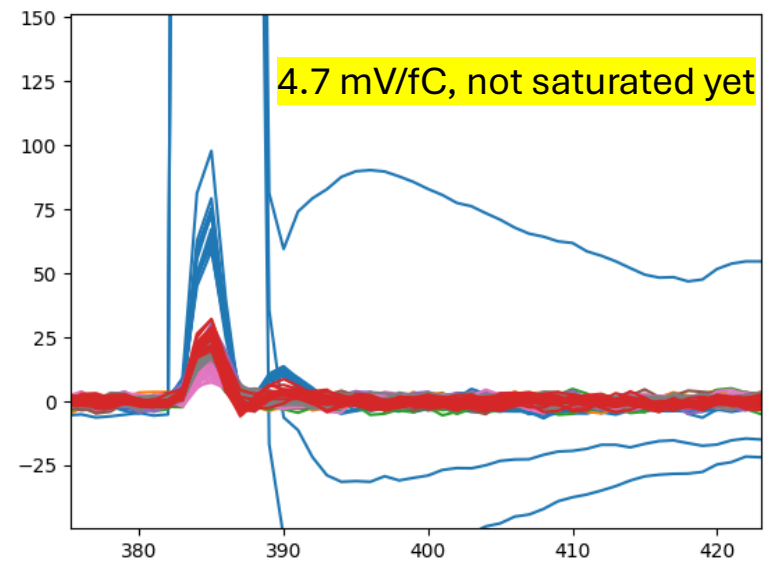
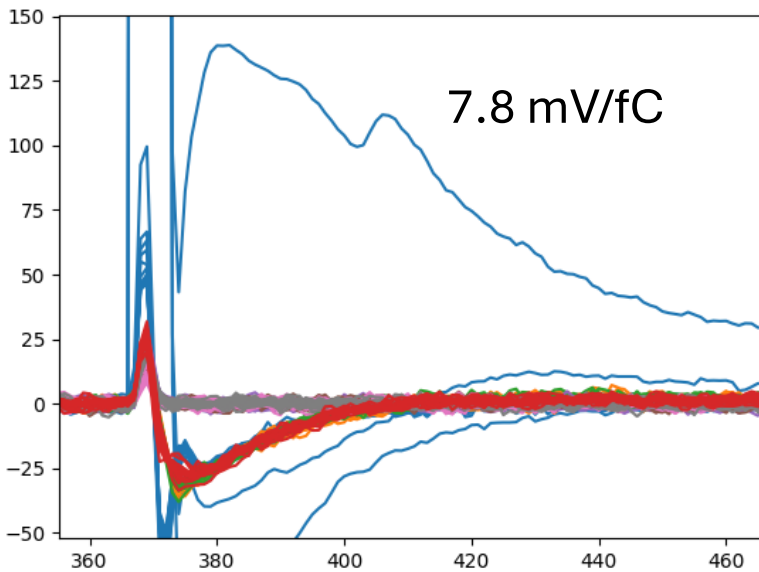


Changing leakage current setting doesn't affect the negative tail much, though it affects the pole-zero cancellation behavior of pulsed channels.

LN2: 3 chns pulsed with 218 fC, different gains

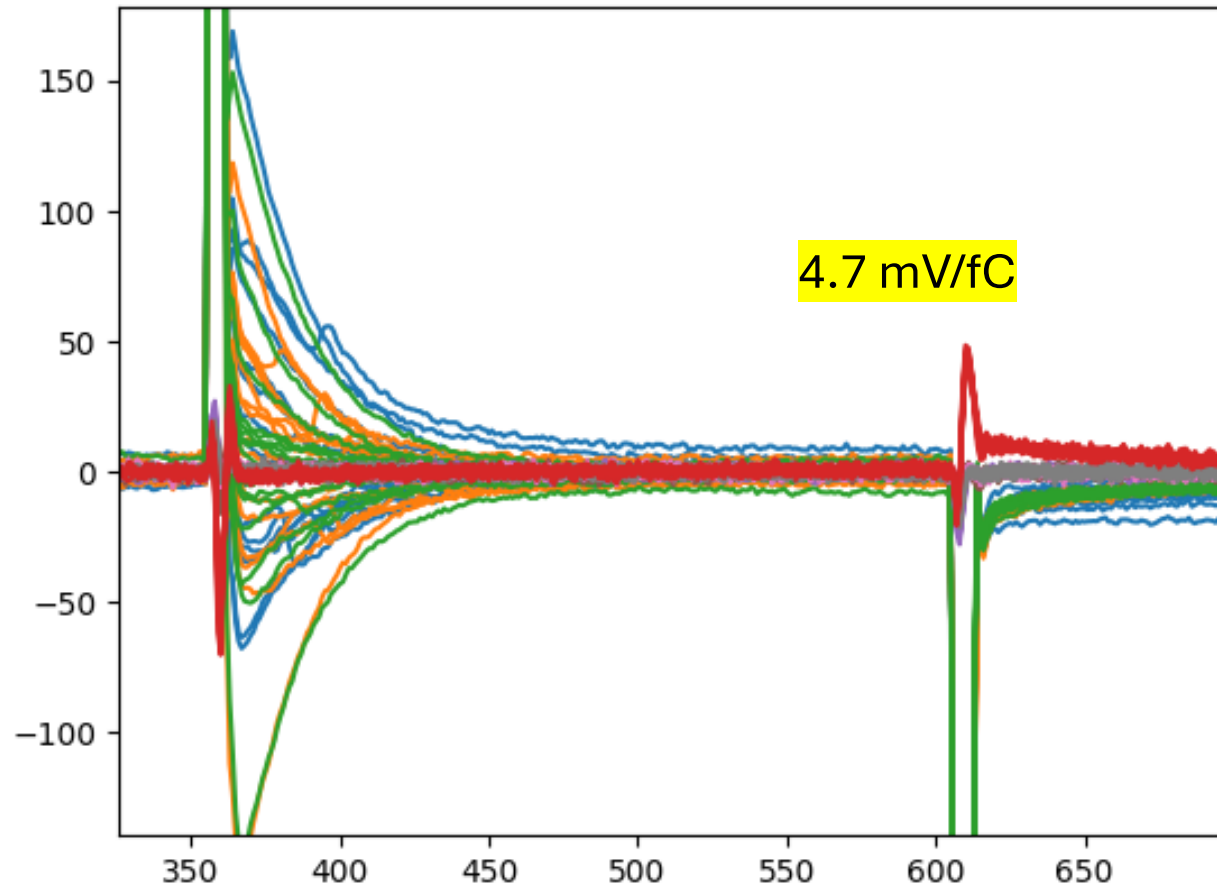


The results from 14 mV/fC and 25 mV/fC indicate the amplitude of negative tail is not related with gain setting when channels are deeply saturated



LN2: 3 chips (48 chns) are pulsed

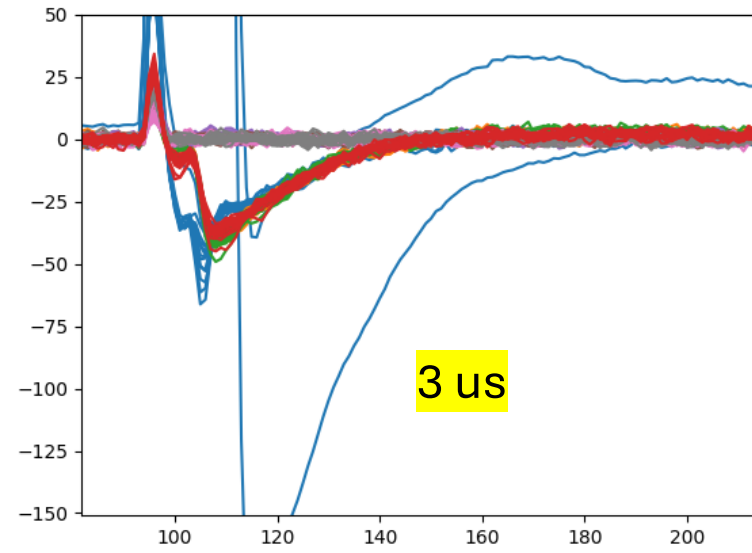
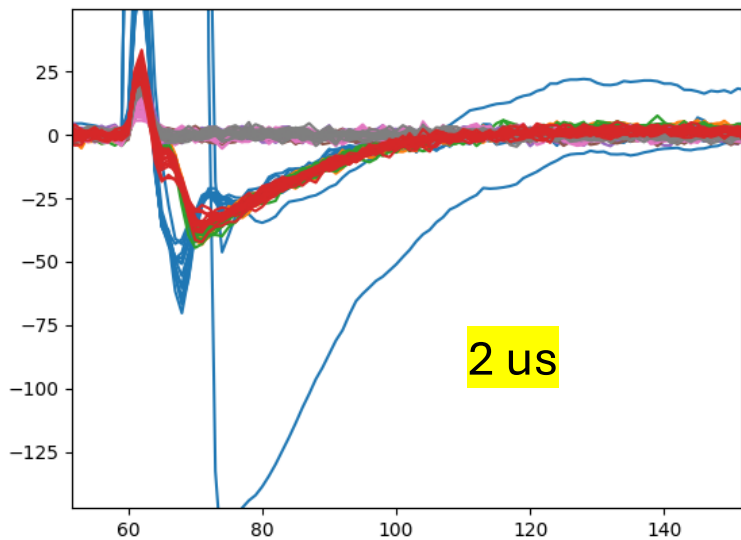
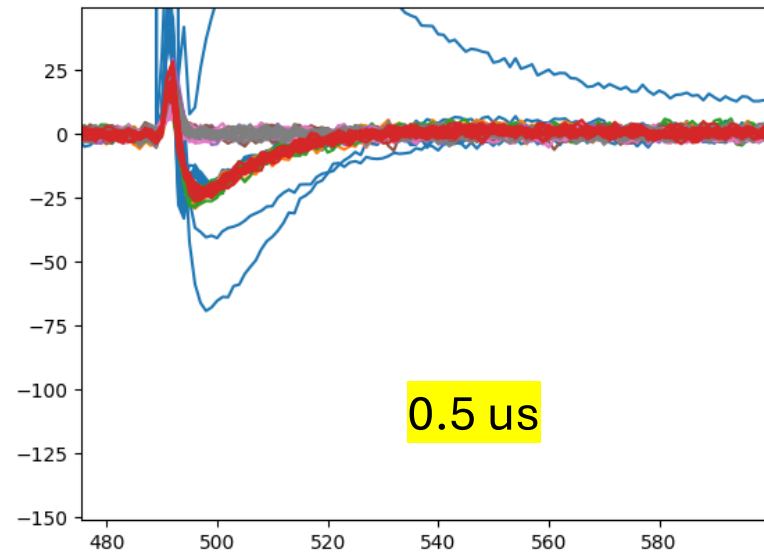
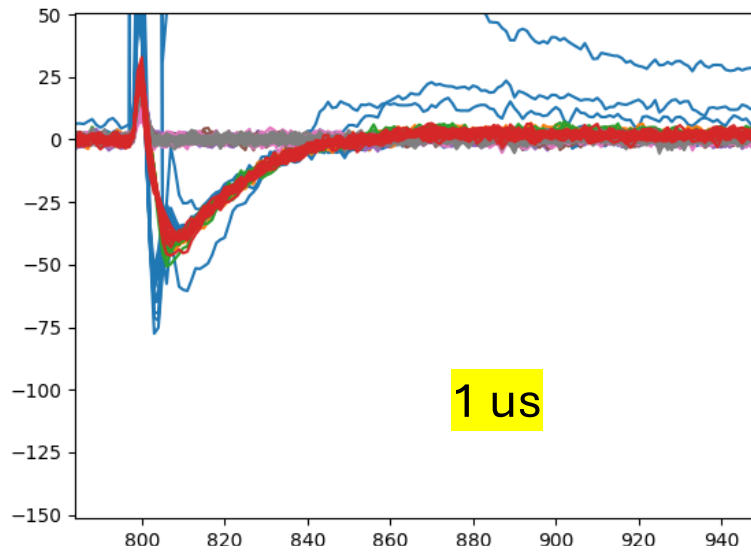
- $sgp=1$, $dac=0x3f$



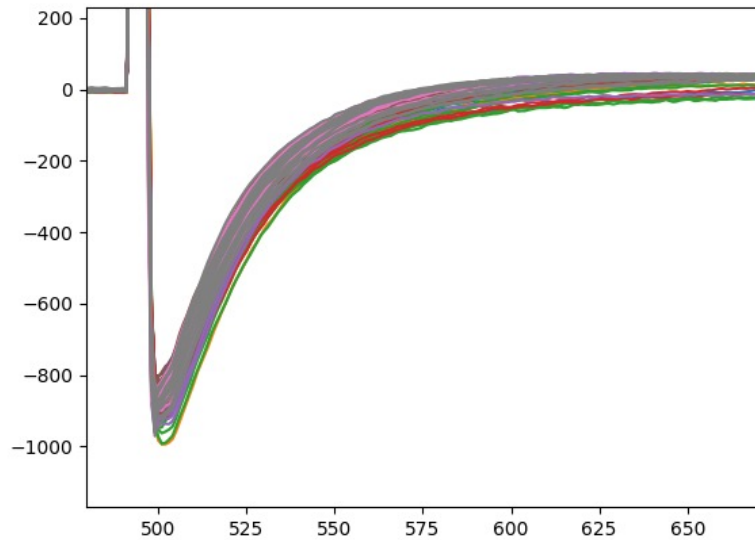
Negative tail is not significant

LN2: 3 chips (48 chns) are pulsed at 218 fC

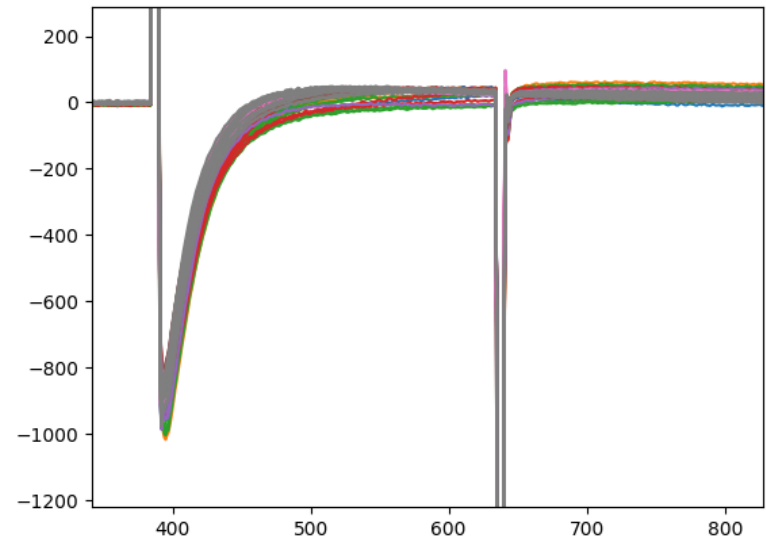
- Different peaking times ($\geq 1 \mu\text{s}$) have minimum impact



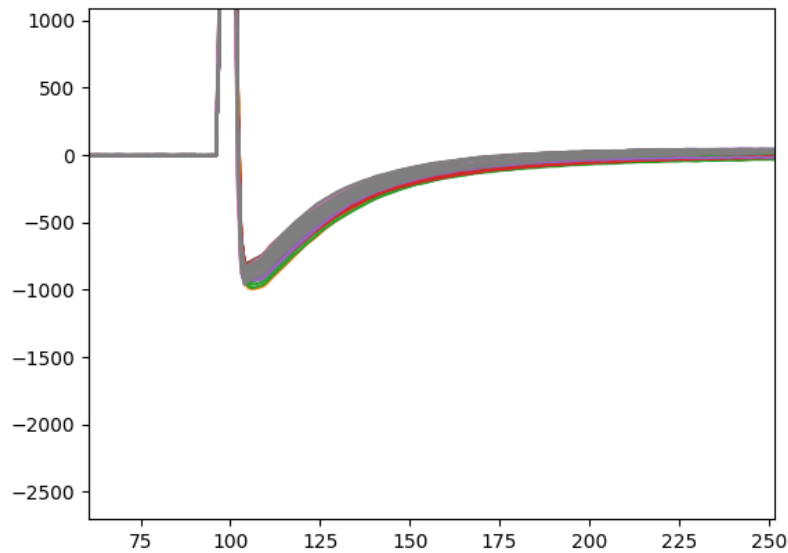
LN2: all channels are pulsed at 218 fC



14 mV/fC, SE and SDF off



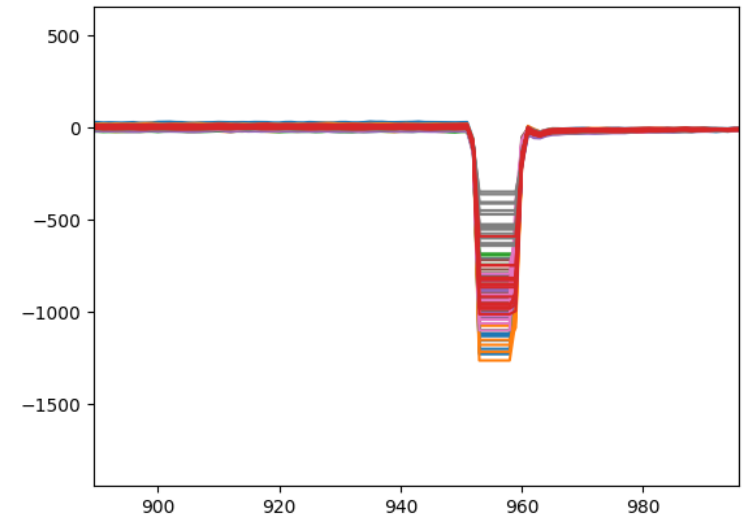
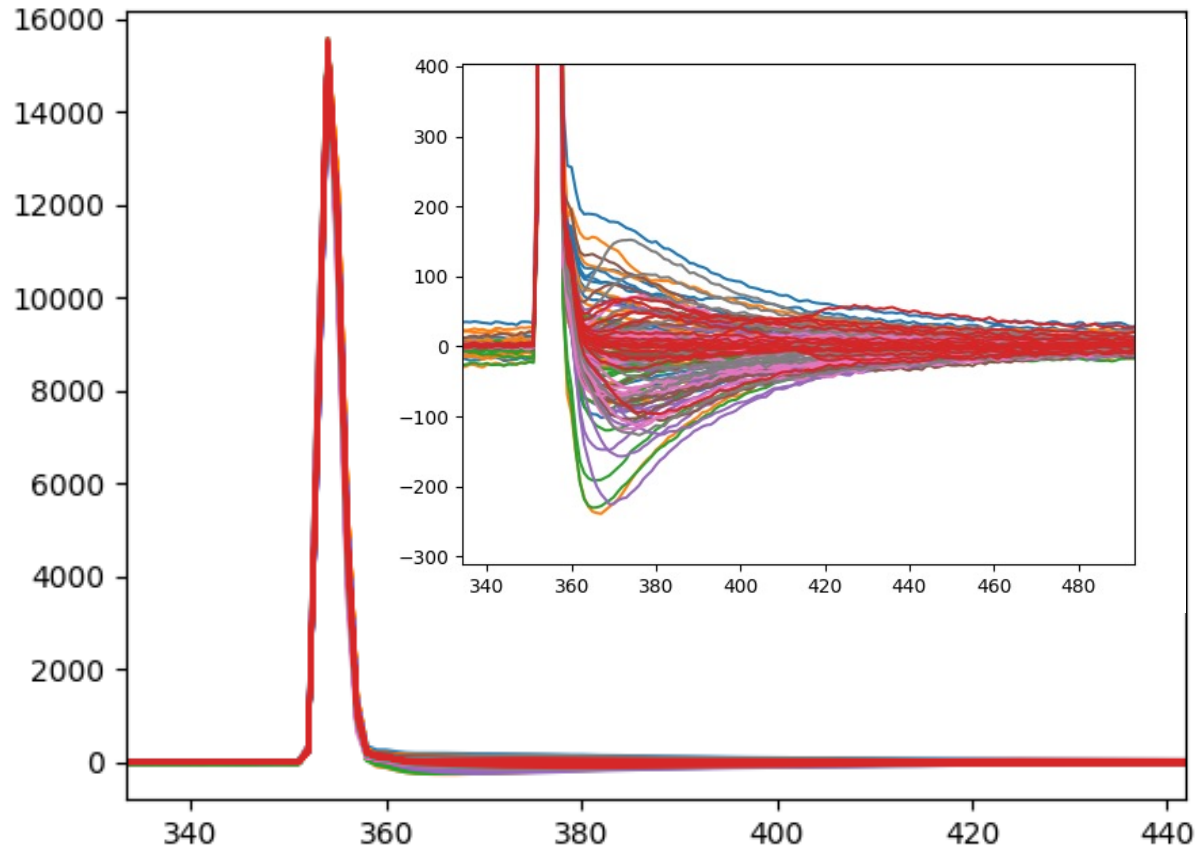
14 mV/fC, SE and SDF on



14 mV/fC, DIFF on

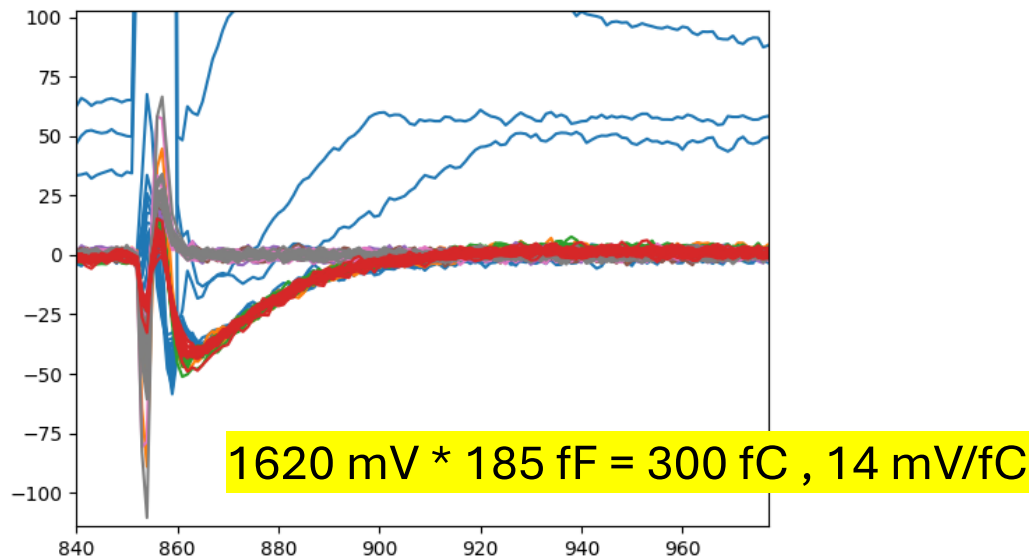
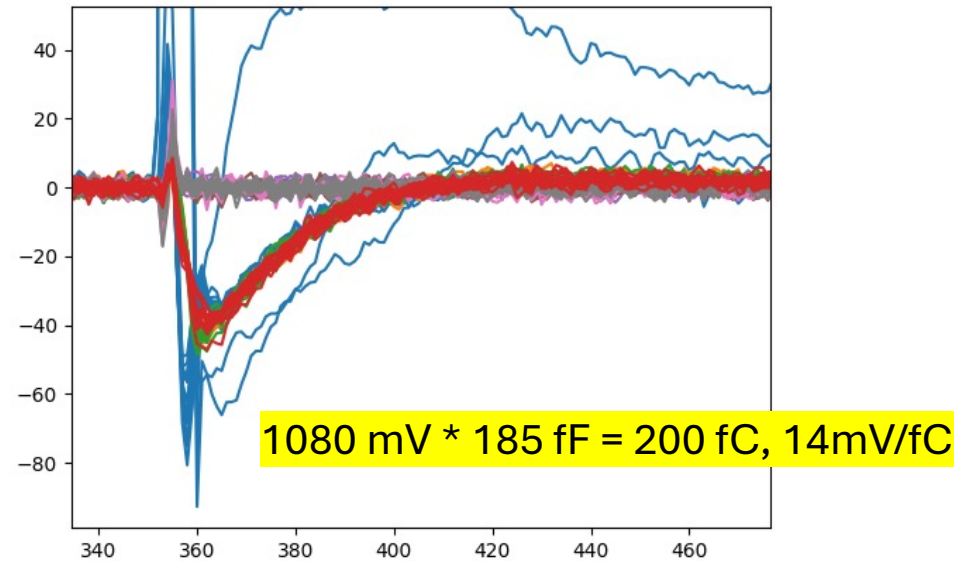
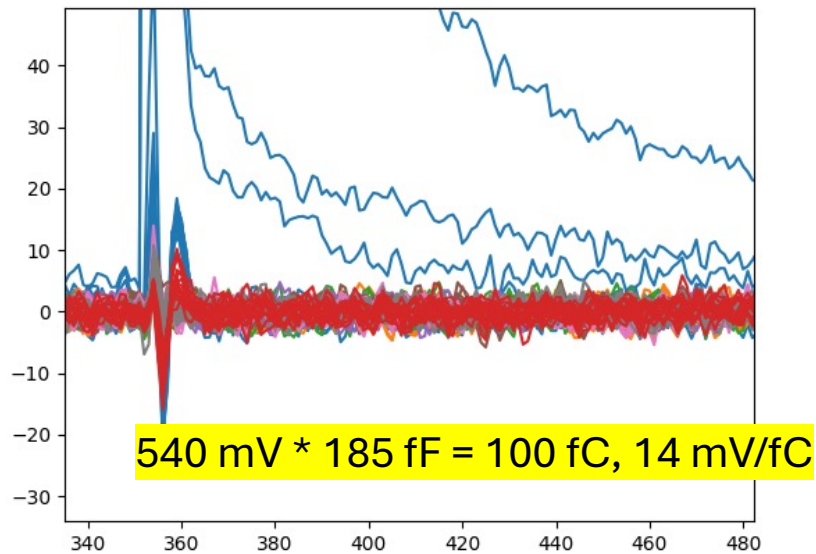
LN2: External calibration pulser from signal generator

- $540 \text{ mV} * 185 \text{ fF} = 100 \text{ fC}$, 14 mV/fC



LN2: External calibration pulser from signal generator

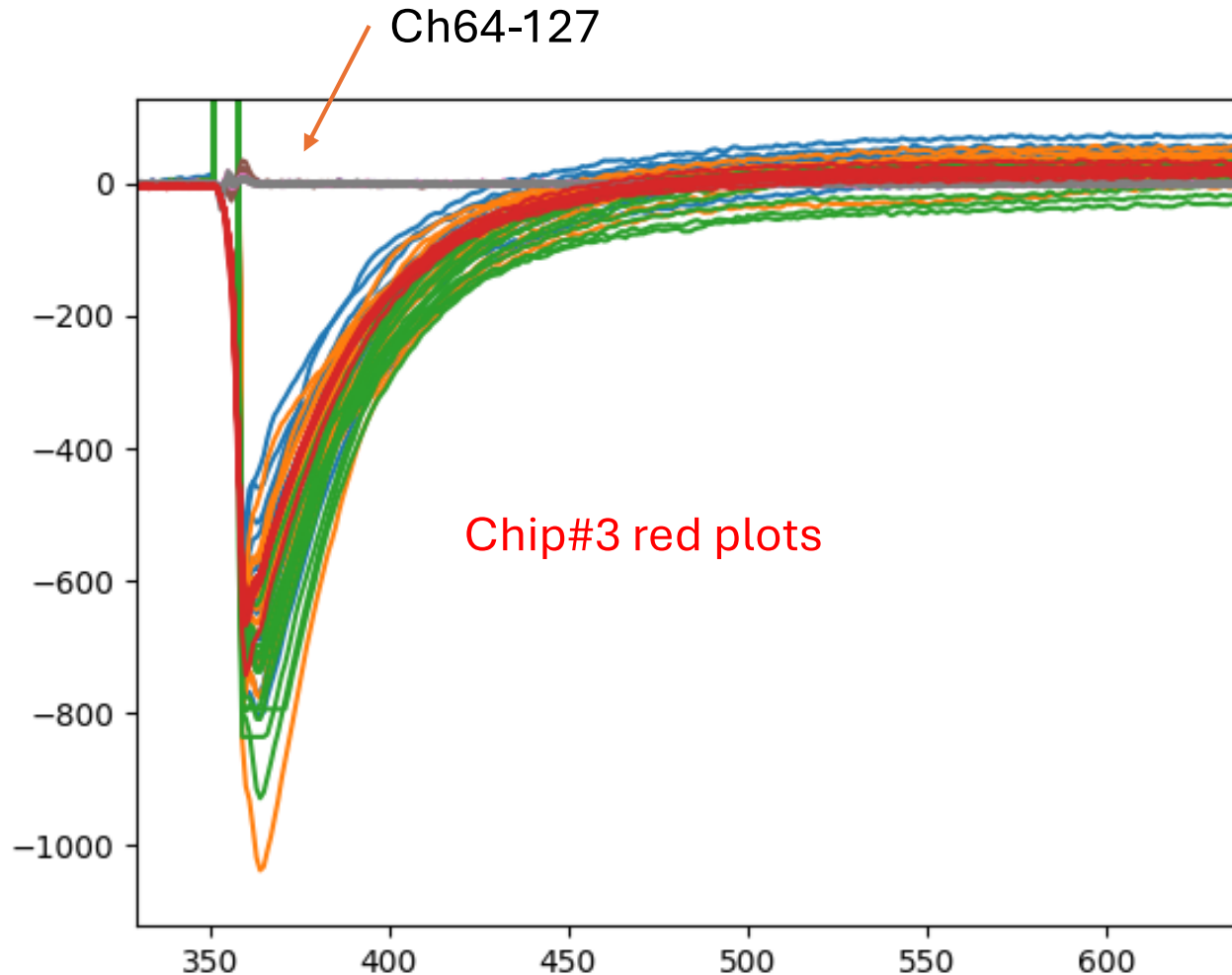
- 3 chns are pulsed



LN2: External calibration pulser from signal generator

- 3 chips (48 chns) are pulsed

$1080 \text{ mV} * 185 \text{ fF} = 200 \text{ fC}, 14 \text{ mV/fC}$

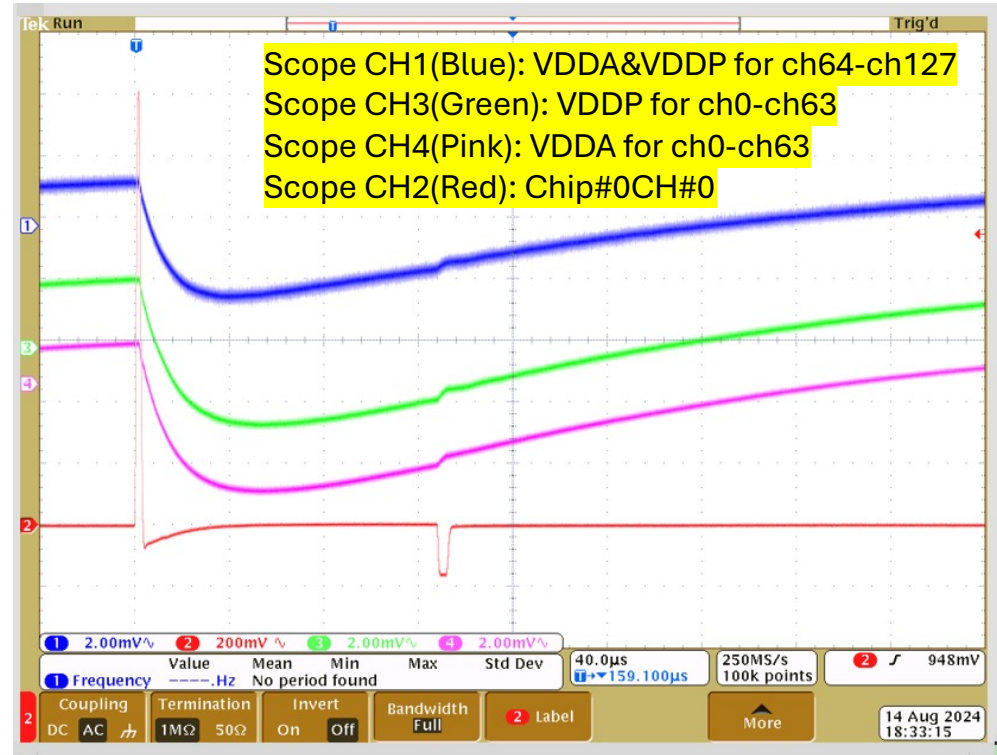
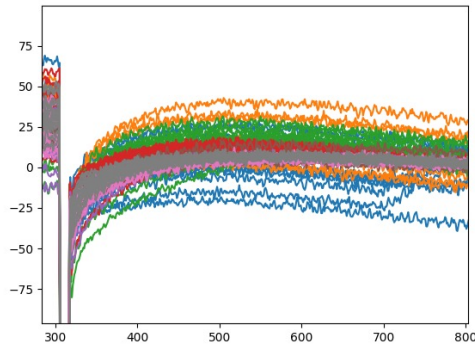
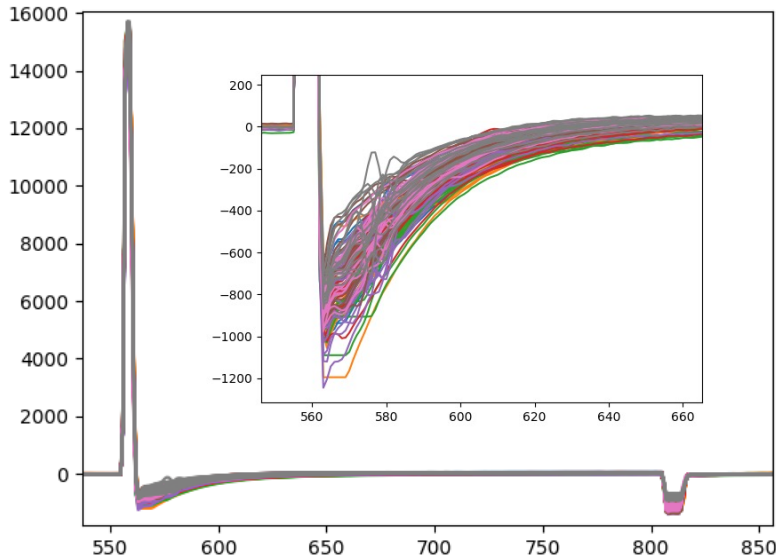


It offers a hint that the negative tail could be corrected via offline processing

LN2: Chip#0CH#0 is selected for monitoring

- All channels are pulsed at 218 fC

VDDA&VDDP of CH64-CH127 tied together
VDDA&VDDP of CH0-CH63 tied together



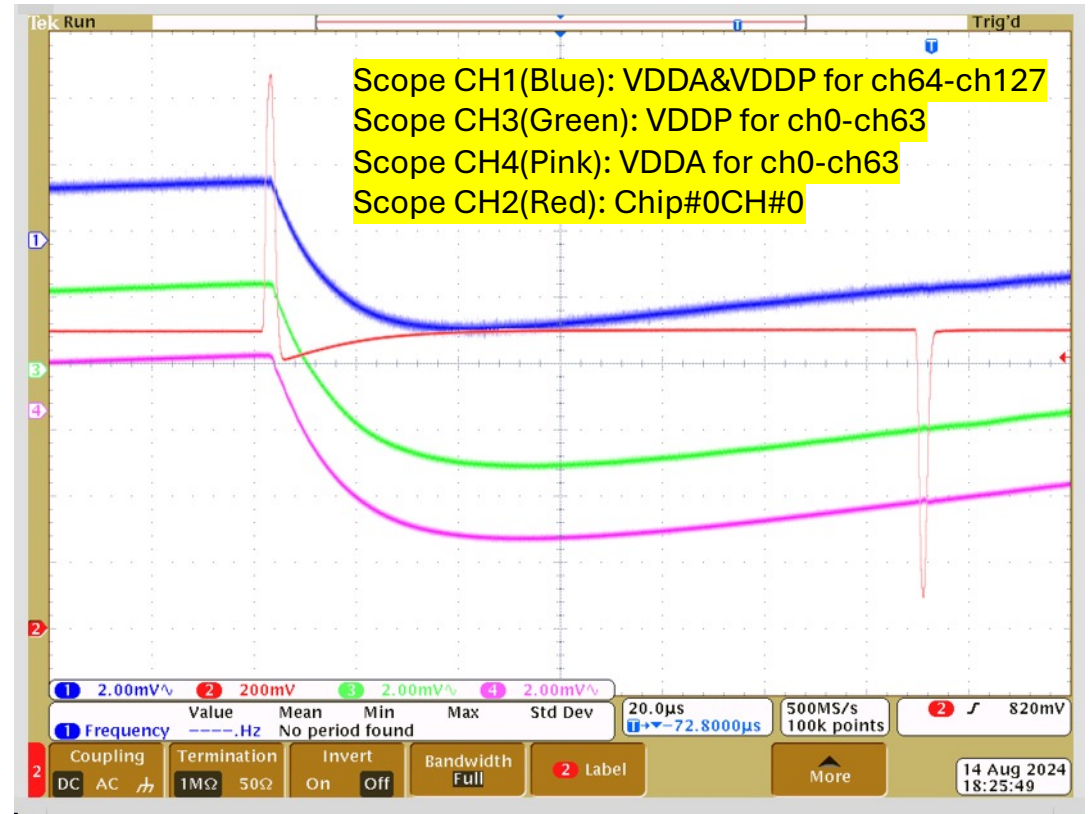
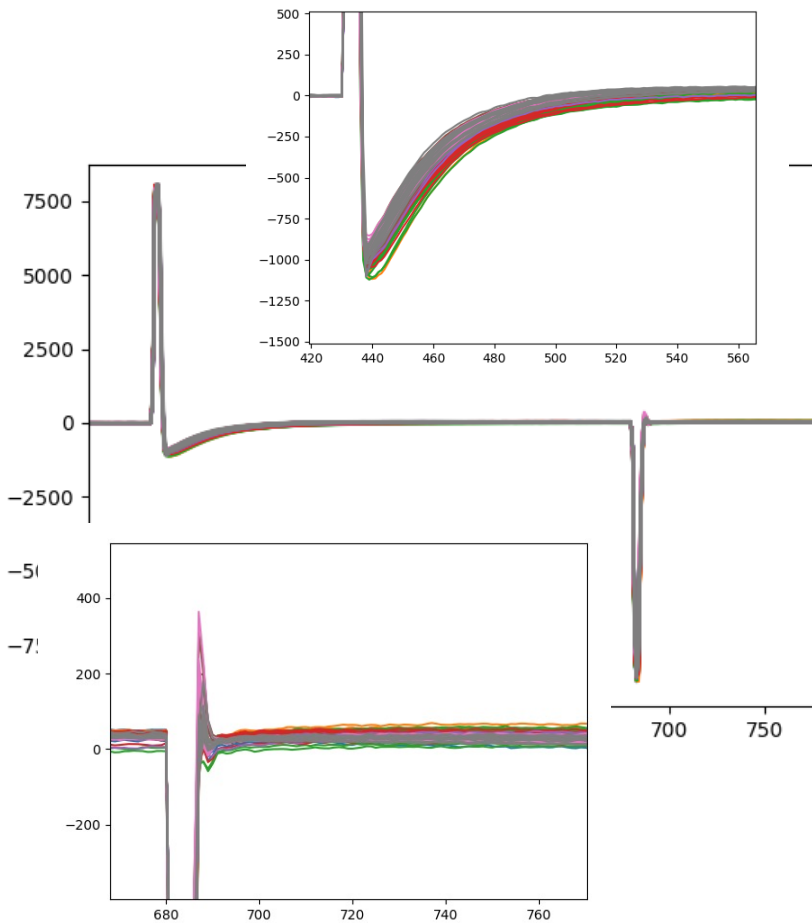
Sagging of 1.8V power rail is observed

200 mV BL

LN2: Chip#0CH#0 is selected for monitoring

- All channels are pulsed at 218 fC

VDDA&VDDP of CH64-CH127 tied together
VDDA&VDDP of CH0-CH63 tied together

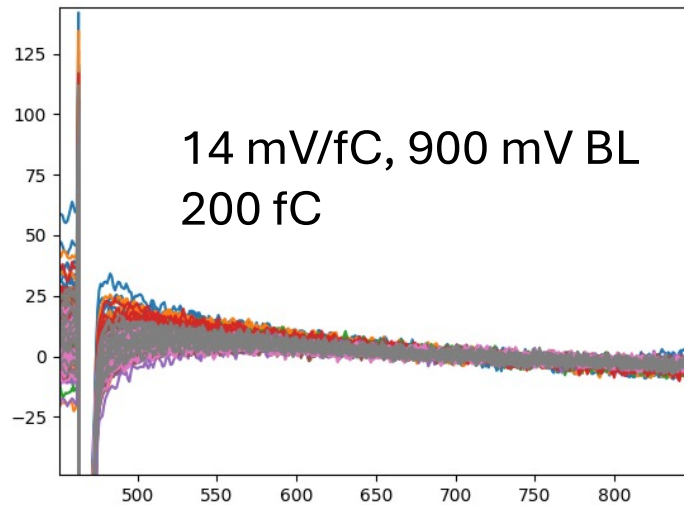
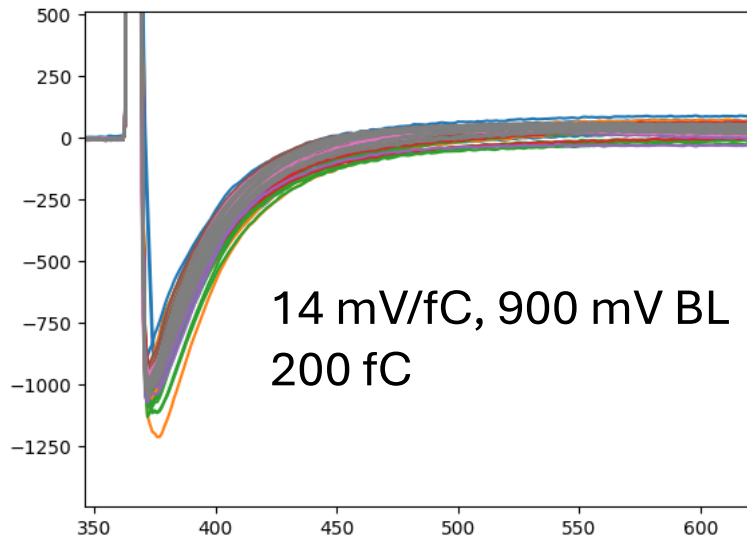


Sagging of 1.8V power rail is observed

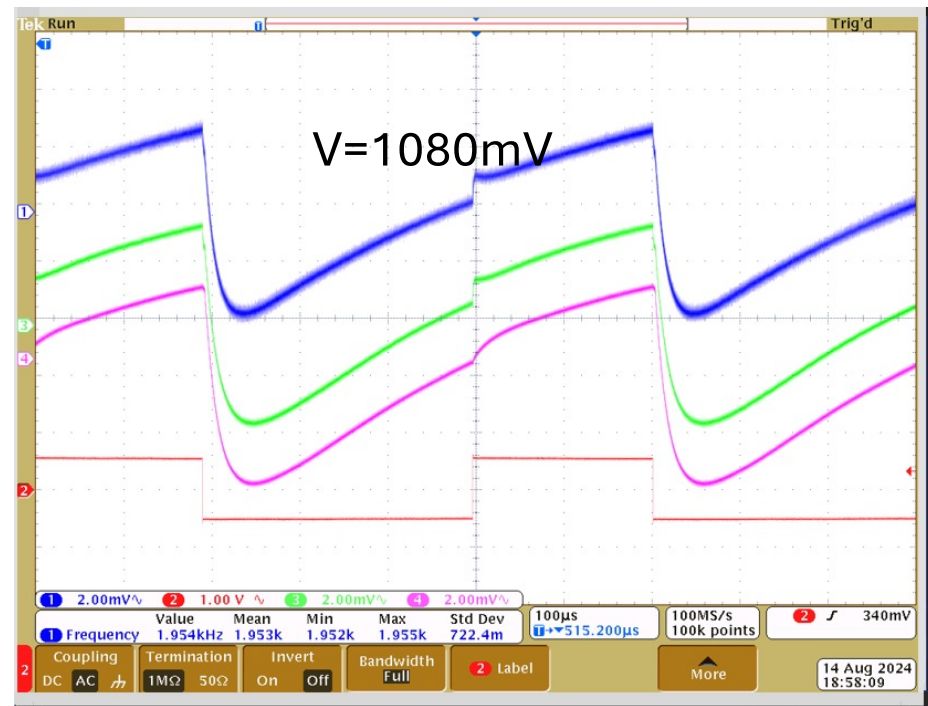
900 mV BL

LN2: External pulser from signal generator

- All channels
 - $Q = 185 \text{ fF} * V$



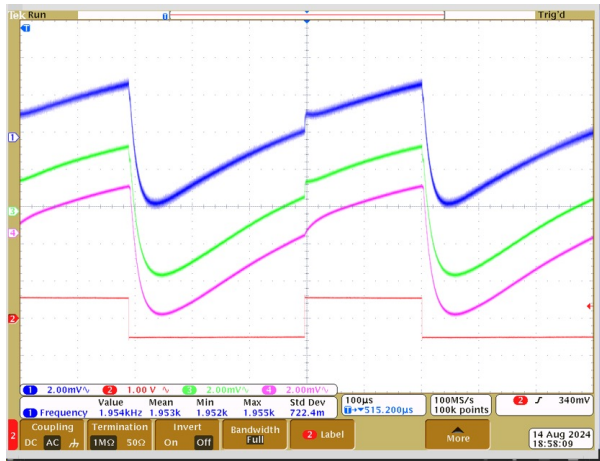
Scope CH1(Blue): VDDA&VDDP for ch64-ch127
Scope CH3(Green): VDDP for ch0-ch63
Scope CH4(Pink): VDDA for ch0-ch63
Scope CH2(Red): Calibration Pulser



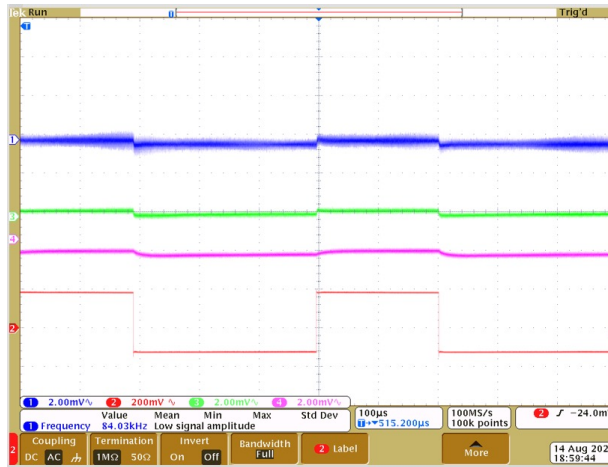
LN2: External pulser from signal generator

14mV/fC, 900mV BL

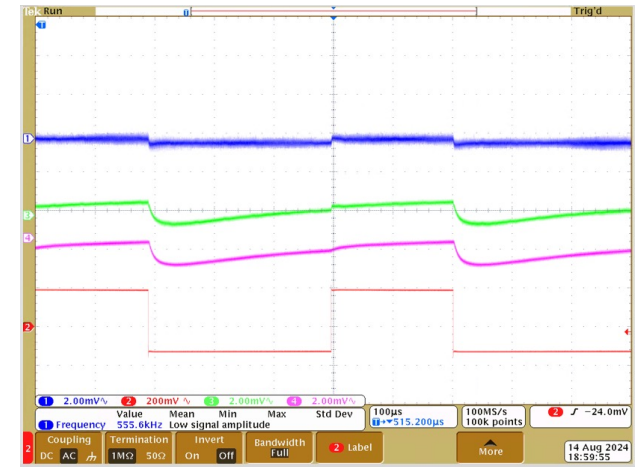
Scope CH1(Blue): VDDA&VDDP for ch64-ch127
 Scope CH3(Green): VDDP for ch0-ch63
 Scope CH4(Pink): VDDA for ch0-ch63
 Scope CH2(Red): Calibration Pulser



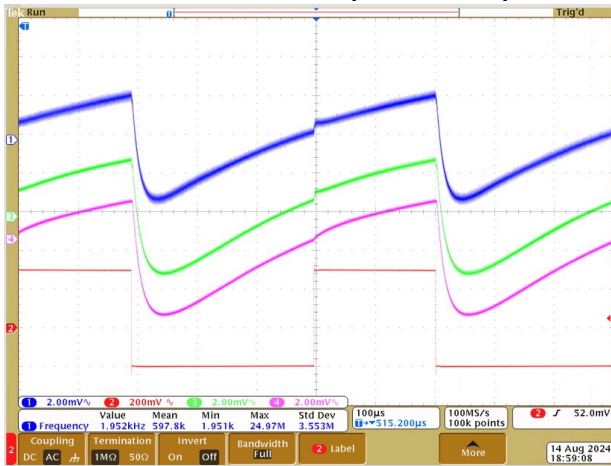
V=1080 mV (200 fC)



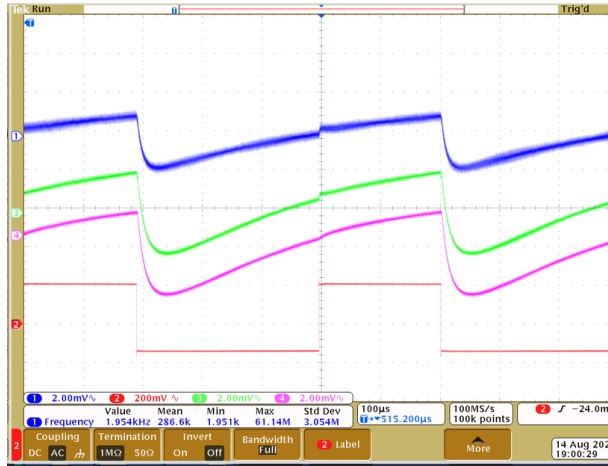
V=310 mV (57 fC)



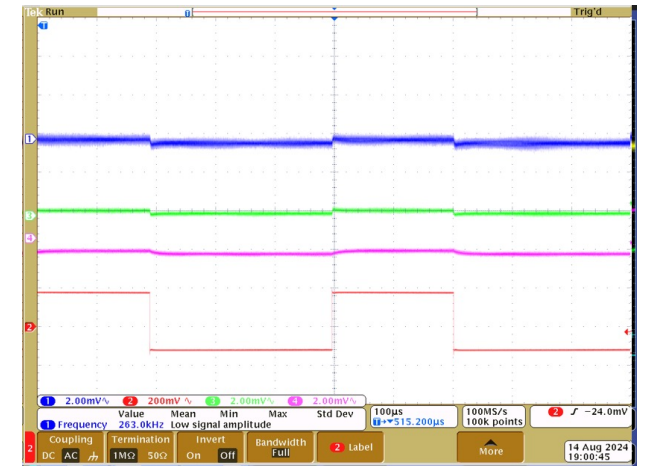
V=320mV (60 fC)



V=500 mV (93 fC)



V=350 mV (65 fC)

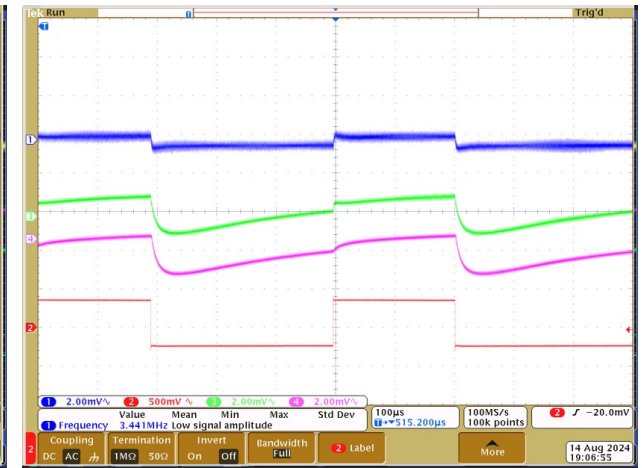
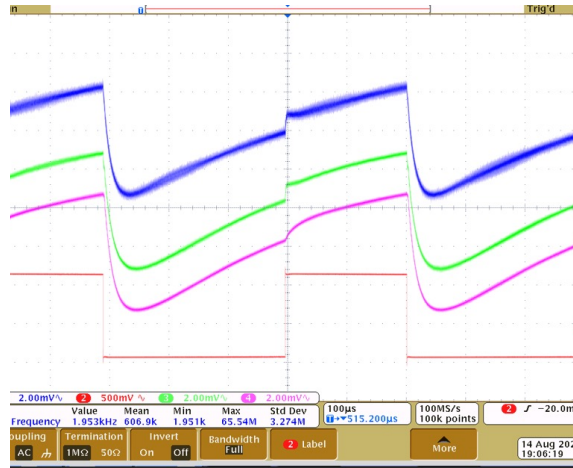
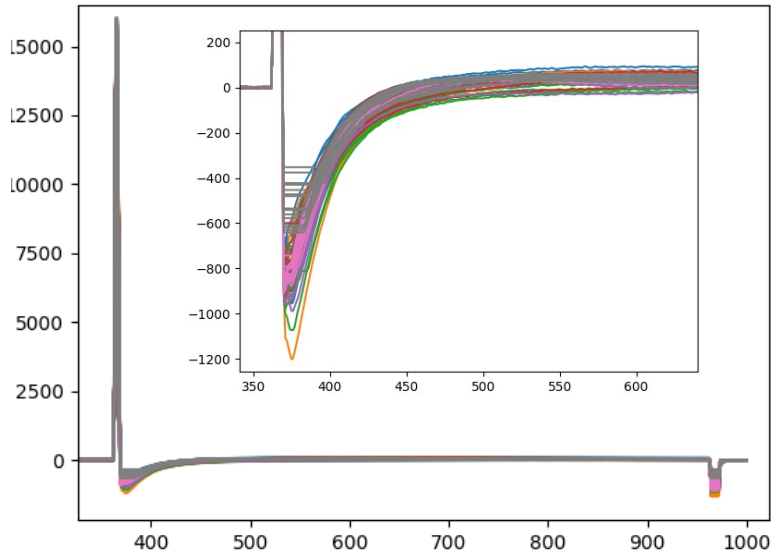


V=300 mV (55 fC)

LN2: External pulser from signal generator

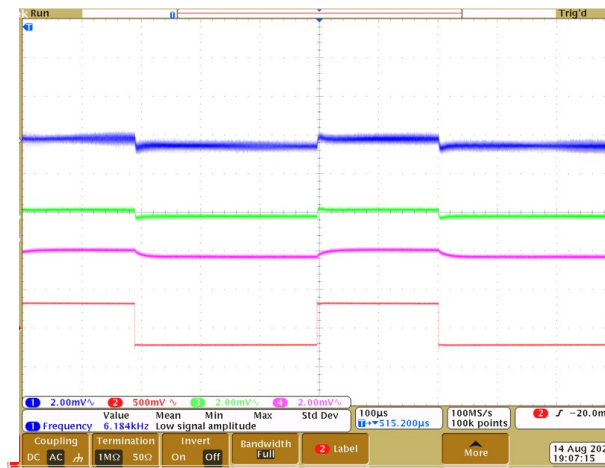
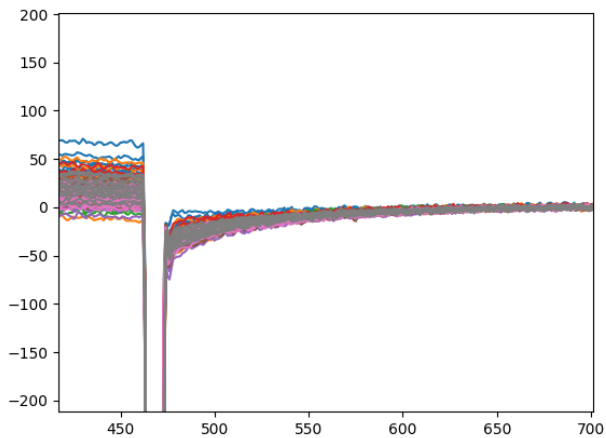
14mV/fC, 200mV BL

Scope CH1(Blue): VDDA&VDDP for ch64-ch127
 Scope CH3(Green): VDDP for ch0-ch63
 Scope CH4(Pink): VDDA for ch0-ch63
 Scope CH2(Red): Calibration Pulser



V=1080 mV (200 fC)

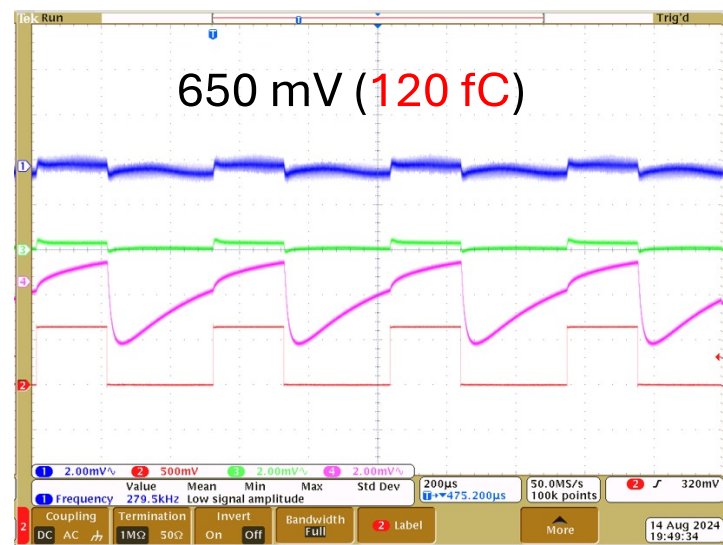
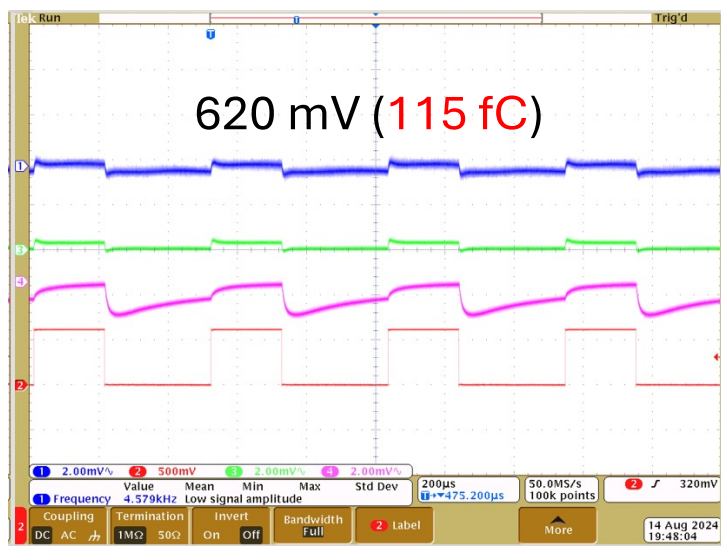
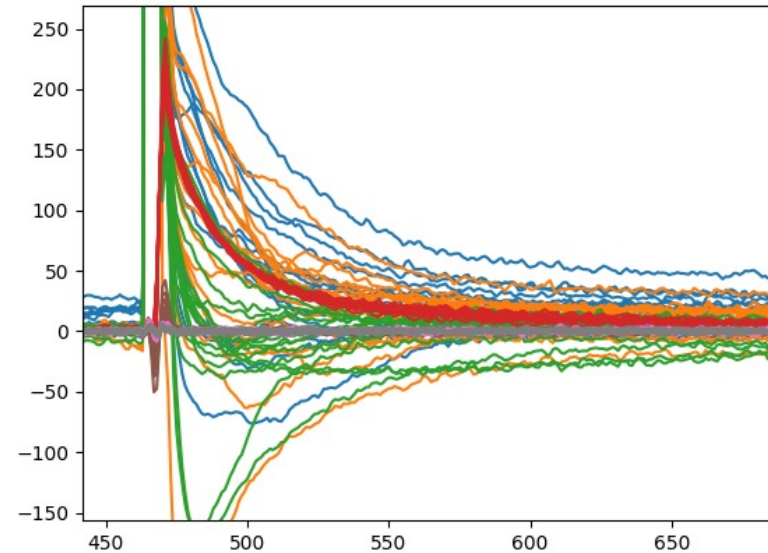
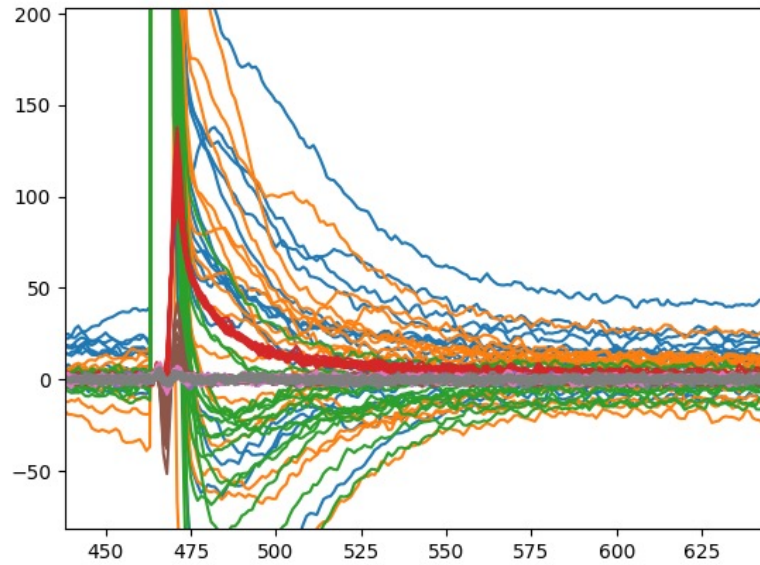
V=600 mV (110 fC)



V=550 mV (102 fC)

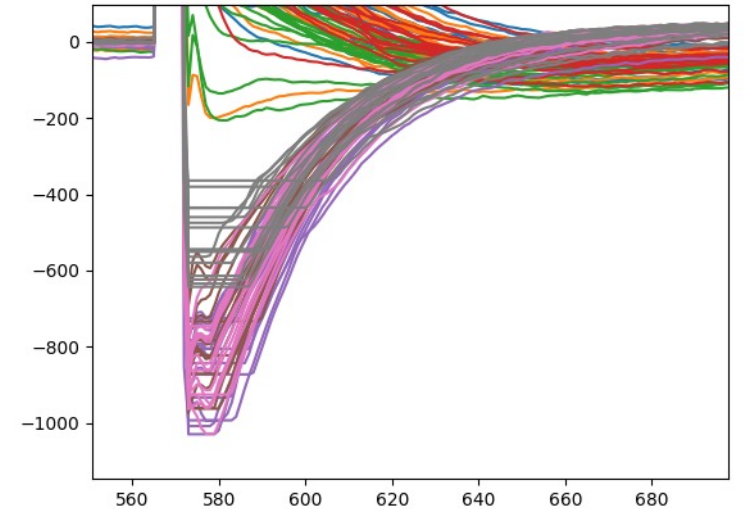
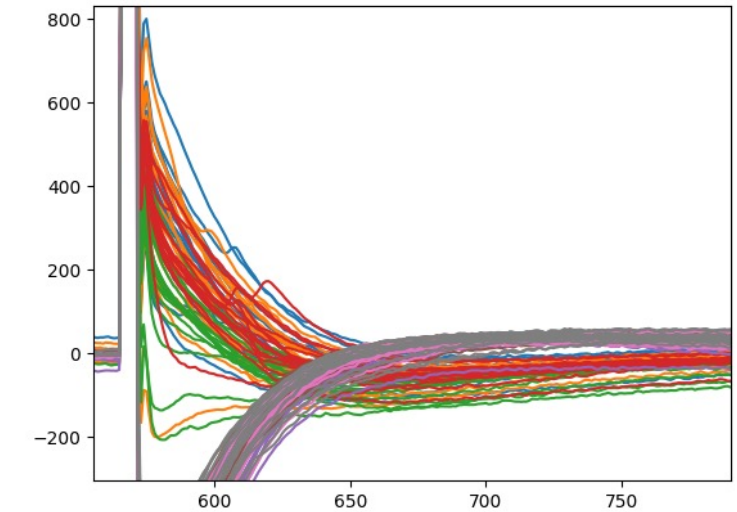
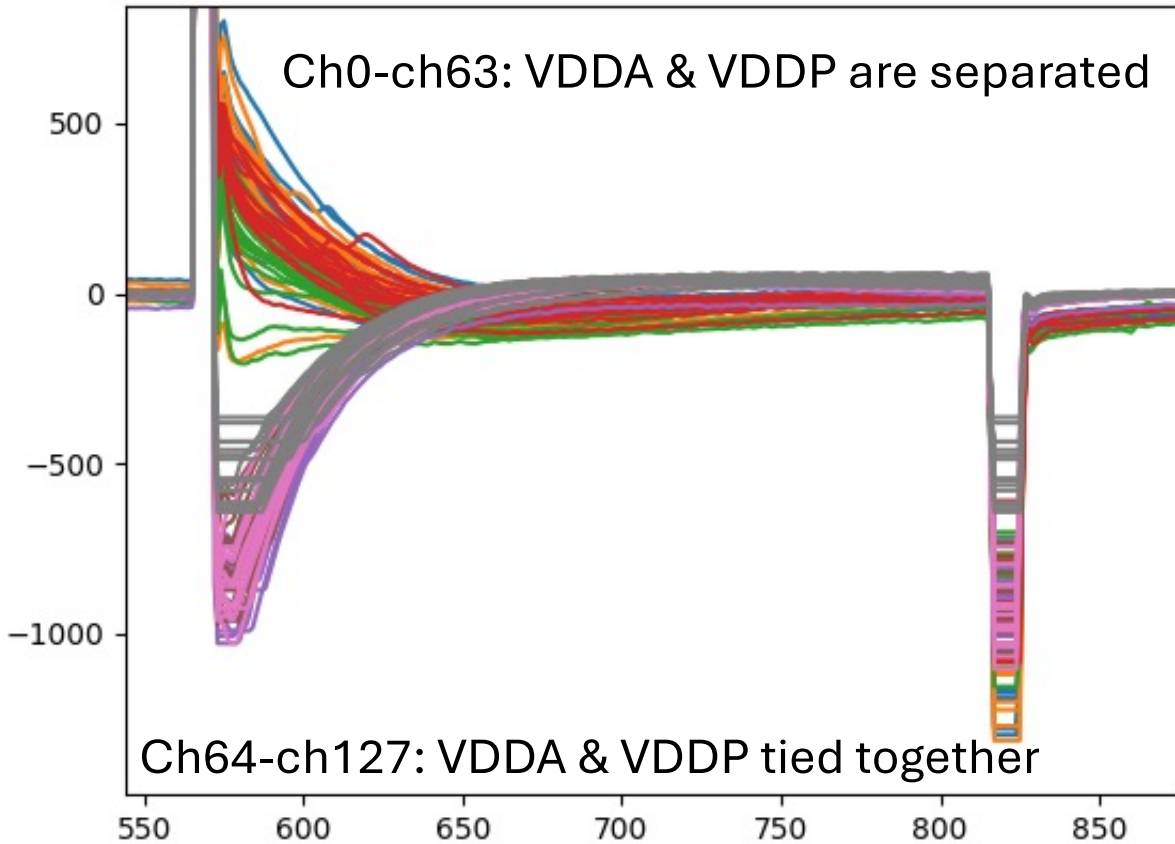
CH#0-63: VDDA & VDDP are separated

- Chip#0,1,2 (48 chns) are pulsed



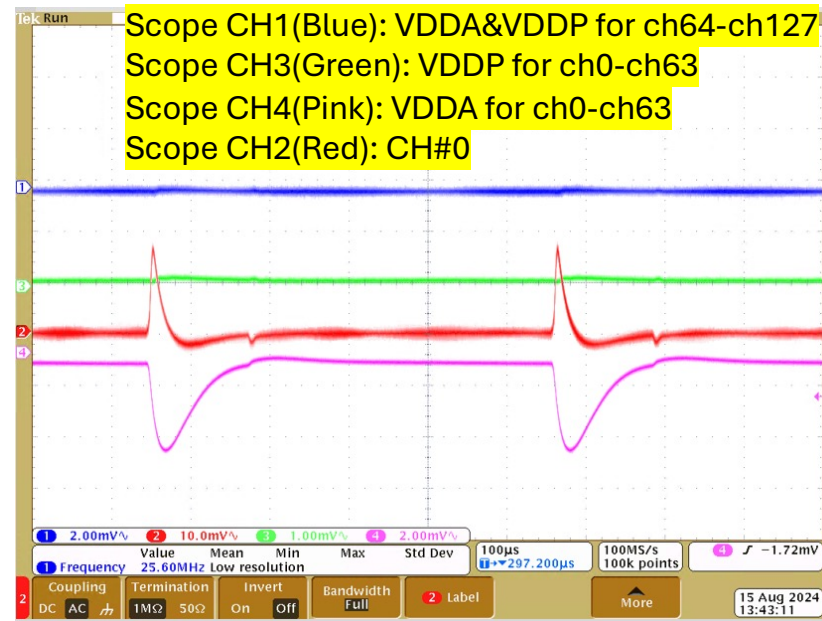
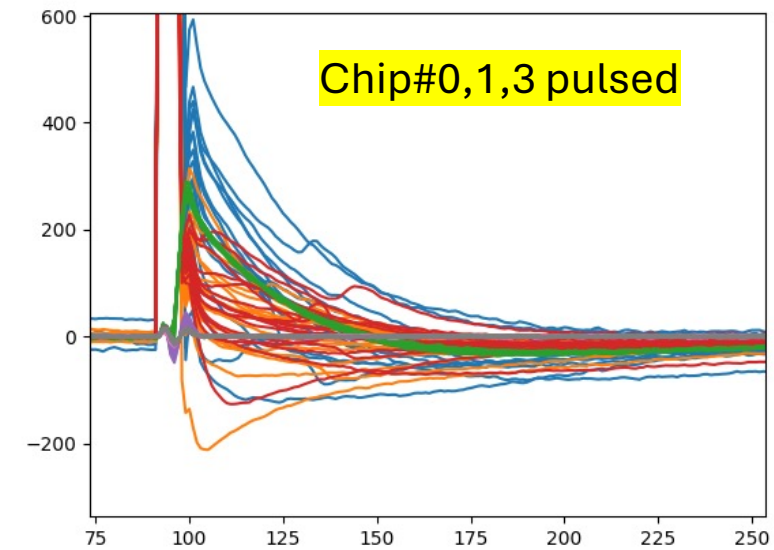
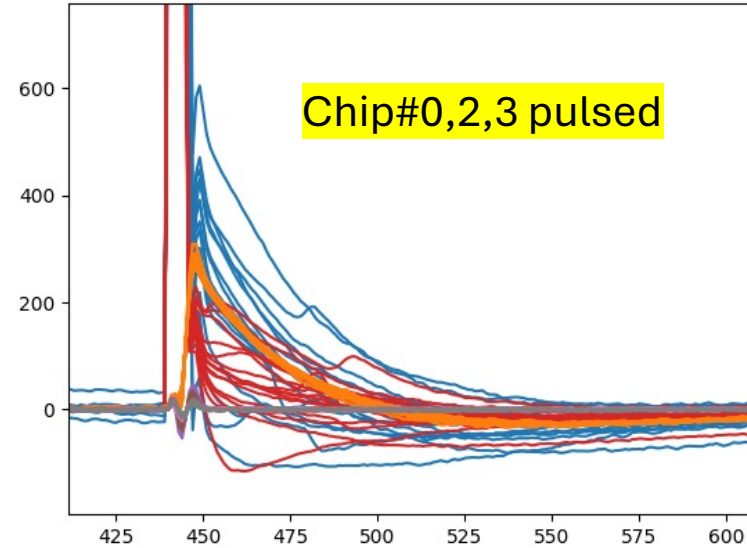
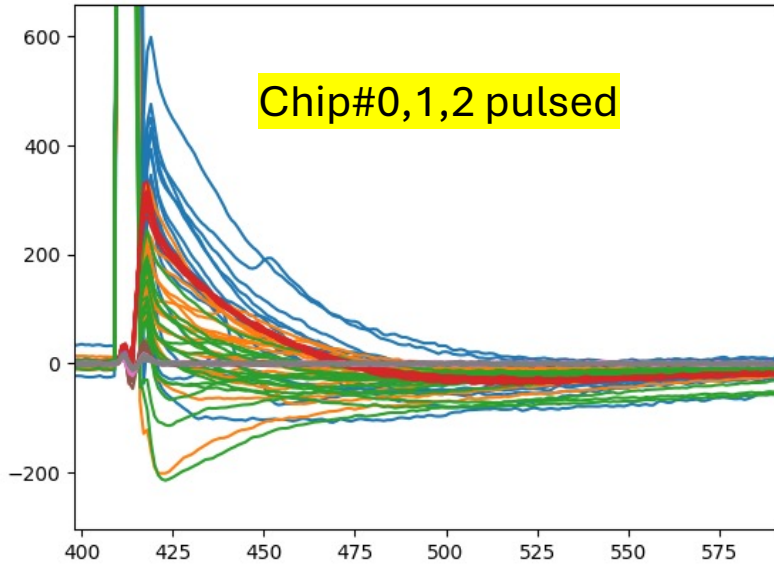
CH#0-63: VDDA & VDDP are separated

- Internal calibration (218 fC) to all channels
 - Both VDDA&VDDP (CH#0-63) R to 0.1 Ohm



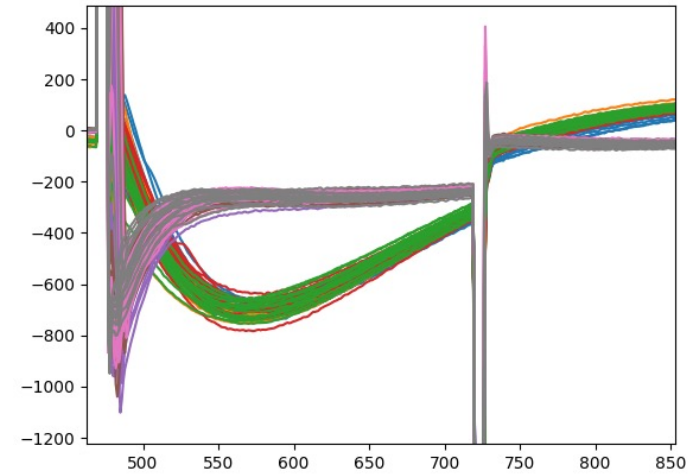
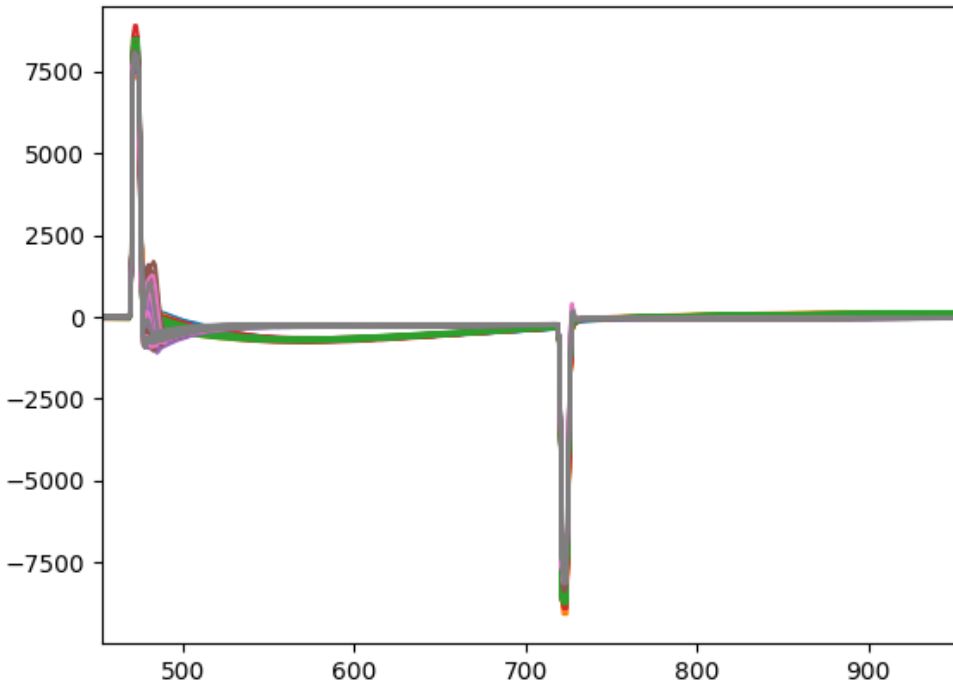
CH#0-63: VDDA & VDDP are separated

- Internal calibration (218 fC)

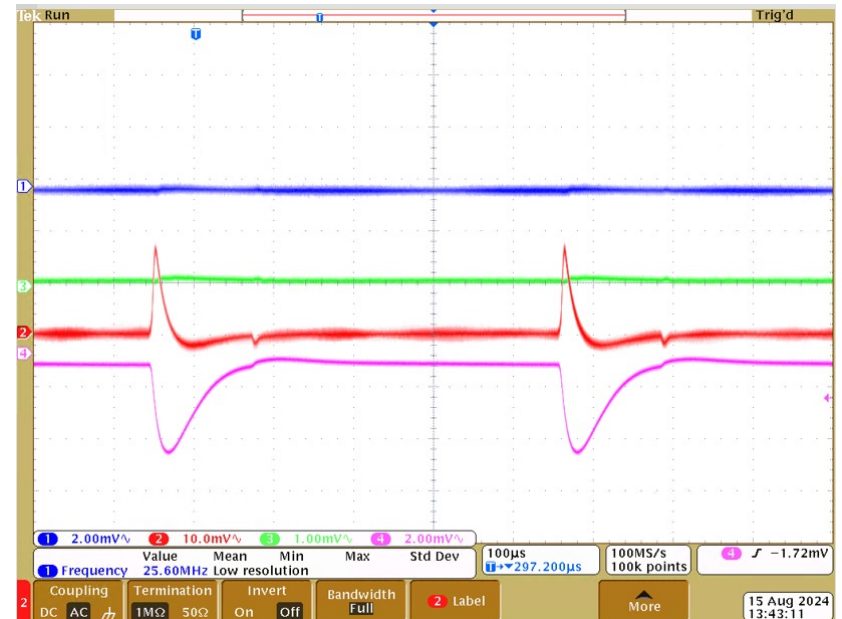


CH#0-63: VDDA & VDDP are separated

- Internal calibration (218 fC) for all channels

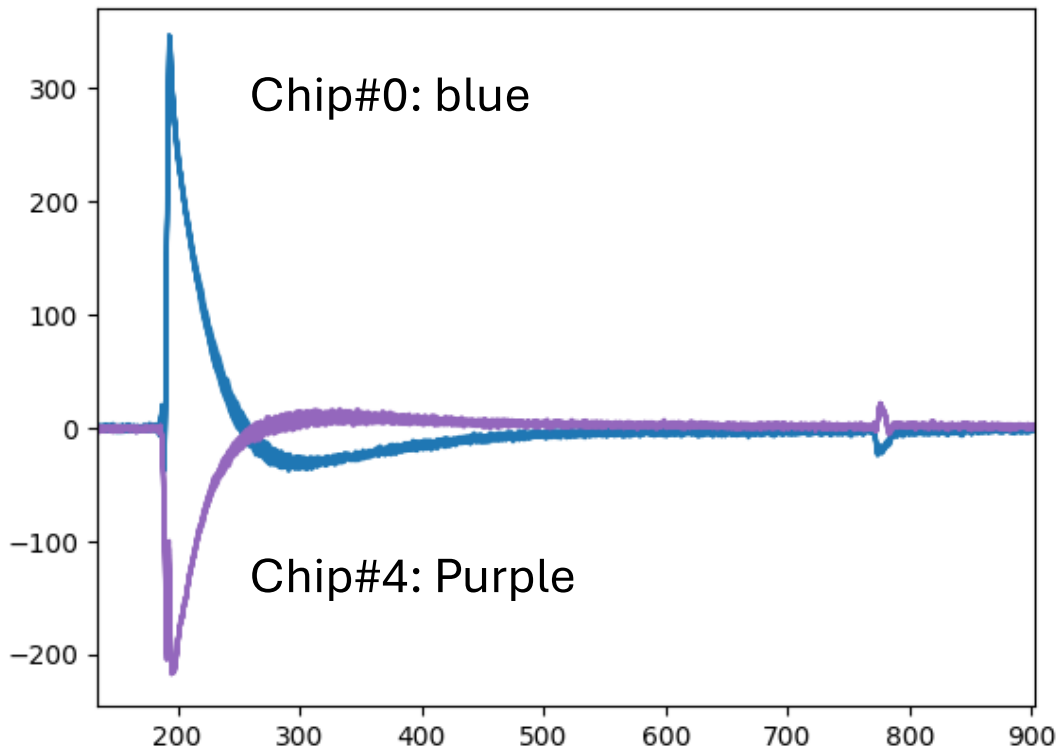


AC coupling mode has no impact

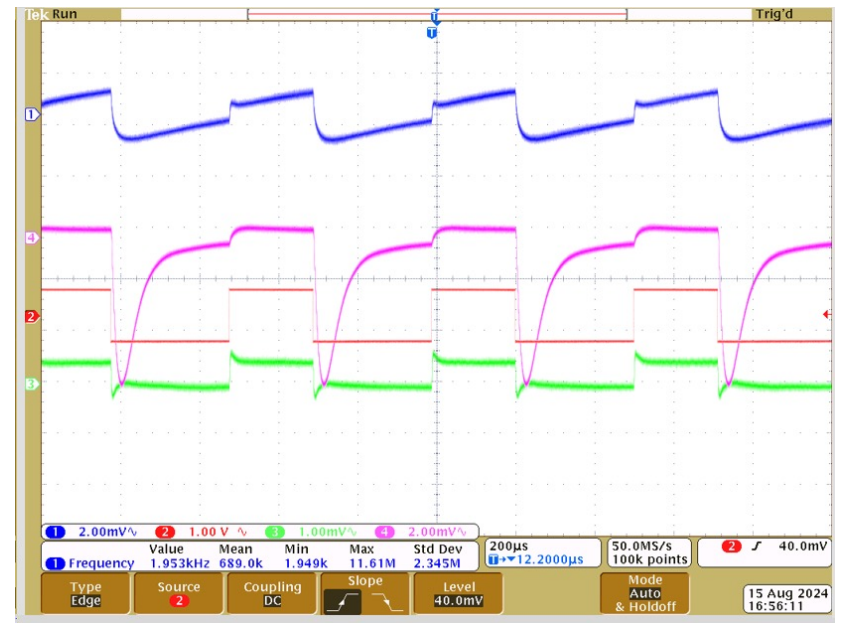


External Pulser from Signal Generator

- Chip#1,2,3,5,6,7 are pulsed at **185 fC**



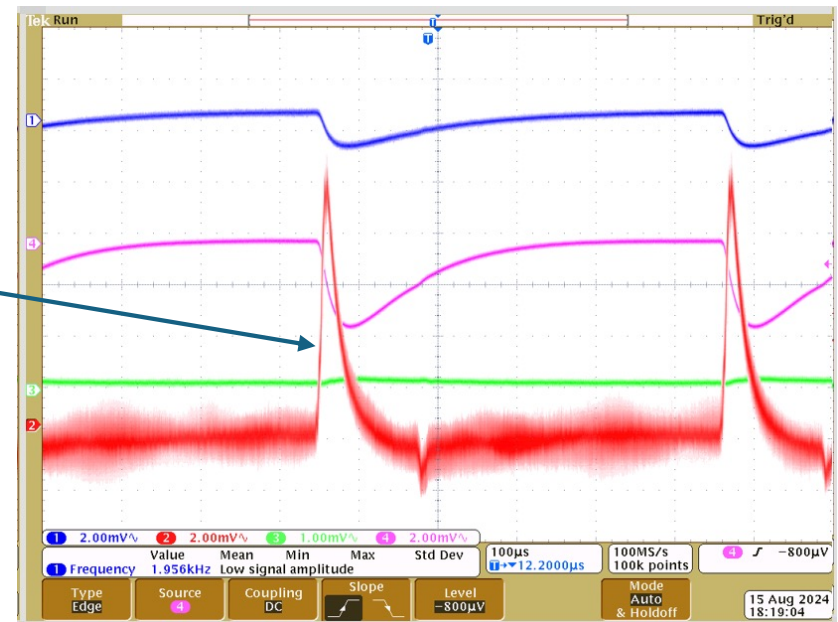
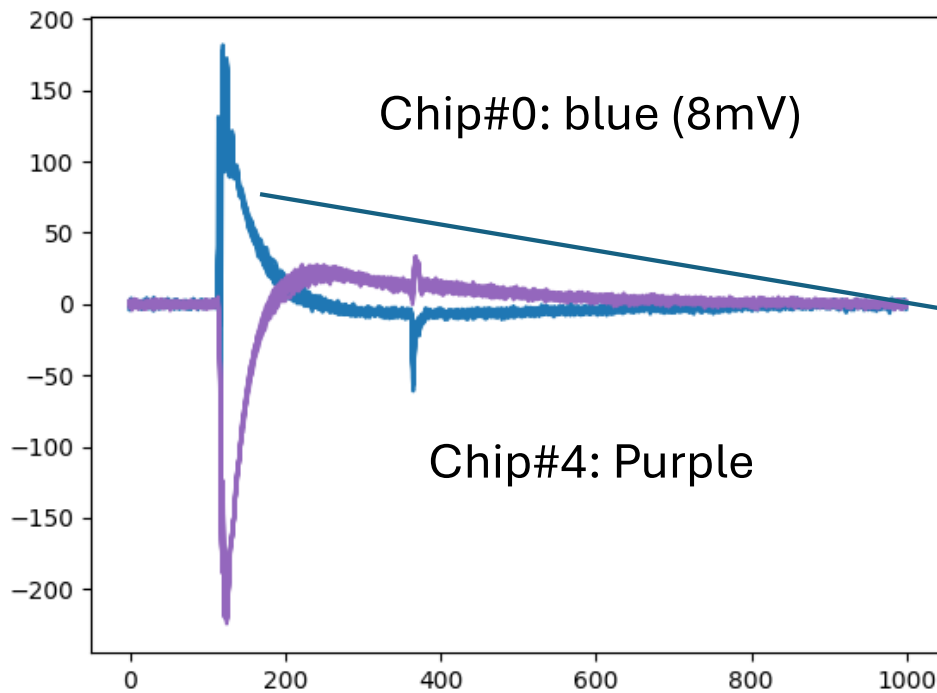
VDDA for chip#0-3: **0.1 Ohm, 1x C**
VDDP for chip#0-3: **0.1 Ohm, 3x C**
VDDA/VDDP (tied together) for chip#4-7: **1 Ohm, 3x C**



Scope CH1(Blue): VDDA&VDDP for ch64-ch127
Scope CH3(Green): VDDP for ch0-ch63
Scope CH4(Pink): VDDA for ch0-ch63
Scope CH2(Red): CH#0

Internal calibration (SE)

- Chip#1,2,3,5,6,7 are pulsed at 218 fC
 - Chip#0CH#0 is used for analog monitoring



Scope CH1(Blue): VDDA&VDDP for ch64-ch127

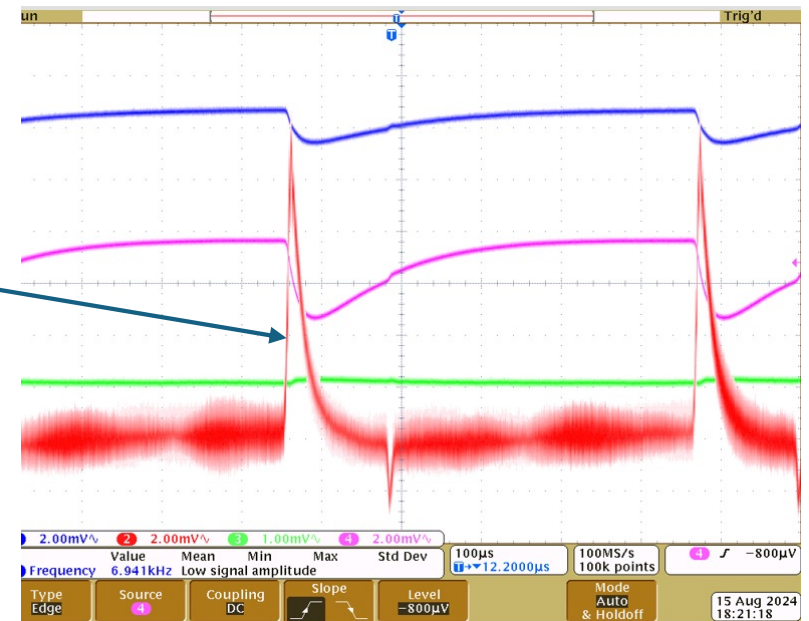
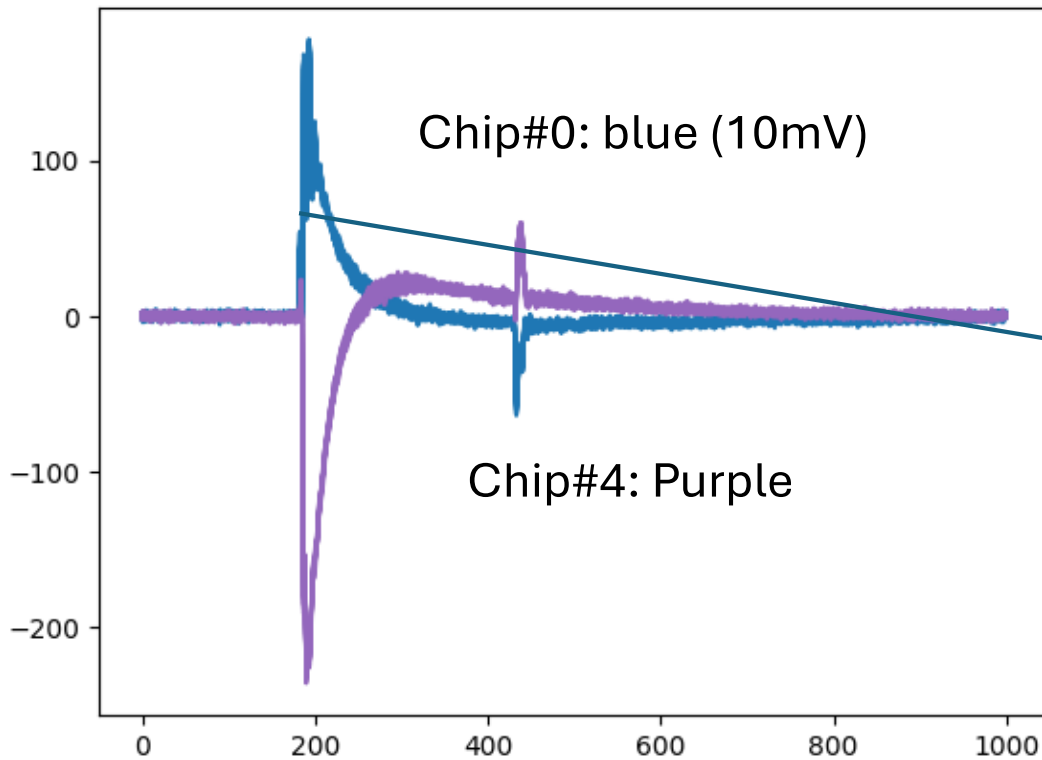
Scope CH3(Green): VDDP for ch0-ch63

Scope CH4(Pink): VDDA for ch0-ch63

Scope CH2(Red): CH#0

Internal calibration (DIFF)

- Chip#1,2,3,5,6,7 are pulsed at 218 fC
 - Chip#0CH#0 is used for analog monitoring



Scope CH1(Blue): VDDA&VDDP for ch64-ch127

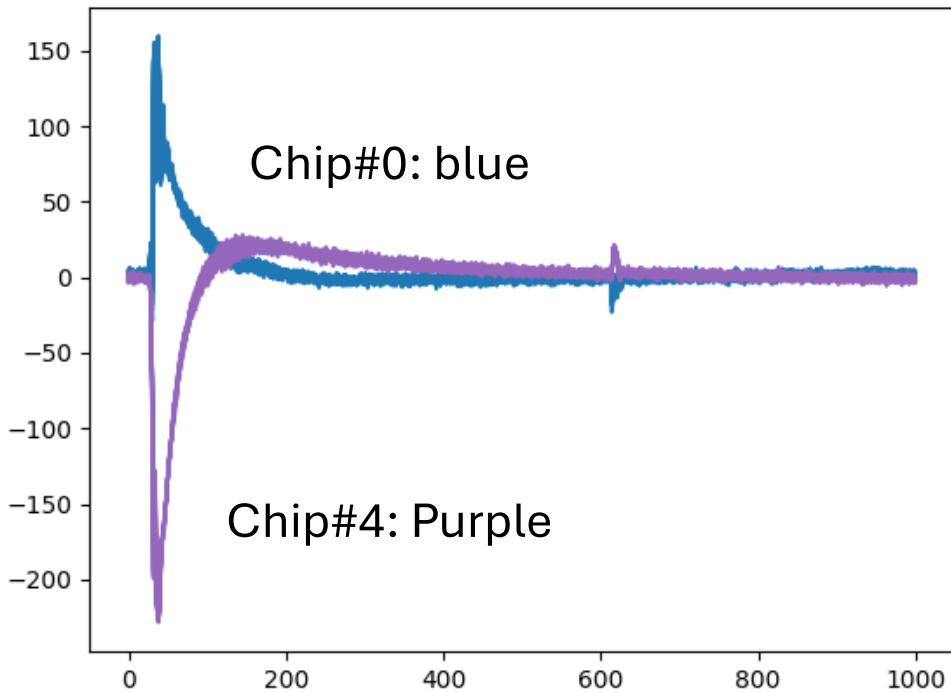
Scope CH3(Green): VDDP for ch0-ch63

Scope CH4(Pink): VDDA for ch0-ch63

Scope CH2(Red): CH#0

External Pulser from Signal Generator

- Chip#1,2,3,5,6,7 are pulsed at **185 fC**

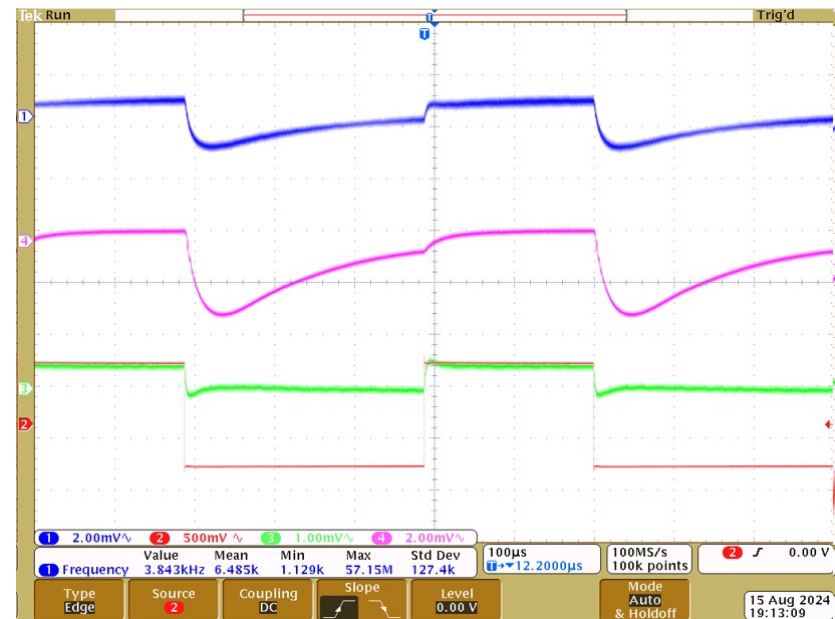


VDDA for chip#0-3: **0.1 Ohm, 2x C**

VDDP for chip#0-3: **0.1 Ohm, 1x C**

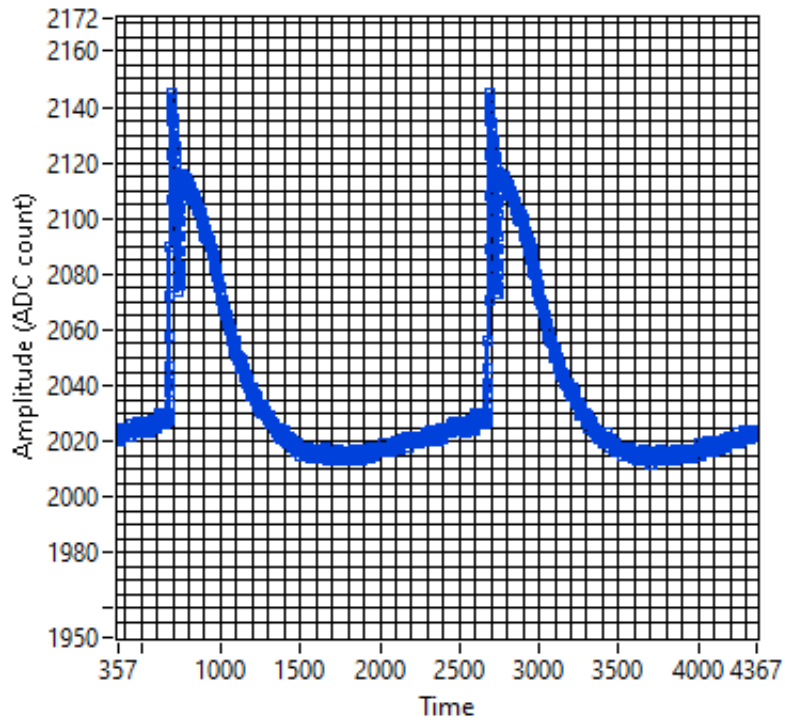
VDDO disconnected from VDDA
re-connected to VDDP for chip#0-3

VDDA/VDDP (tie together) for chip#4-7: **0.1 Ohm, 3x C**

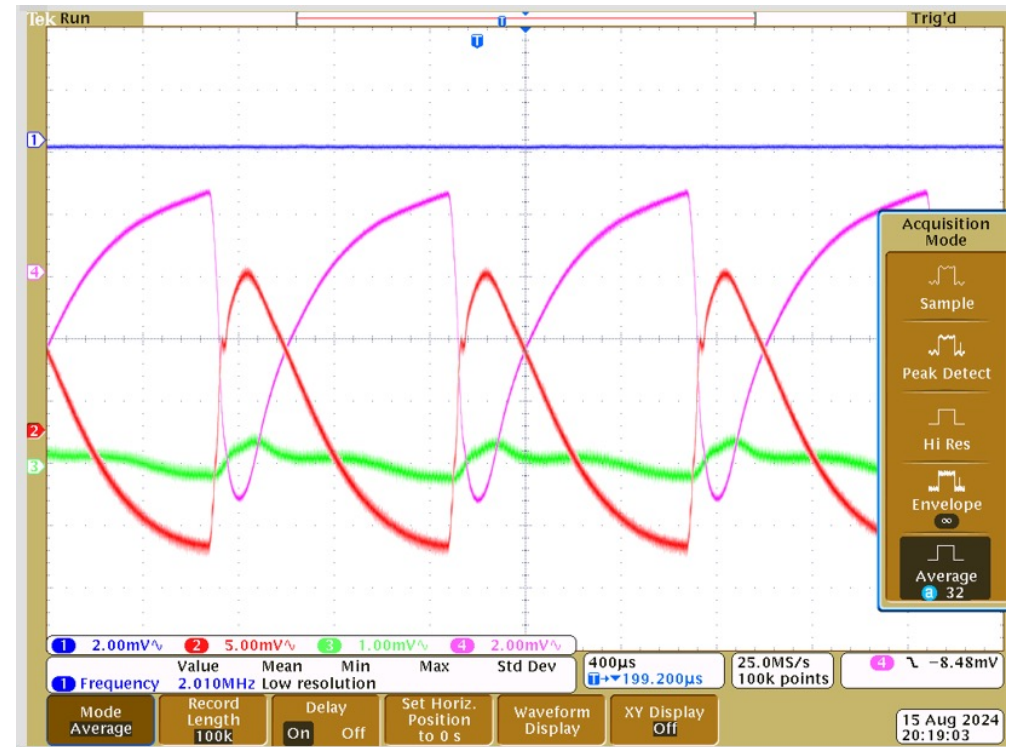


SBND FEMB (LN2)

- VDDP and VDDA are separated
- 3 chips are pulsed (dac = 0x3f)

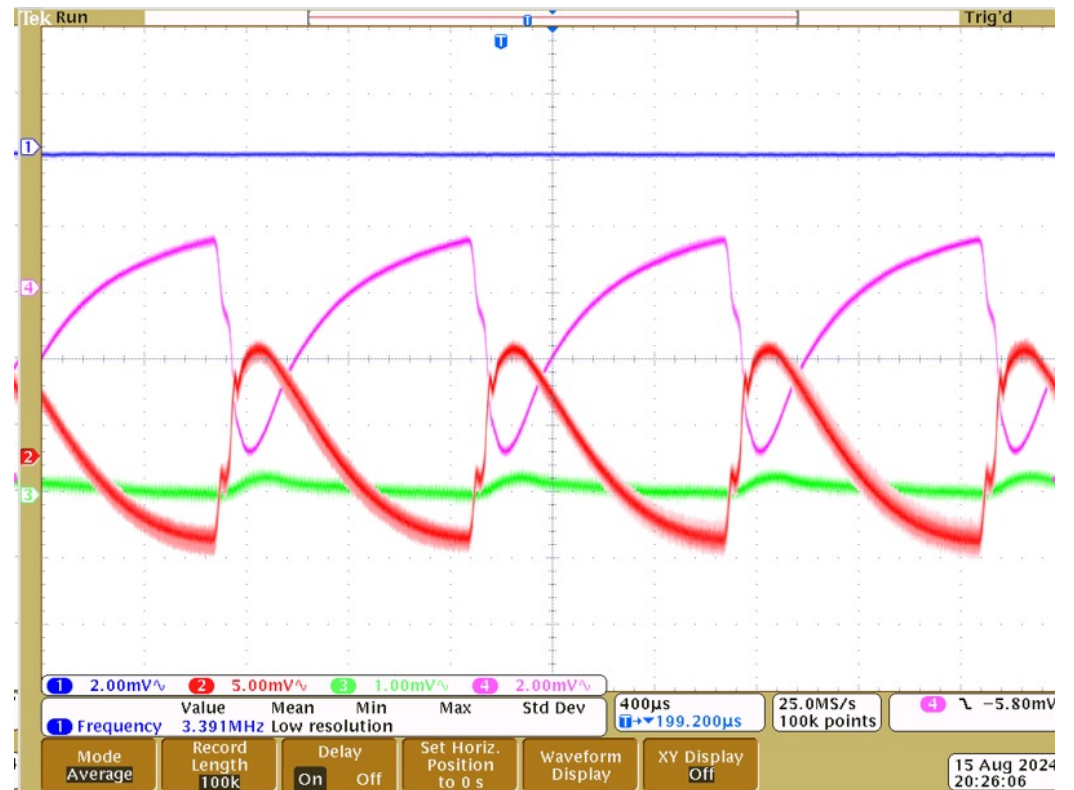
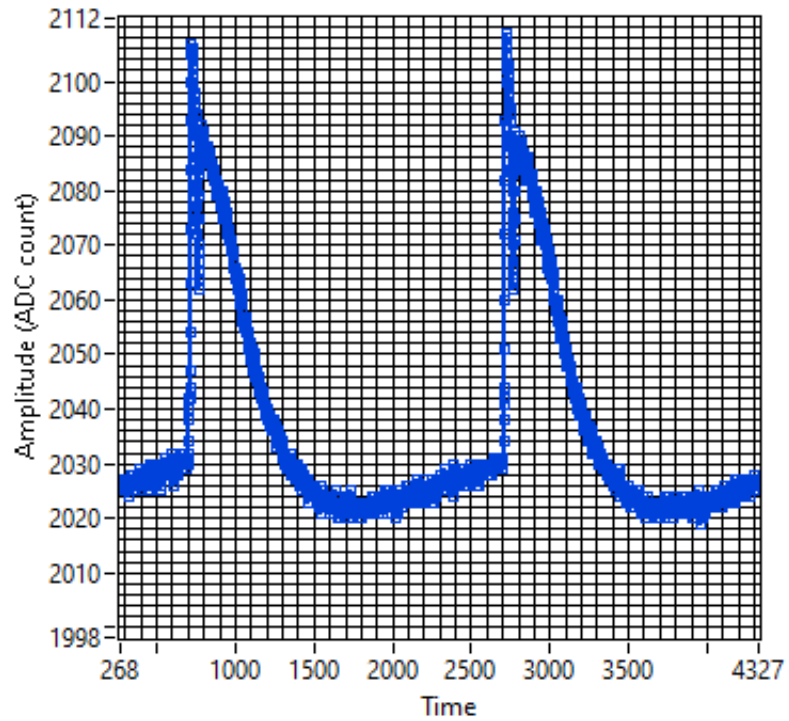


Scope CH1(Blue): VDDA&VDDP for ch64-ch127
Scope CH3(Green): VDDP for ch0-ch63
Scope CH4(Pink): VDDA for ch0-ch63
Scope CH2(Red): CH#0



SBND FEMB (LN2)

- 2 chips are pulsed (dac = 0x3f)



SBND SBND FEMB (LN2)

- 1 chip is pulsed (dac = 0x3f)

